L9945



Automotive fully configurable 8-channel High/Low side MOSFET pre-driver suitable for 12 V and 24 V systems



TQFP64 exposed pad down

Features



- 12 V and 24 V battery systems compliance
- 3.3 V and 5 V logic compatible I/O
- 8-channel configurable MOSFET pre-driver
 - High-side (N-channel and P-channel MOS)
 - Low-side (N-channel MOS)
 - H-bridge (up to 2 H-bridge)
 - Peak & Hold (2 loads)
- Operating battery supply voltage 3.8 V to 36 V
- Operating VDD supply voltage 4.5 V to 5.5 V
- All device pins, except the ground pins, withstand at least 40 V
- Programmable gate charge/discharge currents for improving EMI behavior
- Individual diagnosis for:
 - Short circuit to battery
 - Open load
 - Short circuit to ground
- Highly flexible overcurrent sensing implementation
 - Possibility of monitoring external MOS drain to source voltage
 - Possibility of monitoring voltage on external shunt resistor
 - 64 programmable overcurrent thresholds independent for each channel
 - Ultra-fast output shutdown in case of overcurrent
- Current limitation for H-Bridge configuration
- 32-bit SPI protocol available for configuration and diagnostics
 - Failures latched even if they occur during diagnostics reading
 - Daisy chain operation
 - SDO protected against overvoltage
- Safety features
 - Fast switch off redundant output disable through two external pins
 - Built In Self Test (BIST) for logic operation
 - Hardware Self Check (HWSC) for VDD5 overvoltage comparator
 - Configurable Communication Check (CC) watchdog timer available
 - Disable feedback through bi-directional pin
 - Highly redundant output monitoring through dedicated SPI registers
- 10-bit ADC for battery and die temperature measurements available through SPI
- VDD5 monitoring for over/under voltage
- VPS (battery) monitoring for under voltage

Prod	luct status lin	k
	L9945	
Pro	duct summary	/
Order code	Package	Packing
L9945	TQFP64	Tray
L9945TR	(exposed pad down)	Tape and reel

Description

The L9945 is an 8-channel MOSFET pre-driver configurable for low-side, high-side, peak and hold and H-Bridge load control. It is designed to comply with the requirements of 12 V (passenger vehicle) and 24 V (commercial vehicle) battery systems.

All outputs can be PWM controlled. Six outputs are capable of driving safety relevant loads. One output can be dedicated to the actuation of safety relevant loads requiring a dedicated enable pin (EN6).

The device offers the possibility of controlling two independent H-Bridges.

The device can also drive up to two loads requiring "peak & hold" control strategy.

The driver outputs are protected against short circuit condition.

The device protects the external MOS in case of an overcurrent event.

Each output provides full diagnostic information such as short to battery, short to ground and open-load. Each output status can be constantly monitored through dedicated SPI registers.

The voltage slew rate of the external transistors 1-8 is controlled during turn ON and turn OFF in order to improve EMI behavior.

A double, redundant, external disable source is available through DIS and NDIS pins in order to improve safety.

The device is configurable via SPI through a 32-bit protocol.

1 Block diagram

57

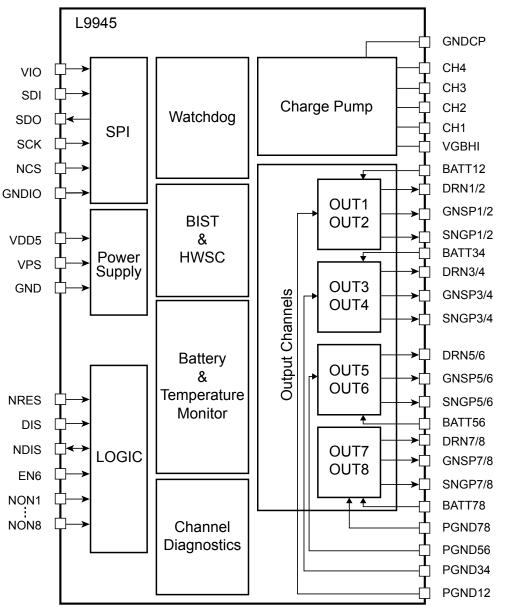


Figure 1. Block diagram

GADG2302170914PS

2 Applications

The device offers three different configuration options for the output channels: High-Side/Low-Side, Peak & Hold and H-Bridge. P&H configuration requires 2 or 4 channels, while H-Bridge requires 4 or 8 channels. Channels not used in P&H or H-Bridge are available for HS/LS usage. All the configurations involving channel 6 require the output driver 6 to be enabled through the EN6 input.

2.1 High-Side / Low-Side, with configurable FET type (N channel or P channel)

Each channel features a dedicated SPI register where the user can specify:

- MOS side: High-Side or Low-Side, through the LS_HS_config_xx bit;
- MOS type: NMOS or PMOS, through the N_P_config_xx bit;
 - PMOS type is available only for High-Side.

The picture below shows an example of High-Side configuration with NMOS transistor on channel 1. Refer to this schematic in order to understand how the external FET must be mounted with respect to the DRNx/GNSPx/SNGPx/BATTx pins.

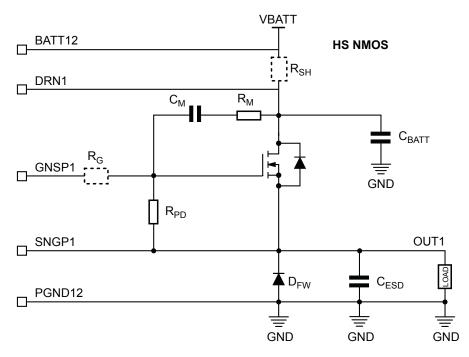


Figure 2. Example of High-Side configuration with NMOS on channel 1

Note: the freewheeling diode is needed only in case of inductive load.

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The following picture shows an example of High-Side configuration with PMOS transistor on channel 5. Refer to this schematic in order to understand how the external FET must be mounted with respect to the DRNx/GNSPx/SNGPx/BATTx pins.

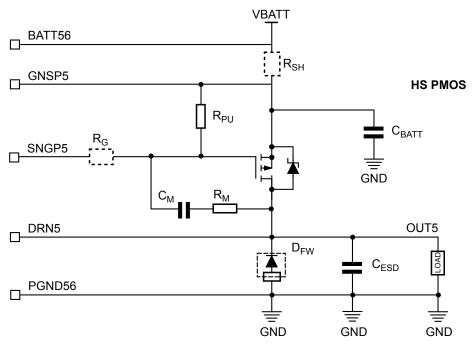


Figure 3. Example of High-Side configuration with PMOS on channel 5

Note: the freewheeling diode is needed only in case of inductive load.

The picture below shows an example of Low-Side configuration with NMOS transistor on channel 3. Refer to this schematic in order to understand how the external FET must be mounted with respect to the DRNx/GNSPx/SNGPx/PGNDx pins.

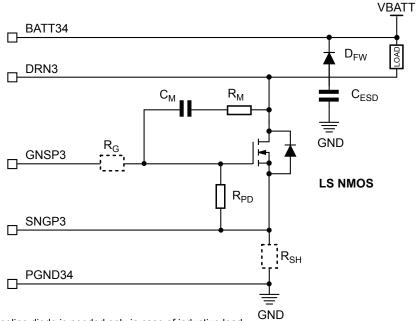


Figure 4. Example of Low-Side configuration with NMOS on channel 3

Note: the freewheeling diode is needed only in case of inductive load.

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GADG2302171301PS

Note: When using channel 6, the EN6 input must be set high to enable the output driver.

- The LS/HS configuration is suitable for driving whatever high-side/low-side loads as:
- Lamps (any channel);
- ON/OFF electrovalves (any channel);
- Any safety relevant load (channel 6 has dedicated EN6 enable input);
- Lambda probe heater (any channel);
- Limp home functionalities or not safety related loads (channels 7 and 8 not affected by external disable input).

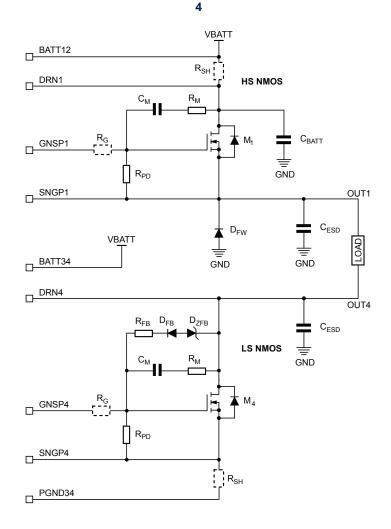
2.2 Peak & Hold

The device can handle up to two peak & hold loads. There are two possible configurations which can co-exist:

- P&H1: it involves channels 1 (HS) and 4 (LS) and can be selected through the PH1_config bit
- P&H2: it involves channels 2 (HS) and 3 (LS) and can be selected through the PH2_config bit

Once a peak & hold configuration is selected through its config bit, the corresponding output channels are automatically configured according to the pre-determined transistor side. The FET type for the High-Side can be selected through its **N_P_config_xx** bit.

Figure 5. Example of peak & hold configuration with NMOS (HS) on channel 1 and NMOS (LS) on channel



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Figure 5 shows an example of P&H1 configuration with NMOS transistor on the High-Side. Refer to this schematic in order to understand how the external FETs must be mounted with respect to the DRNx/GNSPx/SNGPx/PGNDx/BATTx pins.

In case of PMOS on the High-Side, refer to Figure 3 in order to understand the DRNx/GNSPx/SNGPx/BATTx pin connection.

The peak and hold configuration is suitable for driving several types of loads as:

- Injectors;
- Fuel pump;
- Other type of electrovalves and coils that may benefit from peak and hold control.

2.3 H-Bridge

The device can handle up to two H-Bridges. There are two possible configurations which can co-exist:

- H-Bridge 1: it involves channels 1 (HS), 2 (HS), 3 (LS) and 4 (LS) and can be selected through the **HB1_config** bit
- H-Bridge 2: it involves channels 5 (HS), 6 (HS), 7 (LS) and 8 (LS) and can be selected through the HB2_config bit

Once an H-Bridge configuration is selected through its config bit, the corresponding output channels are automatically configured as reported above. The FET type for the High-Side transistors can be selected through their **N_P_config_xx** bit.

In case of H-bridge with PMOS on the High-Side, refer to Figure 3 in order to understand how DRNx/GNSPx/ SNGPx/BATTx are mounted with respect to NMOS pin connection.

The H-Bridge configuration is suitable for driving the following types of loads:

Brushed DC motors

Note: When configuring H-Bridge 2, the EN6 input must be set high to enable the output driver.

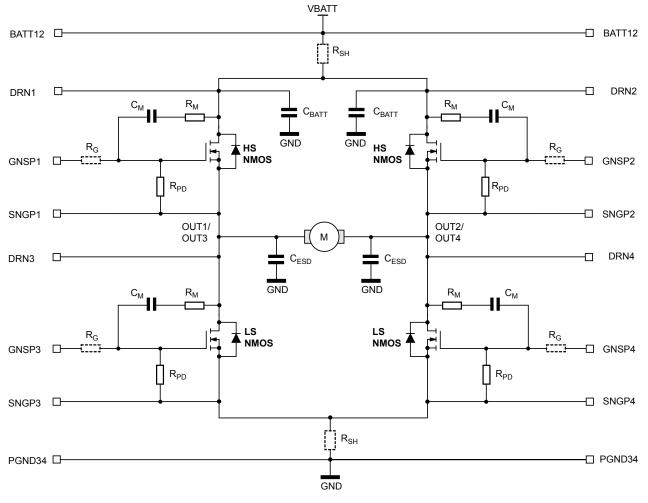


Figure 6. Example of H-Bridge configuration with NMOS as HS and LS transistors (channels 1-4 used)

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3 Device pins

This section contains the device pinout, the pin description and configuration and the electrical characteristics.

3.1 Pinout

The picture below shows the device pinout. Each pin features also the absolute maximum ratings. All pins, except the ground ones, can withstand at least 40 V to GND.

Maximum differential voltage allowed across the following pins is 20 V:

- GNSPx and SNGPx;
- CH2 and VPS;
- CH4 and CH2;
- VGBHI and VPS;
- VGBHI and CH4.

Figure 7. L9945 pinout

negative positive	60V	80V	60V	60V	60V	80V	60V	0.3V	0.3V	60V	80V	60V	60V	60V	80V	60V
negativ	-20V	-14V	-14V	-1	-14V	-14V	-20V	VE.0-	VE.0-	-20V	-14V	-14V	-1	-14V	-14V	-20V
pin name	DRN1	GNSP1	SNGP1	BATT12	SNGP2	GNSP2	DRN2	PGND12	PGND34	DRN3	GNSP3	SNGP3	BATT34	SNGP4	GNSP4	DRN4
	64	63	62	61	60	59	58	57	56	55	54	53	52	51	50	49

positive negative pin name

-0.3V	NON1	1
-0.3V	NON2	2
-0.3V	NON3	3
-0.3V	NON4	4
-0.3V	NON5	5
-0.3V	NON6	6
-0.3V	NON7	7
-0.3V	NON8	8
-0.3V	VIO	9
-0.3V	SDO	10
-0.3V	GNDIO	11
-0.3V	NRES	12
-0.3V	NCS	13
-0.3V	SDI	14
-0.3V	SCK	15
-0.3V	DIS	16
	-0.3V -0	-0.3V NON2 -0.3V NON3 -0.3V NON4 -0.3V NON5 -0.3V NON6 -0.3V NON7 -0.3V NON8 -0.3V SD0 -0.3V GNDIO -0.3V SD0 -0.3V SD0 -0.3V SD0 -0.3V SD0 -0.3V SD0 -0.3V SD0 -0.3V SD1 -0.3V SD1 -0.3V SD1 -0.3V SD1 -0.3V SD1

positive negative pin name

	0045	
– L	.9945	

TQFP64 Exposed Pad

10x10mm with 0.5mm pitch

46	RESERVED	-0.3V	60V
45	NDIS	-0.3V	40V
44	RESERVED	-0.3V	60V
43	CH1	-0.3V	60V
42	VPS	-1V	60V
41	СНЗ	-0.3V	60V
40	CH2	-0.3V	80V
39	CH4	-0.3V	80V
38	VGBHI	-0.3V	80V
37	GNDCP	-0.3V	0.3V
36	GND	-0.3V	0.3V
35	VDD5	-0.3V	40V
34	RESERVED	-0.3V	60V
33	RESERVED	-0.3V	60V

negative positive

60V

40V

-0.3V

-0.3V

pin name

EN6

48 RESERVED

47

17	18	19	20	21	22	23	24	25	26	27	28	29	30	31	32
DRN8	GNSP8	SNGP8	BATT78	SNGP7	GNSP7	DRN7	PGND78	PGND56	DRN6	GNSP6	SNGP6	BATT56	SNGP5	GNSP5	DRN5
-20V	-14V	-14V	-1V	-14V	-14V	-20V	-0.3V	-0.3V	-20V	-14V	-14V	-1V	-14V	-14V	-20V
60V	80V	60V	60V	60V	80V	60V	0.3V	0.3V	60V	X08	60V	60V	60V	80V	60V

GAPG0802160930CFT

Note:

3.2 Pin names and functions

The table below lists all the information about device pins.

The package exposed pad must be soldered on the PCB and connected to ground. Pins GNDIO and GNDCP must be shorted and ground connected.

Syntax: P = Power, G = Ground, D = Digital, A = Analog, I = Input, O = Output, NA = Not Available, L = Low, H = High, PU = Pull Up, PD = Pull Down.

Pin #	Pin Name	Pin	type	PU/PD	Active State	HBM ESD ⁽¹⁾	Description
Power	r Supply And	Grou	und				
42	VPS	Р	NA	NA	NA	4 kV	Battery Input, used to supply charge pump
36	GND	G	NA	NA	NA	2 kV	Ground
35	VDD5	Р	NA	NA	NA	2 kV	5 V Input (usually output of external regulator)
Digita	l inputs (conr	necte	d to e	external	microcontroll	er)	
1	NON1	D		PU	L	2 kV	Output 1 ON-OFF signal
	NONT	D	1	FU	L	2 KV	NPWM signal for H-Bridge 1
2	NON2	D	1	PU	L	2 kV	Output 2 ON-OFF signal
	NONZ			10	L	2 10	DIR signal for H-Bridge 1
3	NON3	D		PU	L	2 kV	Output 3 ON-OFF signal
					_		HIZ signal for H-Bridge 1
4	NON4	D	Ι	PU	L	2 kV	Output 4 ON-OFF signal
5	NON5	D		PU	L	2 kV	Output 5 ON-OFF signal
					_		NPWM signal for H-Bridge 2
6	NON6	D	1	PU	L	2 kV	Output 6 ON-OFF signal
							DIR signal for H-Bridge 2
7	NON7	D	I	PU	L	2 kV	Output 7 ON-OFF signal
							HIZ signal for H-Bridge 2
8	NON8	D	I	PU	L	2 kV	Output 8 ON-OFF signal
	t pre-driver			1			
64	DRN1	A	I	NA	NA	4 kV	FET drain on channel 1
63	GNSP1	A	0	NA	NA	4 kV	NFET gate / PFET source on channel 1
62	SNGP1	Α	0	NA	NA	4 kV	NFET source / PFET gate on channel 1
61	BATT12	Р	I	NA	NA	4 kV	Battery for channels 1 and 2
57	PGND12	G	I	NA	NA	4 kV	Power ground for channels 1 and 2
58	DRN2	Α	I	NA	NA	4 kV	FET drain on channel 2
59	GNSP2	Α	0	NA	NA	4 kV	NFET gate / PFET source on channel 2
60	SNGP2	Α	0	NA	NA	4 kV	NFET source / PFET gate on channel 2
55	DRN3	Α	I	NA	NA	4 kV	FET drain on channel 3
54	GNSP3	Α	0	NA	NA	4 kV	NFET gate / PFET source on channel 3
53	SNGP3	А	0	NA	NA	4 kV	NFET source / PFET gate on channel 3
52	BATT34	Р	I	NA	NA	4 kV	Battery for channels 3 and 4
56	PGND34	G	Ι	NA	NA	4 kV	Power ground for channels 3 and 4

Table 1. Pin list

49 DRN4 A I NA NA 4 kV FET drain on channel 4 50 GNSP4 A O NA NA 4 kV NFET gate / PFET source on channel 4 51 SNGP4 A O NA NA 4 kV NFET source / PFET gate on channel 4 32 DRN5 A I NA NA 4 kV NFET gate / PFET gate on channel 5 31 GNSP5 A O NA NA 4 kV NFET gate / PFET gate on channel 5 30 SNGP5 A O NA NA 4 kV NET gate / PFET gate on channel 5 29 BATT56 P I NA NA 4 kV Power ground for channels 5 and 6 26 DRN6 A I NA NA 4 kV NET gate / PET source on channel 6 27 GNSP6 A O NA NA 4 kV NFET gate / PET source on channel 6 23 DRN7 A I NA A kV
51 SNGP4 A O NA A kV NFET source / PFET gate on channel 4 32 DRN5 A I NA NA 4 kV NFET source / PFET gate on channel 5 31 GNSP5 A O NA NA 4 kV NFET gate / PFET gate on channel 5 30 SNGP5 A O NA NA 4 kV NFET source / PFET gate on channel 5 29 BATT56 P I NA NA 4 kV Battery for channels 5 and 6 26 DRN6 A I NA NA 4 kV Power ground for channels 5 and 6 27 GNSP6 A O NA NA 4 kV PrET gate / PFET source on channel 6 28 SNGP6 A O NA NA 4 kV NET gate / PFET source on channel 6 23 DRN7 A I NA A kV NET gate / PFET source on channel 7 20 BAT78 P I NA NA 4 kV
32 DRN5 A I NA NA 4 kV FET drain on channel 5 31 GNSP5 A O NA NA 4 kV NFET gate / PFET source on channel 5 30 SNGP5 A O NA NA 4 kV NFET source / PFET gate on channel 5 29 BATT56 P I NA NA 4 kV NET source / PFET gate on channel 5 26 DRN6 A I NA NA 4 kV Power ground for channels 5 and 6 27 GNSP6 A O NA NA 4 kV NET source / PFET source on channel 6 28 SNGP6 A O NA NA 4 kV NFET source on channel 7 22 GNSP7 A O NA NA 4 kV NET source / PFET source on channel 7 21 SNGP7 A O NA NA 4 kV NET source / PFET source on channel 7 20 BATT78 P I NA NA
31 GNSP5 A O NA NA 4 kV NFET gate / PFET source on channel 5 30 SNOP5 A O NA NA 4 kV NEET source / PFET gate on channel 5 29 BATT56 P I NA NA 4 kV Battery for channels 5 and 6 25 PGND56 G I NA NA 4 kV Power ground for channels 5 and 6 26 DRN6 A I NA NA 4 kV PFET gate / PFET source on channel 6 27 GNSP6 A O NA NA 4 kV NFET gate / PFET source on channel 6 28 SNGP6 A O NA NA 4 kV NFET gate / PFET gate on channel 6 23 DRN7 A I NA NA 4 kV NFET gate / PFET gate on channel 7 22 GNSP7 A O NA NA 4 kV NFET gate on channel 7 20 BATT78 P I NA NA
30 SNGP5 A O NA NA 4 kV NFET source / PFET gate on channel 5 29 BATT56 P I NA NA 4 kV Battery for channels 5 and 6 25 PGND56 G I NA NA 4 kV Power ground for channels 5 and 6 26 DRN6 A I NA NA 4 kV Peretrain on channel 6 27 GNSP6 A O NA NA 4 kV NFET gate / PFET source on channel 6 28 SNGP6 A O NA NA 4 kV NFET gate / PFET source on channel 6 23 DRN7 A I NA NA 4 kV NFET gate / PFET source on channel 6 23 DRN7 A I NA NA 4 kV NFET gate / PFET source on channel 7 21 SNGP7 A O NA NA 4 kV NFET gate on channel 7 20 BATT78 P I NA NA 4 kV Power ground for channels 7 and 8 17 DRN8 A I<
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Image: Second
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9 VIO P NA NA NA 2 kV as the SPI of the master device (usually the external microcont 11 GNDIO G NA NA 2 kV Ground for SPI. Must be shorted to GNDCP
Reset / Disable
12 NRES D I PU L 2 kV Reset input. Must be connected to ECU reset
16 DIS D I PU H 2 kV Disable input. Must be connected to the external microcontrolle the disabling of the outputs 1-6.
45 NDIS D I/O PD L 2 kV Negated disable input/output. Can be used as a negated disable input/output to generate an interrupt in the extermicrocontroller whenever the NDIS node is pulled down (internevent)
47 EN6 D I PD H 2 kV Output 6 Enable. Can be used to enable output driver for safety load control.
Charge Pump
38 VGBHI P NA NA NA 2 kV Charge pump output (battery + 12 V). Connected to VPS pin th "tank" capacitor
43 CH1 A I/O NA NA 2 kV 1 st node for flying capacitor 1

Pin #	Pin Name	Pin	type	PU/PD	Active State	HBM ESD (1)	Description
41	CH3	А	I/O	NA	NA	2 kV	1 st node for flying capacitor 2
39	CH4	Α	I/O	NA	NA	2 kV	2 nd node for flying capacitor 2
37	GNDCP	G	NA	NA	NA	2 kV	Ground for charge pump. Must be shorted to GNDIO
Other	pins						
44	RESERVED	D	I	NA	NA	2 kV	Tie low
48	RESERVED	NA	NA	NA	NA	2 kV	Leave floating
34	RESERVED	NA	NA	NA	NA	2 kV	Leave floating
46	RESERVED	NA	NA	NA	NA	2 kV	Leave floating
33	RESERVED	NA	NA	NA	NA	2 kV	Leave floating

1. See Table 4and Figure 8.



4 Product electrical and thermal characteristics

This section contains the Absolute Maximum Ratings (AMR), the latch-up trials, the ESD classification and the range of functionality of the device. The information provided here refers to the global behavior of the device. For specific information about the electrical characteristics of each interface/component, refer to the related section of the datasheet.

4.1 Absolute maximum ratings

Within the maximum ratings, no damage to the component or latch-up occurs and the defined leakage currents won't be exceeded. However, the full functionality of the device is guaranteed only in the functional range. This part may be irreparably damaged if taken outside the specified absolute maximum ratings. Operation above the absolute maximum ratings may also cause a decrease in reliability.

Note: A negative current is flowing out of the L9945, a positive current into the L9945.

Symbol	Parameter description	Comment	Min.	Max.	Unit
Supply Pins	5				
VDD5	VDD5 voltage range		-0.3	40	V
		Ext. HS, Static			
V _{VPS_sta}	Static VPS voltage range	Max voltage:	-1	60	V
		VGBHI – VPS = 20 V			
V_{VPS_dyn}	Dynamic VPS voltage range	Dynamic; 2 ms test pulse 1	-2	60	V
I _{PS_leak}	Leakage on pin VPS	POR or NRES active; VPS = $[0 - 36]$ V	0	20	μA
VGBHI	VGBHI voltage range (Ch. Pump)	Max voltage:	-0.3	80	V
VGDHI	VGBHI Voltage range (Ch. Pullip)	VGBHI – VPS = 20 V	-0.3	00	v
V _{VIO}	VIO voltage range	Supply for SDO	-0.3	40	V
Output Pre-	Driver				
		Max voltage:			
V _{SNGPx}	SNGPx voltage range	GNSPx - SNGPx = 20 V (in all conditions)	-14	60	V
		BATTxx – SNGPx \geq 0 V (When DSM is used for OC detection)			
V _{GNSPx}	GNSPx voltage range	Max voltage:	-14	80	v
GNGFX	Civer x voltage runge	GNSPx - SNGPx = 20 V		00	·
V _{DRNx}	DRNx voltage range	-	-20	60	V
		Max voltage:			
V _{BATTxx}	BATTxx voltage range	BATTxx – SNGPx ≥ 0 V	-1	60	V
		When DSM is used for OC detection			
Ground pin	s: GND, GNDIO, GNDCP, PGNDxx				
$V_{\text{GND}_\text{PINS}}$	Ground voltage range	-	-0.3	0.3	V
Charge Pur	np				
V _{CH1&3}	CH1 & CH3	-	-0.3	60	V

Table 2. Absolute maximum ratings capability

Symbol	Parameter description	Comment	Min.	Max.	Unit
		Max voltage:			
Variation	CH2 & CH4	CH2 - VPS = 20 V	-0.3	80	v
V _{CH2&4}		CH4 - CH2 = 20 V	-0.5	00	v
		VGBHI - CH4 = 20 V			
Digital HV p					
V _{DIG_IO}	Input voltage range	SDO and NDIS have to withstand this voltage also in ON-condition	-0.3	40	V

Refer to Figure 7 for the device pinout with AMR indicated for each pin.

4.2 Latch-up trials

The table below lists the information about the Latch-up trials.

Note: A negative current is flowing out of the L9945, a positive current into the L9945.

Table 3. Latch-up trials

Symbol	Parameter description	Comment	Min.	Max.	Unit
LU	Latch-up Test	For all pins according to JEDEC78 class II level A	100	-	mA
	•				L

4.3 ESD performance

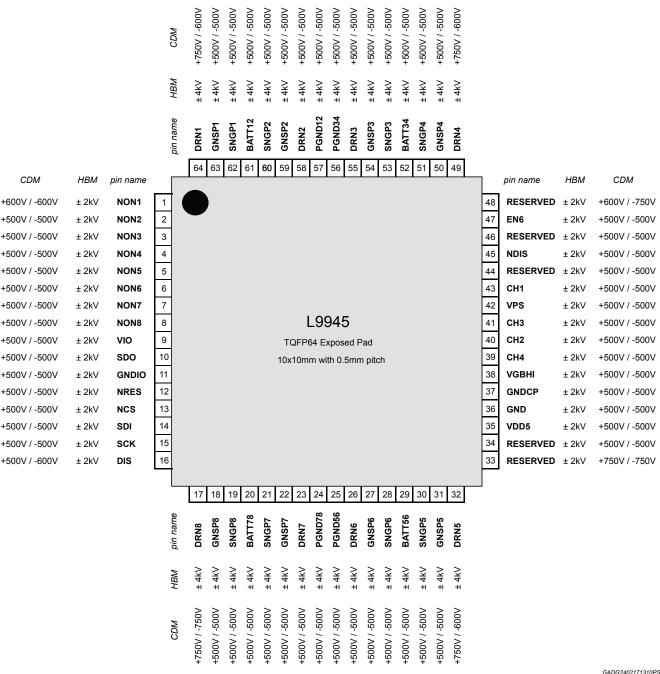
The table below contains all the information about the ESD characterization of the device.

Note: A negative current is flowing out of the L9945, a positive current into the L9945.

Table 4. ESD performance

Symbol	Parameter description	Comment	Min.	Max.	Unit
ESD Classi	fication (refer to Figure 8)				
Human Body Model (HBM)		For pins: DRNx, SNGPx, GNSPx, BATTxx, PGNDxx, VPS According to Q100-002	-4	4	kV
	(100 pF/ 1.5 kΩ)	For all other pins according to Q100-002	-2	2	kV
V _{ESD}	For corner pins DRN1, DRN4, DRN5 according to Q100-011	-600	750	V	
	Charged Device Model (CDM)	For corner pin T1 according to Q100-011	-750	600	V
		For corner pin NON1 according to Q100-011	-600	600	V
		For corner pin DIS according to Q100-011	-600	500	V
		For corner pins T4, T8 according to Q100-011	-750	750	V
		For all other pins	-500	500	V
Protection	diodes current				
I _{ESD_SUP}	ESD protection diode current	For pins VPS, VDD5, VGBHI, VIO	-1	1	mA
I _{ESD_DRNx}	ESD protection diode current	For DRNx pins	-1	1	mA
I _{ESD_DIG}	ESD protection diode current	For pins NONx, NRES, NDIS, DIS, SDI, SCK, EN6, NCS, SDO	-1	1	mA





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Figure 8 summarizes the ESD ratings for each pin according to both CDM and HBM models.

4.4 Thermal behavior

The table below contains the temperature ranges and the thermal resistance information. The device functionality is lifetime guaranteed up to 150 °C (junction temperature). If the junction temperature crosses TOT_OFF, overtemperature is detected. Status of the overtemperature comparator can be monitored reading **OT_STATE** bit via SPI. The external microcontroller can either read the temperature measured by the Temperature ADC or monitor OT_STATE bit: in case of overtemperature, L9945 must be disabled via external input.

Note: $V_{VPS_UV} < V_{VPS} < 60$ V, all supplies are independent; 4.5 V < VDD5 < 5.5 V; 3.0 V < VIO < 5.5 V, unless otherwise noted.

Symbol	Parameter description	Comment	Min.	Max.	Unit
Tempera	ture ranges				
T _{j_op}	Operating / Lifetime (junction)	Lifetime guaranteed	-40	150	°C
T _{stg}	Storage temperature	-55 °C is allowed for a maximum of 15h	-40	+150	°C
T _{j_fct}	Functional (junction)	Transient condition	150	T _{OT_OFF}	
T _{OT_OFF}	Over temperature comparator threshold	-	165	190	°C
t _{Off_prot}	Comparator reaction time including analogue deglitching filter	-	100	900	ns
Thermal	resistance				
R _{th_j_c}	Thermal resistance (junction to case)	Values are according to Jedec JESD51-2,-5,-7 at natural	-	2.4	°C/W
R _{th_j_a}	Thermal resistance (junction to ambient)	convection on FR4 2s2p board (see Figure 9)		30	°C/W

Table 5. Thermal behavior

Figure 9. Sketch of a 2s2p PCB with thermal vias

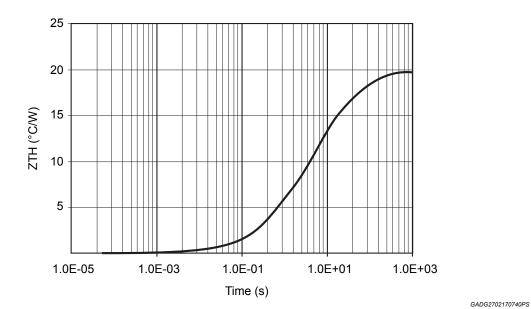


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Note: In "2s2p", the "s" suffix stands for "Signal" and the number before indicates how many PCB layers are dedicated to signal wires. The "p" suffix stands for "Power" and the number before indicates how many PCB layers are dedicated to power planes.

The graph below shows the thermal impedance of the package.





4.4.1 Temperature ADC

An internal ADC monitors the junction temperature. Measure is available reading Temp_ADC[x] bit and applying the following conversion law:

Eq. (1): Junction temperature conversion law

$$T_j = \left(0.28 \times CODE\right) - 65\tag{1}$$

The table below reports the electrical characteristics for the temperature ADC.

Note: $V_{VPS_UV} < V_{VPS} < 60 V$, all supplies are independent; 4.5 V < VDD5 < 5.5 V; 3.0 V < VIO < 5.5 V, unless otherwise noted.

Table 6. Temperature ADC electrical characteristics

Symbol	Parameter	Test condition	Min.	Тур.	Max.	Unit
ADC_res	Resolution	-	-	10	-	bit
f _{ADC}	Conversion rate	-	-	62.5	-	kHz
Tj_ADC_in	Temperature range	-	-40	-	190	°C
T_ACC	Temp accuracy	From -40 °C to 190 °C	-10	-	10	°C

Note:

4.5 Range of functionality

The table below lists the range of functionality for the electrical parameters.

Junction temperature is assumed $T_j = T_{j_fct}$ unless otherwise noted.

Table 7	Range of	f functionality
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Symbol	Parameter description	Comment	Min.	Max.	Unit
Supply pin	S				
		Operational	3.8	36	V
	External load and charge pump supply	For 15 min		48	v
V _{VPS}		at 45 °C	-		v
		Load dump	_	60	v
		(< 500 ms)		00	v
V _{VDD5}	Supply for internal digital, analog and SPI (except SDO)	$T_j = T_{j_op}$	4.5	5.5	V
V _{VIO}	Supply for SPI pin SDO	$T_j = T_{j_op}$	3.0	5.5	V

5 Functional description

This section contains the functional description of the L9945. A general description of the device functionality is provided along with the detailed operation of each sub-block. Relations and interconnections between various sub-blocks are explained. For a detailed diagnostic analysis, refer to Section 6.2 Diagnostics overview.

5.1 General description

The device contains eight pre-drivers for external FETs. Each pre-driver can be configured to drive a high-side or low-side external driver (**LS_HS_config_xx** bit). The external FET can be either N-channel (low-side and high-side) or P-channel (high-side). FET type is selectable through **N_P_config_xx** bit. Complex configurations for P&H and H-Bridge are automatically applied programming the corresponding bit via SPI (**HBx_config** or **PHx_config**).

The outputs are controlled either directly by pins **NONx** or via SPI commands (programming **SPI_ON_OUTxx** bit). For each channel, control strategy is selected by programming the **SPI_input_sel_xx** bit.

Output channels must be enabled prior to use by programming the **en_OUT_xx** bit in the corresponding output register. Channel 6 requires also the EN6 input to be set high in order to be enabled (suitable for safety relevant load control).

IC provides charge pump for driving external low-side and high-side NMOS. Gate charge/discharge currents can be either constant, with value selectable via SPI, or limited by external resistor. **GCC_config_xx** bit defines the charge/discharge strategy. An external capacitor connected between transistor gate and drain is recommended to improve EMI performances.

External FET is protected against overcurrent (OC) during the ON phase by rapidly switching OFF the transistor with a high gate current in case of OC detection. The value of such shutdown current can be programmed via the **GCC_OVERRIDE_CONFIG** bit. Two detection strategies are available: either monitoring the voltage between transistor drain and source (DSM) or monitoring the drop on an external shunt resistor. Detection strategy is selectable via **OC_DS_Shunt_xx** bit. OC threshold is programmable via SPI (**OC_config_xx** bit). The device offers the possibility of compensating the OC threshold with respect to temperature (**OC_Temp_comp_xx** bit) and battery variations (**OC_Batt_comp_xx** bit). In case of an OC event, output re-engagement strategy is selectable through **prot_config_xx** bit.

Detection of Open Load (OL) and STB/STG failures is performed during the OFF phase. The diagnostic phase durations and currents can be selected through **tdiag_config_xx** and **diag_i_config_xx** bit.

In peak and hold configuration, the OFF diagnostic strategy can be programmed through **PHx_diag_strategy** bit. In H-Bridge mode, the dead time to avoid cross conduction on the same branch of the bridge can be programmed through the **HBx_dead_time** bit. An extended set of OFF diagnostic times is available for the H-Bridge mode by programming the **HBx_tdiag_ext_config** bit.

A current limitation feature is available for H-Bridge configuration.

The diagnostic status of each channel is reported in the next received frame after having sent the following SPI command: **0x9AAA0001**.

Note: The "x" in the bit names symbolize the generic channel number or the configuration index (e.g. NONx refers to NON1, NON2, ..., NON8. PHx_diag_strategy refers to PH1_diag_strategy and PH2_diag_strategy).

5.2 Supply concept

The device has 4 supply pins: VDD5, VPS, VGBHI, and VIO.

- VDD5 has to be provided by the ECU power supply and feeds most of the internal sub-blocks. Two internal regulators are used to generate separate 3.3 V supplies for analog and digital domains.
- VPS has to be provided by the battery and is used to feed the internal charge pump.
- VGBHI is the output voltage of the charge pump and it is used for driving the gate of the external FETs.
- VIO is a separate power supply dedicated for the SDO pin of the Serial Peripheral Interface. It must be connected to the same voltage level of the SPI master. The VIO pin is implemented in order to be compliant with both 3.3 V and 5 V systems.

5.2.1 VDD5 supply block

The VDD5 pin is internally split between analog and digital domain to reduce interference between the different parts of the component. Two regulators are implemented in order to provide separate 3.3 V domains:

- VDD_int_a is generated out of VDD5. It is the overvoltage protected internal supply of the low voltage analog part, such as diagnostic comparators, gate drives for integrated low-side, bias currents, bandgap etc.;
- VDD_int_d is generated out of VDD5. It is the overvoltage protected internal supply for the digital part.

The component starts operation when VDD5 is higher than the power-on reset threshold (VPOR). Details about the reset block are given in the Section 5.3 Reset.

The VDD5 is monitored to generate over (OV) and under voltage (UV) disable in case of fault. The disable signal acts both internally and externally: in case of output disable due to failure on VDD5, the NDIS bidirectional pin is internally pulled down. The purpose is providing a feedback to the external microcontroller monitoring the device status. Detailed information about disable sources is given in the Section 6.1 Disable sources paragraph.

Range of characteristic is defined for VDD5 from **4.5 V** to **5.5 V**. In this range, the component works according to the specification without any restrictions and all parameters are in the specified range.

The table below lists the electrical characteristics of the VDD5 supply block.

Note:

 $T^{j} = T_{j_{op}}$; $V_{VPS_{UV}} < V_{VPS} < 60$ V, all supplies are independent; 4.5 V < VDD5 < 5.5 V; 3.0 V < VIO < 5.5 V, unless otherwise noted.

Symbol	Parameter	Test condition	Min.	Тур.	Max.	Unit
I _{VDD5_opm}	VDD5 operating mode current	All outputs controlled ON	7	-	35	mA
I _{VDD5OV}	VDD5 current in case of overvoltage	5.5 V < VDD5 ≤ 36 V	8	-	40	mA
V _{VDD5_UV}	VDD5 UV threshold	Undervoltage	4.5	-	4.7	V
V _{VDD5_UV_HYS}	VDD5 UV hysteresis	VVDD5_UV	10	-	50	mV
t _{VDD5_UV1}	VDD5 undervoltage filter time	-	2	2.6	3.25	ms
t _{VDD5_UV_react}	VDD5_UV Comparator output reaction time	-	100	-	700	ns
t _{VDD5_UV2}	VDD5 under voltage filter time for NDIS activation	-	415	500	625	ms
V _{VDD5_OV}	VDD5 overvoltage disable threshold	Self-checked by HWSC	5.3	-	5.5	V
V _{VDD5_OV_HYS}	VDD5 OV disable hysteresis	-	10	-	50	mV
t _{VDD5_OV}	VDD5 overvoltage filter time	-	2.0	2.6	3.25	ms
t _{VDD5_OV_react}	VDD5_OV Comparator output reaction time	-	100	-	700	ns
V _{POR}	POR release threshold	Related to VDD5	4.15	-	4.45	V
V _{POR_HYS}	POR hysteresis	-	0.15	-	0.25	V
t _{POR_D}	POR RESET delay time	POR delay at startup of VDD5	10	-	50	μs

Table 8. VDD5 supply block electrical characteristics

5.2.2 VPS supply block

The VPS pin is a battery supply. It is used for the internal charge pump to drive the N-channel external MOSFETs. The VPS line is monitored to detect low voltage on VPS. In case the voltage on VPS is lower than V_{VPS_UV} the pre-drivers are actively turned off. Such event is latched in **VPS_LATCH**, cleared on SPI readout. The undervoltage comparator output can be monitored reading **VPS_STATE** bit via SPI. The table below lists the electrical characteristics for the VPS supply block:

Note: $T_j = T_{j_op}$; $V_{VPS_UV} < V_{VPS} < 60$ V, all supplies are independent; 4.5 V < VDD5 < 5.5 V; 3.0 V < VIO < 5.5 V, unless otherwise noted.

Table 9. VPS supply block electrical characteristics

Symbol	Parameter	Test condition	Min.	Тур.	Max.	Unit
I _{VPS_OPM}	IVPS operating mode current	-	3	-	50	mA
V _{VPS_UV}	VPS low battery detection threshold	-	3.5	-	3.8	V
t _{VPS_react}	VPS Comparator output reaction time	-	100	-	700	ns
t _{LBD_FIL}	Filter time for VPS low battery detection	-	0.5	-	5	μs

5.2.3 VPS ADC

L9945 has an internal ADC monitoring VPS. Measure is obtained reading VPS_ADC[x] bit and applying the following conversion law:

Eq. (2): Battery monitor conversion law

$$V_{PS} = 0.048 \times CODE$$

(2)

The table below reports the electrical characteristics of the VPS ADC.

Note:

 $T_j = T_{j_op}$; all supplies are independent; 4.5 V < VDD5 < 5.5 V; 3.0 V < VIO < 5.5 V, unless otherwise noted.

Table 10. VPS ADC electrical characteristics

Symbol	Parameter	Test Condition	Min.	Тур.	Max.	Unit
ADC_res	Resolution	-	-	10	-	bit
f _{ADC}	Conversion rate	-	-	62.5	-	kHz
VPS_ADC_in	Input range VVPS	-	0	-	48	V
VPS_ACC	V _{VPS} accuracy	3.5 V < V _{VPS} < 12 V	-400	-	400	mV
		12 V < V _{VPS} < 48 V	-3.3	-	3.3	%

5.2.4 Charge pump (VGBHI)

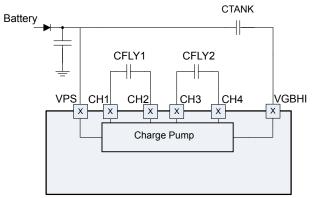
To effectively bias the high side drivers and fail safe switch, a charge pump is used to drive the gate voltage above VPS. The charge pump switching frequency is nominally 200 KHz.

A built-in monitoring circuit checks if the charge pump output voltage is sufficient to control the high side valve driver. In case of undervoltage (VGBHI < VCP_UV), the outputs are actively turned off and VCP_UV_LATCH is set (readable via SPI, cleared on readout). The output of the undervoltage comparator can be monitored reading VCP_UV_STATE via SPI.

At power ON, the charge pump is enabled when VDD5 is above VPOR and NRES is not asserted.

Refer to the AN: "Charge Pump Stress Estimation In Switching Applications" in order to understand how the switching frequency of the outputs affects the charge pump behavior.

Figure 11. Charge pump connections



Ratings: CTANK: 16 V CFLY1, CFLY2: 50 V for 12 V systems, 100 V for 24 V systems.

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The table below lists the electrical characteristics of the charge pump:

Note:

 $T_j = T_{j_op}$; $V_{VPS_UV} < V_{VPS} < 60$ V, all supplies are independent; 4.5 V < VDD5 < 5.5 V; 3.0 V < VIO < 5.5 V, unless otherwise noted.

Table 11	Charge p	oump electrical	characteristics
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Symbol	Parameter	Test Condition	Min.	Тур.	Max.	Unit
		VVPS ≥ 8 V; IVGBHI = 15 mA (DC)	VVPS+9	VVPS+12	VVPS+16	V
V _{VGBHI}	Charge pump voltage versus charge pump load current	$VVPS_UV \le VVPS < 8 V$; $IVGBHI = 6 mA$ (DC)	VVPS+5	-	VVPS+16	v
f _{CP}	Charge pump frequency	Dependent on t _{SYS}	184	200	216	kHz
C _{TANK}	Charge pump tank capacitor	Connected to VPS IVGBHI = 15 mA	420	470	520	nF
C _{FLY}	Charge pump flying capacitors	Connected between CH1-CH2, CH3-CH4; IVGBHI = 15 mA	198	220	242	nF
V _{CP_UV}	Under voltage threshold	Referenced to VVPS	VVPS+3.9	-	VVPS+5.1	V
Vh_{CP_UV}	Under voltage hysteresis	Referenced to VVPS	250	-		mV
t _{CP_UV}	Under voltage filter time	-	10	-	30	μs
V _{VGBHI_MAX}	Charge pump max voltage	Referenced to GND	-	-	80	V
t _{CPstartup}	Startup time	-	-	-	2	ms
I _{BIAS_ON}	Internal absorption in when $V_{GNSPx} = ON$	Design info. Not tested in ATE	-	-	530	μA
I _{BIAS_OFF}	Internal absorption in when V _{GNSPx} = OFF	Design info. Not tested in ATE	-	-	480	μA

5.2.5 VIO supply pin & SDO pin characteristics

The VIO supply pin is used to feed SDO output driver. It can be connected either to 5 V or 3.3 V supply, in order to be compatible with different external I/O logic.

In case of an overvoltage condition at the SDO output, the SDO driver is switched off and eventual back feeding current towards VIO is blocked. Once the over-voltage is removed from SDO-pin, the output is re-activated at NCS low-to-high transition. SDO overvoltage event is latched in **SDO_OV_LATCH**, cleared via SPI readout. Table below lists the electrical characteristics for the SDO output pin.

Note:

$T_j = T_{j_op}$; $V_{VPS_UV} < V_{VPS} < 60$ V, all supplies are independent; 4.5 V < VDD5 < 5.5 V; 3.0 V < VIO < 5.5 V,
unless otherwise noted.

Symbol	Parameter	Test condition	Min.	Max.	Uni
t _{sdo_trans}	SDO Rise and Fall time	C _{LOAD} = 20 to 150 pF	5	35	ns
t _{pcld}	Propagation delay – incl. Rise/Fall time (SCLK to data at SDO active)	C _{LOAD} = 150 pF	-	50	ns
t _{csdv}	NCS = LOW to output SDO active	C _{LOAD} = 150 pF	-	90	ns
t _{pchdz}	NCS L/H to SDO @ high impedance	-	-	75	ns
C _{IN_SPI}	Input capacitance at SDI; SDO; SCLK; NCS	-	-	10	pF
V _{SDOH}	High output level	ISDO = -2 mA	V _{IO} - 0.4 V	-	V
V _{SDOL}	Low output level	ISDO = 3.2 mA		0.4	V
		NCS = HIGH;	-5	5	
		$0 < V_{SDO} < V_{IO} - 0.3 V$	-5	5	μ
	Tri state leakage current	NCS = HIGH;	-5	15 30	μ
I _{SDO_Leak}		$V_{\text{SDO}} = V_{\text{IO}} - 0.3 \text{ V}$	-5		μ
		NCS = HIGH;	2		μ
		V _{SDO} = V _{IO}		50	μ
V _{OV_SDO}	Over voltage detection threshold at SDO output (for reverse supply protection)	Prevent output from damage; avoid back supply to VIO; no hysteresis required	VIO + 0.05	VIO + 0.2	V
t _{OV_SDO_fil}	Overvoltage detection analog filter time	-	100	700	n
t _{OFF_PROT_OV}	Overvoltage detection HS turn OFF/ON time at SDO.	Includes analog filter time and comparator reaction time until 50% IOVpeak_SDO_HS	0.5	5	μ
OVpeak_SDO_HS	Maximum possible peak reverse current at SDO HS before protection Turn Off	VSDO = 36 V; VIO = 3 V; limited by R _{DSON} only; HS channel On	90	250	m

Table 12. SDO pin electrical characteristics

Note: The SDO pin electrical characteristics are also reported in the SPI table. SDO PCB trace must be routed carefully in order avoid spikes on SDO pin, which may generate an overvoltage failure. A pull-down resistor in the $[10 - 47] k\Omega$ range on SDO pin is also recommended.

5.3 Reset

The device is reset by the following two events:

Power On Reset (POR)

- $0 \leq VDD5 \leq VPOR$:
 - Logic is reset;
 - Outputs are in three-state, diagnostics regulators for open load detection are OFF;
 - No violation of leakage current requirements;
 - Charge pump is disabled.



- VPOR \leq VDD5 \leq 4.5 V:
 - SPI functional (if VIO is stable);
 - Internal oscillator is functional and the logic is working correctly;
 - The outputs can switch according to the control;
 - Regulators for open load detection may provide wrong diagnostic;
 - Overcurrent shutdown is active but thresholds may be inaccurate.

NRES assertion:

- NRES input is active low;
- It is typically connected to the VDD5 reset of the ECU power supply;
- NRES is internally pulled up: in case of NRES pin left unconnected, NRES is inactive;
- Open load failure detection is inactive during NRES assertion;
- Charge pump is disabled while NRES is asserted.

Both POR and NRES events are latched and readable via SPI:

- After POR, the **n_POR_LATCH** is set and can be cleared via SPI readout;
- When NRES is active, NRES_LATCH is set and can be cleared via SPI readout.

The two reset events are ORed, so that full functionality is achieved only when both POR and NRES are released.

The default configuration for the outputs after reset is Low-Side with NFET. Channels are three-stated until the output is enabled through the **en_OUT_xx** bit.

After configuration and enable, all outputs follow the control signal as long as reset (NRES, POR) is not active. In case of a reset all outputs will be immediately disabled and all diagnostic and protection information will be lost.

5.4 Output pre-drivers

This paragraph contains the available configurations for the output pre-drivers. Enable and control strategies are explained. Output diagnostic is also explained, along with other useful application information.

5.4.1 Available configurations

There are eight pre-driver channels. Each channel can be independently configured in three different ways, via SPI configuration commands:

- Low-Side with NFET;
- High-Side with NFET;
- High-Side with PFET.

Channel side is programmed through LS_HS_config_xx bit, while FET type is selected through N_P_config_xx bit. Refer to Section 2 Applications in order to understand how the external FET must be mounted with respect to device pins. Complex configurations for H-Bridge and Peak & Hold are presented in their respective section.

5.4.2 Default configuration and output enable

After reset channels are configured as Low-Side with NFET by default. Outputs are in three-state until they are configured and enabled through the **en_OUT_xx** bit.

Channel 6 has an additional enable control via the EN6 input: **EN6** is in logical AND with en_OUT_06 bit, meaning that both signals have to be set high in order to enable the output driver. This feature makes it suitable for safety relevant load control. EN6 status can be monitored reading **EN6_STATE** bit via SPI. If channel 6 has been disabled setting EN6 low, the event is latched in **EN6_LATCH**, cleared on SPI readout.

5.4.3 Output control

The outputs can be controlled ON and OFF via SPI bit SPI_ON_OUTxx or input pins NONx. The selection of the control signal is independent for each channel and is programmed via the SPI_input_sel_xx bit:

- SPI_input_sel_xx = 0: control via NONx input
 - The NONx inputs are active low, meaning that the output is ON when the input is low and vice-versa



- SPI_input_sel_xx = 1: control via SPI_ON_OUTxx bit
 - The SPI_ON_OUTxx bit are positive asserted, meaning that the output is ON when the input is high and vice-versa

The table below summarizes output behavior depending on control strategy and control input.

SPI_input_sel_xx	NONx	SPI_ON_OUTxx	External FET status
0	0	X ⁽¹⁾	ON
0	1	Х	OFF
1	Х	0	OFF
1	Х	1	ON

Table 13. Output status depending on control strategy and control input

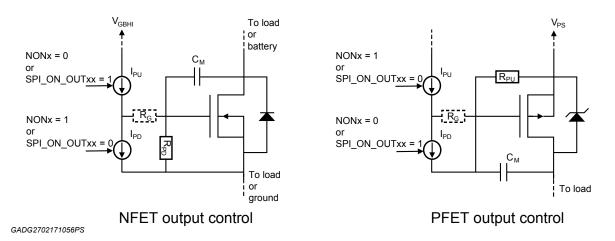
1. All "X" = don't care.

5.4.4 Gate charge/discharge currents

During normal operation external FET is actively switched ON/OFF by means of a pull up/pull down current source, as shown in Figure 12.

Figure 12. Output pre-driver control

Ratings: C_M = 50 V for 12 V systems, 100 V for 24 V systems.



The pull up/pull down currents can be programmed via SPI through the GCC_config_xx bit, as shown in the table below:

GCC_config_xx	I _{PU} / I _{PD} [mA]				
00	Limited by external resistor (R_G)				
00	Internally clamped to I _{Ch0Gx} /I _{DCh0Gx}				
01	20				
10	5				
11	1				

Table 14. Selection of gate charge/discharge currents

In case GCC_config_xx is programmed "0b00", an external resistor RG is required for protecting the transistor gate against excessive current: the resistor must be mounted in series on the IPU / IPD path, as shown in Figure 12. However, to prevent charge pump stress, L9945 internally limits the maximum charge/discharge current to ICh0Gx/IDCh0Gx (refer to Table 15).

External measures have to be taken to keep the external MOS reliably OFF in case of output three-state. For external NMOS a gate pull down resistor RPD is needed and for external PMOS a gate pull up resistor RPU is necessary (refer to Figure 12).

In order to improve EMI behavior, an external Miller capacitor CM can be mounted between transistor gate and drain. Value of this capacitor depends on:

- The switching frequency required by the application;
- The programmed charge/discharge current.

The AN "How To Improve EMI Behavior In Switching Applications" provides a guideline for C_M selection. It also helps choosing the right value for IPU/IPD in order to reduce EMI.

5.4.5 Internal and external clamping

The device guarantees a maximum gate to source voltage of 20 V by means of an internal clamping circuitry which limits the overdrive. However, such a clamp is not intended as a protection against external spikes or failures (STB/STG).

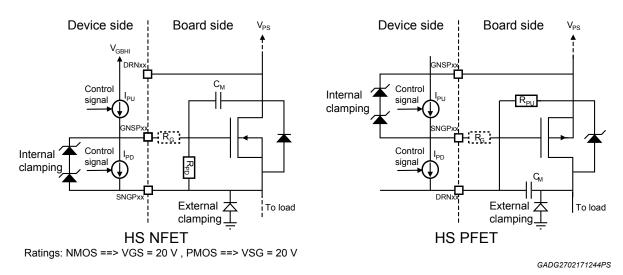
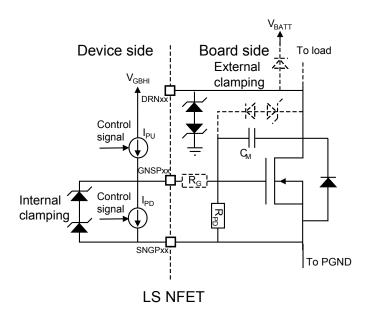


Figure 13. Clamping for HS configuration

Figure 13 shows the recommended clamping for the external FETs used in HS configuration. The internal clamping is meant to protect against overdrive but is not intended to be a recirculation path for the current. An external freewheeling diode is needed for inductive switching loads.



GADG2702171519PS

Figure 14 shows the recommended clamping solutions for the LS configuration. Voltage on the DRNx pin has to be limited to prevent component damage. A suppressor circuit can be used to clamp the voltage on DRNx pin (AMR is 60 V). For the freewheeling of inductive loads:

- A Zener feedback to the gate can be a solution to allow active freewheeling;
- A diode on DRNx pin can be used to allow passive freewheeling towards battery.

5.4.6 Electrical characteristics

57/

The table below lists the electrical characteristics for the output pre-drivers.

Note: $T_j = T_{j_op}$; $V_{VPS_UV} < V_{VPS} < 60$ V, all supplies are independent; 4.5 V < VDD5 < 5.5 V; 3.0 V < VIO < 5.5 V, unless otherwise noted. A current flowing out of L9945 has minus (-) sign; a current flowing into L9945 has plus (+) sign. Charge currents turn ON the NMOS and OFF the PMOS. Discharge currents turn OFF the NMOS and ON the PMOS.

Table 15.	Output	pre-driver	stages e	electrical	characteristics
-----------	--------	------------	----------	------------	-----------------

Symbol	Parameter	Test condition	Min.	Тур.	Max.	Unit
V _{GNSP} -V _{SNGP}	Gate Output voltage (Reversed for PMOS)	-	10	-	14	V
1	Gate charge current NMOS		-1.88	-	-1.1	mA
I _{Ch3Gx}	Gate charge current PMOS	GCC[1:0] = [1, 1]	-1.85	-	-0.55	mA
I _{Ch2Gx}	Gate charge current NMOS and PMOS	GCC[1:0] = [1, 0]	-8.6	-	-4	mA
I _{Ch1Gx}	Gate charge current NMOS and PMOS	GCC[1:0] = [0, 1]	-32.4	-	-19.6	mA
la sa	Gate charge current NMOS	GCC[1:0] = [0, 0]	-100	-	-40	mA
I _{Ch0Gx}	Gate charge current PMOS	GCC[1.0] = [0, 0]	-77	-	-43.5	mA
I _{DCh3Gx}	Gate discharge current NMOS and PMOS	GCC[1:0] = [1, 1]	0.75	-	1.9	mA
I _{DCh2Gx}	Gate discharge current NMOS and PMOS	GCC[1:0] = [1, 0]	3.8	-	7.4	mA
I _{DCh1Gx}	Gate discharge current NMOS and PMOS	GCC[1:0] = [0, 1]	16.8	-	27.4	mA
I _{DCh0Gx}	Gate discharge current NMOS and PMOS	GCC[1:0] = [0, 0]	55	-	101	mA
T _{sw_GC}	Delay to switch from GCC[a,b] to GCC[c,d]	-	-	-	0.1	μs

Unit

mΑ

nF

μs

μs

mA

μΑ

μA

μA

mV

Max.

-

1.5

1.5

2

10

10

10

100

Тур.

_

_

_

_

-

_

_

Min.

40

0.1

_

_

-10

-10

-10

5.5 H-Bridge

is on

The pre-drivers can be configured into two independent H-Bridges. In this configuration Channels 1-4 are used for H-Bridge 1, while Channels 5-8 are used for H-bridge 2.

V SNGPx = 0 V to 28 V

Test condition

Tested at VPS > 7.5 V and output shorted to

test condition: 0.1 nF checked for LS/HS config

GNSP-SNGP voltage requirements < 20 V in

case of external P-channel (Gate to SNGPx) POR or NRES active; V DRNx = 0 V to 28 V

POR or NRES active or Normal mode;

The AN5311 "L9945 in H-Bridge configuration" covers all the main aspects of H-Bridge configuration.

GND

(switch)

test condition: 0.1 nF

guaranteed by design

checked for LS/HS config (switch)

The device can handle up to two H-bridge. There are two possible configurations which can co-exist:

- **H-Bridge 1**: it involves channels 1 (HS), 2 (HS), 3 (LS) and 4 (LS) and can be activated by setting **HB1_config = 1**
- H-Bridge 2: it involves channels 5 (HS), 6 (HS), 7 (LS) and 8 (LS) and can be activated by setting HB2_config = 1

Configurations above are automatically applied once the HBx_config bit is set.

The **N_P_config_xx** bit set the MOSFET type (NMOS, PMOS) used in the H-bridge high-side. For H-bridge 2, **EN6** must be set high to enable channel 6.

5.5.1 H-Bridge driving modes

The H-Bridge must be controlled via the external NONx pins. Such inputs have different meanings while in H-Bridge mode:

HB1	HB2	Signal description
NON1	NON5	NPWM – Negative asserted Pulse Width Modulation signal
NON2	NON6	DIR – Direction signal
NON3	NON7	HiZ – High Impedance (all FETs actively switched off, load floating)
NON4	NON8	Not used

Table 16. NONx signals in H-bridge configuration



Symbol

Ipeak

CLOAD

 t_{d_OFF}

td_ON

ICR_CON

ILEAK_Gx

IDRNx

ILEAK S

VGNSP-VSNGP

Parameter

Minimum peak current capability VPS > 7.5V

Equivalent capacitive load to be driven

50% NONx to 50% OFF gate current

50% NONx to 50% ON gate current

Pre-driver Cross conduction current

GNSPx leakage current in tristate

DRNx input leakage current

SNGPx input leakage current

GNSP to SNGP voltage when OFF gate current

Turn ON/OFF delay

Turn OFF/ON delay

HiZ	DIR	NPWM	HBx_AFW	Q1	Q2	Q3	Q4	Load's driving direction
0	0	0	X ⁽¹⁾	OFF	ON	ON	OFF	Reverse
0	0	1	0	OFF	OFF	ON	OFF	Freewheeling (reverse)
0	0	1	1	OFF	OFF	ON	ON	Active freewheeling (reverse)
0	1	0	Х	ON	OFF	OFF	ON	Forward
0	1	1	0	OFF	OFF	OFF	ON	Freewheeling (forward)
0	1	1	1	OFF	OFF	ON	ON	Active freewheeling (forward)
1	Х	Х	Х	OFF	OFF	OFF	OFF	High Impedance

Table 17. Truth table

1. X = don't care.

The freewheeling is performed on low side, as shown in Figure 15. Software brake mode can be performed by setting the active freewheeling bit (**HBx_AFW**).



VBR

Q1

33

GND

(Active) Freewheeling

Q1

GND

low-side (reverse)

CH1

Out1(HB+

СНЗ

CH3_OC

CH1_OC

CH1

Out1(HB+)

CH3

СН3_ОС

Rshunt

Q2

047

Rshunt

NPWM = '0'; DIR = '0'; HBx_AFW='x'; HiZ='0'

VBR

M

Rshunt

Q2

Q.

Rshunt

₫мЪ

CH2

Out2(HB-)

CH4

CH4_OC

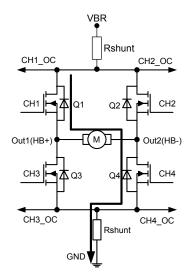
CH2_OC

CH2

Out2(HB-)

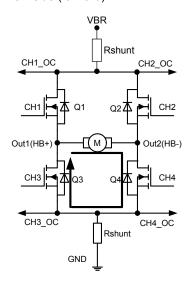
CH4

CH4_OC

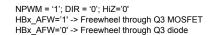


NPWM = '0'; DIR = '1'; HBx_AFW='x'; HiZ='0'

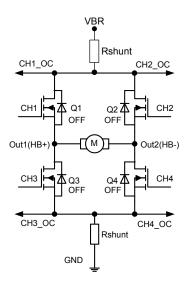
(Active) Freewheeling low-side (forward)



NPWM = '1'; DIR = '1'; HiZ='0' HBx_AFW='1' -> Freewheel through Q3 MOSFET HBx_AFW='0' -> Freewheel through Q3 diode



High impedance



NPWM = 'x'; DIR = 'x'; HBx_AFW='x'; HiZ='1'

GAPG0102161245CFT

5.5.2 H-Bridge diagnostics

H-bridge status can be monitored by reading each channel diagnostic as if they operated independently (refer to Section 6.2 Diagnostics overview). However, different OC sensing strategies can be implemented, as discussed in Overcurrent detection. While in H-Bridge configuration, an extended set of values is available for OFF state diagnostic timer (t_{DIAG}), as shown in H-Bridge OFF state diagnostic timings.

5.5.3 H-bridge dead time

To prevent shoot-through (e.g. Q1 and Q3 ON) it's possible to choose different dead time values for both Hbridges independently. Such parameters are selectable via SPI through the **HBx_dead_time** bit according to the following table.

Table 18. Dead time values

HBx_dead_time [1]	HBx_dead_time [0]	Dead time (min)	Dead time (typ)	Dead time (max)	Unit
0	0	0.5	1	1.5	μs
0	1	1	2	3	μs
1	0	3	4	5	μs
1	1	7	8 (default)	9	μs

Note:

x = H-bridge number

The dead time intervenes in case of H-Bridge direction change, that is upon DIR transitions. The following table describes the output behavior in case of DIR transition.

Table 19. Output response in case of DIR transition

DIR Transition	Q1/Q5 Q2/Q6		Q3/Q7	Q4/Q8	
0 → 1	Turns ON after HBx_dead_time , if NPWM was '0' before DIR switch and did not toggle during dead time	Turns OFF immediately	Turns OFF immediately	Turns ON after HBx_dead_time	
$1 \rightarrow 0$	Turns OFF immediately	Turns ON after HBx_dead_time , if NPWM was '0' before DIR switch and did not toggle during dead time	Turns ON after HBx_dead_time	Turns OFF immediately	

Note:

NPWM should be stable before applying the DIR transition, and it should not be switched during the dead-time due to DIR switch. Otherwise, once dead-time for DIR switch event has expired, the dead-time for NPWM transition will start, resulting in twice the dead-time applied.

Once NPWM has been toggled at t_{NPWM_SWITCH} time instant, DIR input shall not be switched within a defined grey-zone in respect to t_{NPWM_SWITCH} . Grey zone is defined by:

$$t_{GREY} = t_{NPWM}$$
 SWITCH + HBx_dead_time $\pm \frac{5}{f_{MAW}}$

For further information refer to the AN "L9945 DIR switching recommendations".

The dead timers also operate during NPWM switching activity. Transitions are described in the following table.

	DIR = 1	DIR = 0	D	IR = 1	D	IR = 0				
NPWM Transitio n	Q1/Q5	Q2/Q6	Q3/Q7		Q3/Q7		Q3/Q7		c	Q4/Q8
			HBx_AFW = 0	HBx_AFW = 1	HBx_AFW = 0	HBx_AFW = 1				
$0 \rightarrow 1$	Turns OFF after HBx_dead_time if NPWM is still '1'	Turns OFF immediately	Kept OFF	Turns ON after 2*HBx_dead_time if NPWM is still '1'	Kept OFF	Turns ON after 2*HBx_dead_time if NPWM is still '1'				
1 → 0	Turned OFF immediately. Then, it turns ON after HBx_dead_time if NPWM is still '0'	Turns ON after HBx_dead_time if NPWM is still '0'	Kept OFF	Turned OFF immediately	Kept OFF	Turned OFF immediately				

Table 20. Output response in case of NPWM transition

Note:

in case NPWM is switched with a very high frequency, which is incompatible with **HBx_dead_time**, the HS will be kept OFF. This happens because every time NPWM toggles $1 \rightarrow 0$, the HS output is reset to its default value of '0'. However, this condition should be avoided by choosing switching frequency and duty-cycle in order to allow dead-timer to expire after both transitions.

5.5.4 H-bridge disabling

When DIS/NDIS is asserted the H-bridge is disabled and all the pre-drivers are actively turned off. The same behavior is observed when HiZ or NRES is asserted.

NRES	HiZ	HBx_config	DIS	NDIS	H-bridge state
0	0	1	0	1	All 4 MOSFET actively OFF
1	1	1	0	1	All 4 MOSFET actively OFF
1	0	1	0	0	All 4 MOSFET actively OFF
1	0	1	0	1	Normal operation
1	0	1	1	0	All 4 MOSFET actively OFF
1	0	1	1	1	All 4 MOSFET actively OFF

Table 21. H-bridge state for different DIS/NDIS and NRES

HBx_config must not be changed while H-Bridge is operating.

5.5.5 Overcurrent detection strategies for H-Bridge

The over current detection can be performed either by measuring the voltage drop on external shunt resistors or through the Drain to Source Measurement of each transistor (DSM). Each transistor of the H-Bridge can detect overcurrent independently. If an OC event occurs on a channel, the four devices will be actively shut-off and H-Bridge outputs will be three-stated. Diagnostic latches have always to be cleared before re-engaging the H-Bridge after an overcurrent detection. Different scenarios for OC detection are possible:

- OC detection through one shunt resistor mounted on the low-side between SNGPx and PGNDxx pins, as shown in Figure 16. DSM used for OC detection on the HS transistors.
 - To avoid inhomogeneous OC protection over the H-Bridge, OC threshold programmed for HS via DSM must be adapted to the ones programmed on the LS via shunt sensing. OC threshold adaption must account for the RDSon of the HS devices.
- OC detection through two shunt resistors. The first mounted on the low-side between SNGPx and PGNDxx pins, the second mounted on the high-side between GNSPx (PMOS)/DRNx (NMOS) and BATTxx pins (see Figure 16).
 - To avoid inhomogeneous OC threshold for the H-Bridge, the two shunt resistors must be equal and the four OC thresholds must hold the same value.
- OC detection through DSM (see Figure 16)
 - In case the 4 MOSFETs are equal, the 4 OC thresholds must be equal;
 - In case the 2 FETs used on high-side are different from the ones on low-side, a different value for OC threshold must be specified for the HS pair. OC threshold adaption must account for the RDSon of the HS devices.

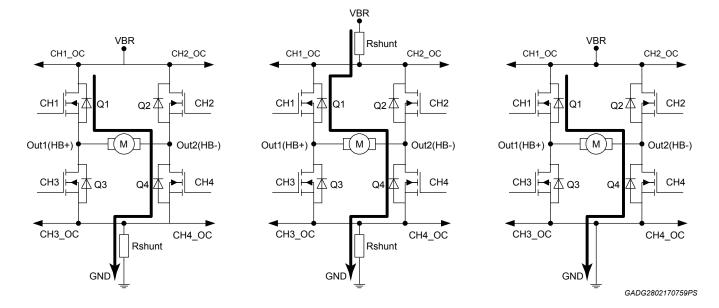


Figure 16. OC detection strategies for H-Bridge: (left) one shunt resistor for LS, DSM for HS; (center) two shunt resistors; (right) DSM

When shunt measurement is selected, current limitation feature is available.

- In case current limitation feature is enabled (HBx_ILIM_en = 1), the comparator on CH3/CH7 is used for current limitation while the one on CH4/CH8 detects OC. In order to guarantee full protection of the load and the FETs, CH4/CH8 overcurrent comparator is enabled even if transistor is OFF phase. Therefore, in case Rshunt is shorted to battery, the OC event will be immediately detected;
- In case current limitation feature is disabled (HBx_ILIM_en = 0), both LS channels are used for OC detection. OC comparators are active only in the ON phase of the transistors.

OC detection timings depend on the selected sensing strategy, as explained in Section 6.3.3 OC sensing strategy. Once an actual OC event has been recognized, behavior depends on the current limitation feature:

- If HBx_ILIM_en = 0, the current limitation feature is disabled and the H-Bridge is three-stated (all FETs actively OFF, load floating);
- If HBx_ILIM_en = 1, the current limitation feature is enabled. The device will limit the current one more time
 after OC threshold crossing and, in case of failure still persisting, the H-Bridge is three-stated (all FETs
 actively OFF, load floating) after t_{OC} + t_{OFF} (refer to Figure 18).

5.5.6 Current limitation for H-Bridge

Current limitation feature is able to limit the maximum current in the load modulating the NPWM signal, as shown in Figure 17. This allows keeping the current of the load below the current limitation threshold (ILIM_th). Current limitation function is available only when shunt measurement is selected and can be activated setting **HBx_ILIM_en** = 1.

Current limitation threshold (I LIM_th) is set by **OC_config_03** [5-0] bit for H-bridge 1 and **OC_config_07** [5-0] bit for H-Bridge 2. Hence, channel 3 is no longer used for OC detection in H-Bridge 1, but it activates the current limitation. The same function is implemented on channel 7 in H-Bridge 2.



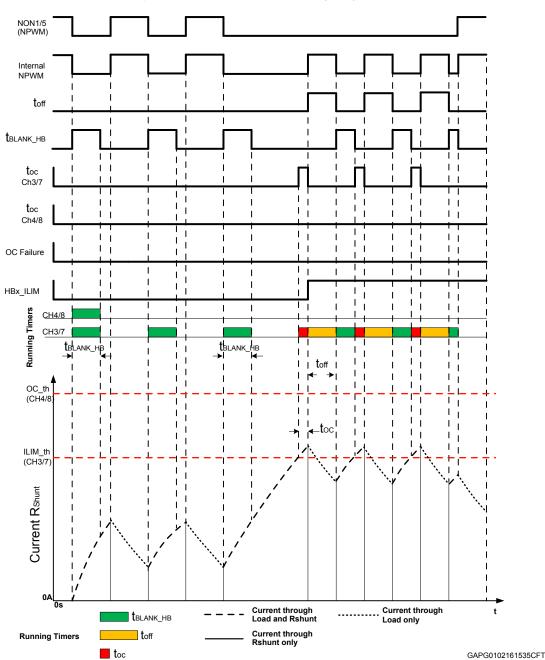


Figure 17. Current limitation timing diagram

If the current stays above the programmed threshold (I_{LIM_th}) longer than t_{OC} , the H-bridge is driven into freewheeling phase (active freewheeling or not, depending on HBx_AFW bit) for a programmable OFF time (t_{OFF}). During t_{OFF} , high-side outputs are actively OFF but low-side outputs remain controlled according to DIR and HBx_AFW values, performing a freewheeling action on the low-side.

Once tooff expires, load current is compared against ILIM_th threshold:

- In case load current is below I_{LIM_th}, normal operation can continue (refer to Figure 17).
- In case current is not below I_{LIM_th}, the high-side channel is turned on for a t_{FIL_ON} + t_{OC} period and then turned off for another t_{OFF} time. Such operation continues until either the current decreases below I_{LIM_th} or the current reaches the overcurrent threshold and H-Bridge is three-stated (all FETs actively OFF, load floating) (refer to Figure 18).

Note: since current limitati

57

since current limitation makes use of shunt sensing, the blanking time programmed for CH3/CH7 has no effect in detection timings. The blanking time has only effect on FETs using DSM.

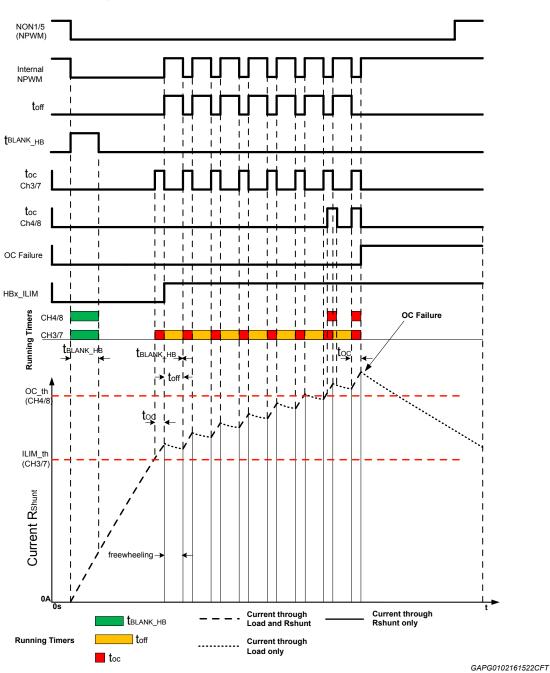


Figure 18. Current limitation iterations (until OC failure)

When current limitation threshold is reached for the first time, a dedicated HBx_ILIM latch is set, indicating that current limitation function has been activated. This latch is cleared on SPI readout. The OFF time interval for current limitation (t_{OFF}) is selectable via SPI according to HBx_toff bit:

Table 22. t_{OFF} selection

HBx_toff [1-0]	Min t _{OFF} value	Typical t _{OFF} value	Max t _{OFF} value	Unit
00	28	31	34	μs
01	42	48	52	μs
10	56	62.5	70	μs
11	110	125	140	μs

5.5.7

H-Bridge OFF state diagnostic timings

The device offers the possibility to select the OFF state diagnostic filter times t_{DIAG} among two different strategies, selectable via **HBx_tdiag_ext_config** bit (refer to Table 23):

- When HBx_tdiag_ext_config = 0, the diagnostic filter time t_{DIAG} selected for CH1 (CH5) is automatically extended to all channels member of the bridge;
- When HBx_tdiag_ext_config = 1, the diagnostic filter time t_{DIAG} must be set individually for each channel member of the bridge.

Regardless of the strategy selected, the t_{DIAG} filter time can be programmed via tdiag_config_xx bit.

Symbol	tdiag_config_xx	Parameter	Min.	Тур.	Max.	Unit	Comment
T _{HB_diag_1}	00	H-Bridge Diag Time 1	10	11.2	12.4	μs	HBx_tdiag_ext_config = 0 (all channels set as CH1/CH5)
T _{HB_diag_2}	01	H-Bridge Diag Time 2	26	28.9	31.8	μs	
T _{HB_diag_3}	10	H-Bridge Diag Time 3	36	40	44	μs	
T _{HB_diag_4}	11	H-Bridge Diag Time 4	46	51.2	56.4	μs	
T _{DIAG_HB_100}	00	H-Bridge Diag Time 1	23	25.6	28.2	μs	HBx_tdiag_ext_config = 1 (channels to be set individually)
T _{DIAG_HB_101}	01	H-Bridge Diag Time 2	55	61.2	67.4	μs	
T _{DIAG_HB_110}	10	H-Bridge Diag Time 3	95	105.6	116.2	μs	
T _{DIAG_HB_111}	11	H-Bridge Diag Time 4	135	150	165	μs	

Table 23. OFF state diagnostic timings for H-Bridge

5.6 Peak & Hold

The pre-drivers can be configured into two independent peak & hold blocks. In this configuration Channels 1,4 are used for Peak & Hold 1, while Channels 2,3 are used for Peak & Hold 2.

The device can handle up to two Peak & Hold branches. There are two possible configurations which can coexist:

- Peak & Hold 1: it involves channels 1 (HS) and 4 (LS) and can be activated by setting PH1_config = 1;
- Peak & Hold 2: it involves channels 2 (HS) and 3 (LS) and can be activated by setting PH2_config = 1.

Configurations above are automatically applied once the **PHx_config** bit is set.

The N_P_config_xx bit set the MOSFET type (NMOS, PMOS) used in the Peak & Hold high-side.

5.6.1 Peak & Hold driving mode

All channels involved in the peak & hold configuration can be driven independently either via the corresponding **NONx** pin or via SPI, depending on **SPI_INPUT_SEL_xx** bit. An external microcontroller shall close the control loop in order to guarantee the desired current profile in the load. The device does not feature any internal current control capability while in peak & hold configuration.

5.6.2 Peak & Hold diagnostics

When in peak & hold configuration, diagnostic is performed independently on each channel, as if a low-side or high-side configuration was applied. The external microcontroller monitoring the device must properly combine the diagnostic information of the high-side channel to the one read on the low-side channel in order to determine the eventual fault type. Refer to Table 36 for the diagnostic codes.

5.6.3 ON state diagnostics

ON state diagnostic latches are updated only when both channels are switched ON, that is, only when the current is supposed to actually flow in the load. In case an OC event occurs on a channel while the other is switched OFF, OC protection is triggered and the external FET is protected, but the diagnostic code of that channel is not updated. OC event will be eventually confirmed once both channels are switched ON (OC or OC pin will be reported).

When in peak & hold configuration, L9945 protects the external FET against overcurrent as in the HS/LS configuration. However, an additional diagnostic code is available for this configuration:

- If an overcurrent event occurs while the output is switching ON (tblank_oc timer still running), an OC pin failure is stored in the diagnostic latches → code "000"
- If an overcurrent event occurs while the output is fully ON (tblank_oc timer expired), an OC failure is stored in the diagnostic latches → code "001"

In order to detect **a short across the load** (SCL) failure, when an OC/OC pin event occurs simultaneously on HS and LS, an OC pin failure is latched for both sides.

5.6.4 OFF state diagnostics

When both HS and LS are commanded OFF by the control signal, an intentional open load occurs on both load pins (refer to Internal regulator for open load (OL) detection). In order to avoid false OL detection, OL fault is masked in this condition. The diagnostic code reported in such case can be selected by programming the **PHx_diag_strategy** bit:

- If PHx_diag_strategy = 0, "No OL/STG/STB failure" is reported → code "110";
- If PHx_diag_strategy = 1, "No diagnostic done" is reported → code "111".

OL detection is guaranteed in case HS and LS have different states. In normal HS/LS configuration, the OFF diagnostic filter timer t_{DIAG} is started every time a channel is switched OFF. In peak & hold configuration, two additional events generate a start condition for t_{DIAG} :

- HS OFF, LS OFF \rightarrow ON;
- LS OFF, HS OFF \rightarrow ON.

Therefore, an eventual OL fault is detected as soon as one of the two transistor is switched ON (after t_{DIAG})

While HS is in the OFF state, if the voltage on the load node rises above VOL, the fast discharge current is activated to prevent false STB detection (refer to OFF state diagnostics and Fast charge/discharge currents). Referring to Figure 19, Table 24 shows the possible faults in peak & hold configuration, along with the diagnostic strategy. Refer to Table 36 for the diagnostic codes.

Note: Table 24 has been compiled under the assumption of all channels starting from "No failure" state (100). Such state is reached during normal operation of the circuit when no failure has been detected by both OFF and ON state diagnostics. Therefore, the diagnostic strategy can be applied if at least one ON/OFF switching cycle has been completed without failures. In case the starting state was "No diagnostic done", the "No failure" state can be replaced with "No OL/STG/STB failure" (110) for OFF state diagnostics and with "No OC failure" (101) for ON state diagnostics. Diagnostic codes follow a priority concept. Diagnostic latches are reset in case of NRES/POR assertion or in case of SPI readout. Refer to Diagnostics overview to understand priority and FSM algorithm.

			Circuit	state				
Fault type	HS	OFF	HS	NC	HS	OFF	HS	ON
	LS	OFF	LS C	DFF	L٤	S ON	LS	ON
	HS	LS	HS	LS	HS	LS	HS	LS
OUT1 STB	STB	No fail	No fail	No fail	STB	No fail ⁽¹⁾	No fail ⁽²⁾	No fail ⁽¹⁾
0011316	516	NO TAIL	NU Idii	NU Iali	510	INO Idii		OC ⁽¹⁾
OUT1 STG	No fail	STG	No fail ⁽¹⁾	STG	No fail	No fail	OC	No fail ⁽²⁾
0011316	NO IAII	310	NO IAII	310	NU Iali	NU IAII	OC pin ⁽³⁾	
OUT1 OL	No diag ⁽⁴⁾	No diag ⁽⁴⁾	No fail	OL	OL	No fail	No fail ⁽²⁾	No fail ⁽²⁾
OUTFOL	No STB/STG/OL ⁽⁴⁾	No STB/STG/OL ⁽⁴⁾	No Iali	UL	UL	No fair	NU Iali V	NU Iali V
OUT4 STB	STB	No fail	No fail ⁽²⁾	No fail	STB	No fail ⁽¹⁾	No fail	OC ⁽³⁾
0014 316	516	NO TAIL		NU Iali	510	INO Idii	NU IAII	OC pin ⁽³⁾
OUT4 STG	No fail	STG	No fail ⁽¹⁾	STG	No fail	No fail ⁽²⁾	No fail ⁽¹⁾	No fail ⁽¹⁾
0014 316	NO IAII	316	NO IAII	316	INU IAII		OC ⁽¹⁾	
OUT4 OL	No diag ⁽⁴⁾	No diag ⁽⁴⁾	No fail	OL	OL	No fail	No fail ⁽¹⁾	No fail ⁽¹⁾
0014 OL	No STB/STG/OL ⁽⁴⁾	No STB/STG/OL ⁽⁴⁾	INU IAII	UL	UL	NU IAII		
OUT1-OUT4 short (SCL)	No diag ⁽⁴⁾	No diag ⁽⁴⁾	No fail	No fail	No fail	No fail	OC nin ⁽³⁾	OC nin ⁽³⁾
0011-0014 Short (30L)	No STB/STG/OL ⁽⁴⁾	No STB/STG/OL ⁽⁴⁾	INU Idii	NU Idli	INU Idli	NU Idli	OC pin ⁽³⁾	OC pin ⁽³⁾

Table 24. Diagnostic strategy for peak & hold configuration

1. Current limited by the load. In case current is greater than the OC threshold, protection is triggered and external FET is shut OFF. However, diagnostic latches are not updated.

2. Current in the shunt resistor is 0 mA. Micro may monitor.

3. Depending on transistor switch ON delay and configured tblank_oc.

4. Depending on **PHx_diag_strategy**.

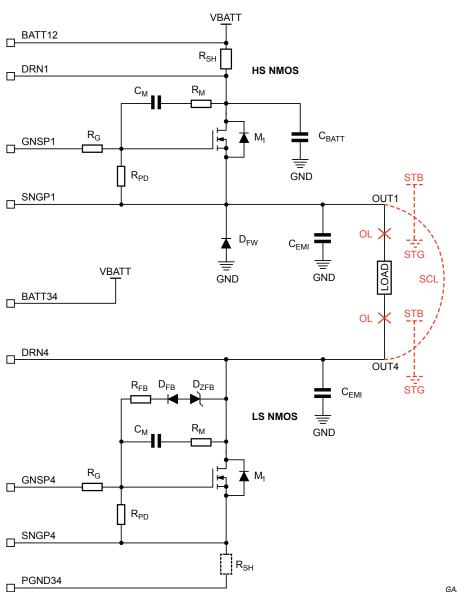


Figure 19. Possible faults in peak & hold configuration

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5.7 Internal oscillator

The L9945 has an internal oscillator providing the timing and control for all device operating functions. The nominal clock frequency is 10 MHz. The oscillator is functional when VDD5 > VPOR.

5.7.1 Spread spectrum

In order to minimize the noise generated by the internal clock signal, the device offers the spread spectrum functionality. Such feature is disabled by default and can be activated by programming the **spread_spectrum** bit.

5.7.2 Internal oscillator electrical characteristics

The table below reports the detailed electrical characteristics of the internal oscillator.

Note: $T_j = T_{j_op}$; $V_{VPS_UV} < V_{VPS} < 60$ V, all supplies are independent; 4.5 V < VDD5 < 5.5 V; 3.0 V < VIO < 5.5 V, unless otherwise noted.

Table 25. Internal oscillator electrical characteristics

Symbol	Parameter	Test condition	Min.	Тур.	Max.	Unit
fMAIN_CLK1	Clock Frequency	-	-	10	-	MHz
tol _{MAIN_CLK}	Tolerance of frequency of internal clock oscillator	Spread spectrum disabled; 4.5 V < $V_{VDD5} \le 36$ V	-7.7	fMAIN_CLK1	7.7	%
^f MOD_range_MAIN	Clock frequency modulation range spread spectrum enabled	-	-4	-	4	%
fmod_main	Spread spectrum modulation frequency	-	-	80	-	kHz

5.8 Digital I/Os

Table 1 reports each pin functionality, along with the pull-up/pull-down implementation. Back supply current into any digital pin is not allowed.

For detailed information about the functionality of the SPI related pins (SCK, SDI, SDO, NCS), refer to Serial Peripheral Interface (SPI). For the electrical characteristics of the SDO output refer to VIO supply pin & SDO pin characteristics.

For detailed information about the functionality of the reset pin (NRES), refer to Reset.

For detailed information about the functionality of the channel control pins (NONx and EN6), refer to Output predrivers.

For detailed information about the functionality of the device disable pins (DIS and NDIS), refer to Disable sources.

5.8.1 Digital I/Os electrical characteristics

The table below lists the electrical characteristics for the digital pins.

Note: $T_j = T_{j_op}$; $V_{VPS_UV} < V_{VPS} < 60$ V, all supplies are independent; 4.5 V < VDD5 < 5.5 V; 3.0 V < VIO < 5.5 V, unless otherwise noted.

Symbol	Parameter	Test condition	Min.	Тур.	Max.	Unit
V _{IN_L}	Low input level	-	-	-	0.75	V
V _{IN_H}	High input level	-	1.75	-	-	V
V _{IN_HYS}	Hysteresis	-	0.1	-	0.5	V
I _{PU}	Input pull-up current source	NONx, NRES, DIS, NCS, SDI, SCK	-30	-	-100	μA
I _{PD}	Input pull-down current sink	NDIS, EN6	30	-	100	μA
t _{FIL_a}	Filter time	Applies to NRES, DIS, NDIS	0.5	-	5.0	μs
V _{NDISL}	Low output level for NDIS bidirectional pin	VDD5 > VPOR; I _{NDIS} = 5 mA	-	-	0.4	V

Table 26. Digital I/Os electrical characteristics

Note: The NDIS bidirectional pin features internal protection against overvoltage when used as output. Such electrical characteristics are listed in the DIS & NDIS pins paragraph.

5.9 Serial Peripheral Interface (SPI)

The device is equipped with a Serial Peripheral Interface implementing a 32-bit, synchronous, full duplex, serial protocol. The interface is used to configure the L9945 by programming its internal registers. Device status and diagnostic information can also be read via SPI.

5.9.1 SPI Quick Look

Table	27.	SPI	quick	look
-------	-----	-----	-------	------

Parameter	Value
Frame length	32 bit or multiple
SPI Mode	Mode 1 (CPOL = 0 & CPHA = 1)
Max Frequency	5 MHz
Protocol	Out of frame
Chip Select Signal Active State	Active Low
Endianess	MSB first

The SPI can work in two different ways: parallel operation and daisy chain. These two methods can co-exist, as shown in Figure 20, where a parallel communication is implemented between a master device and three subblocks. Two of them are daisy chains while the last one is made of a single device. In the example, three Chip Select (CS) wires are used for communicating with 6 devices.

5.9.2 Parallel operation

In parallel operation the communication is performed between a device, named master and one or more devices, named slaves. The master can start/stop the communication and generates the clock signal. Each slave device has a dedicated chip select (CS) signal, used to address the communication between the master and the selected slave.

5.9.3 Daisy chain

In daisy chain configuration, master device can communicate with several slaves using only one wire for chip select (CS). All the slaves in the daisy chain are selected when the CS is in the active state. The serial output line of every slave is connected to the serial input line of the following device. This means that data shifted out by a device is shifted in the following one. For instance, after each 32 clock chunk, an entire frame is transferred from a slave to another. Example given, if a three devices chain is implemented, after 96 clock pulses, the master will program the slaves by shifting out three different frames (each one made up of 32 bits). The first frame shifted out of the master will reach the last device of the chain, the second frame will reach the mid device while the third frame will be shifted into the first member of the chain (refer to Figure 21).



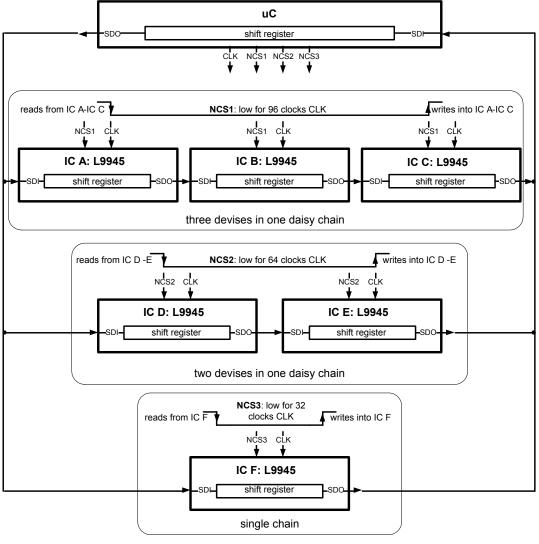
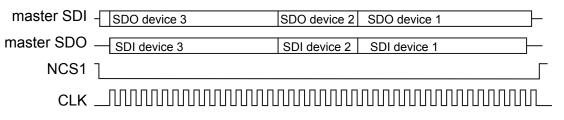


Figure 20. Daisy chain and parallel operation

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Figure 21. Data transfer in daisy chain operation



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5.9.4 SPI electrical characteristics signal and the timing diagram

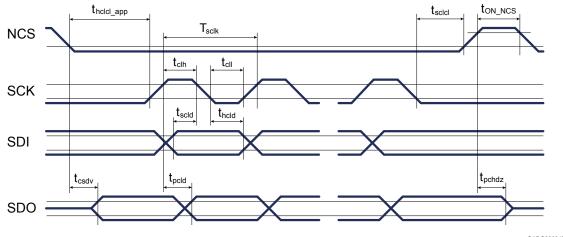
This section contains the electrical characteristics of the SPI signal and the timing diagram.

Note: $T_j = T_{j_op}$; $V_{VPS_UV} < V_{VPS} < 60$ V, all supplies are independent; 4.5 V < VDD5 < 5.5 V; 3.0 V < VIO < 5.5 V, unless otherwise noted.

Symbol	Parameter	Comment	Min.	Max.	Unit
f _{SCK}	Clock frequency (50% duty cycle)	SPI works for all frequencies	0	5	MHz
t _{sdo_trans}	SDO Rise and Fall time	20 pF to 150 pF load	5	35	ns
t _{clh}	Minimum time SCLK=HIGH	-	75	-	ns
t _{cll}	Minimum time SCLK=LOW	-	75	-	ns
t _{pcld}	Propagation delay – incl. Rise/Fall time (SCLK to data at SDO active)	150 pF load	-	50	ns
t _{csdv}	NCS = LOW to output SDO active	150 pF load	-	90	ns
t _{sclch}	SCLK low before NCS low (setup time SCLK to NCS change $\mbox{\rm H/L})$	-	75	-	ns
SCLK change L	/H after NCS = low				
t _{hclcl_app}	SCLK change L/H after NCS = Iow	-	600	-	ns
t _{scld}	SDI input setup time (SCLK change H/L after SDI data valid)	-	15	-	ns
t _{hcld}	SDI input hold time (SDI data hold after SCLK change $\rm H/L)$	-	15	-	ns
t _{sclcl}	SCLK low before NCS high	-	100	-	ns
t _{hclch}	SCLK high after NCS high	-	100	-	ns
t _{pchdz}	NCS L/H to SDO @ high impedance	-	-	75	ns
t _{onNCS}	NCS min. high time	Minimum high time between two consecutive commands	400	-	ns
C _{IN_SPI}	Input capacitance at SDI; SDO; SCLK; NCS	-	-	10	pF
t _{fNCS}	NCS Filter time (Pulses $\leq t_{fNCS}$ will be ignored)	-	10	40	ns
V _{SDOH}	High output level	ISDO = -2 mA	VIO - 0.4 V	-	V
V _{SDOL}	Low output level	ISDO = 3.2 mA	-	0.4	V
		NCS = HIGH; 0 < V _{SDO} \leq V _{IO} - 0.3 V	-5	15	μA
I _{SDO_Leak}	Three state leakage current	NCS = HIGH;	2		
		$V_{SDO} = V_{IO}$	2	30	μA
SDO protection	; 0 V < VIO < 36 V; 0 < VSDO < 36 V; all voltages are in	dependent			
V _{OV_SDO}	Over voltage detection threshold at SDO output	-	VIO + 0.05	VIO + 0.2	V
t _{OV_SDO_fil}	Overvoltage detection analog filter time	-	100	700	ns
t _{OFF_PROT_OV}	Overvoltage detection HS turn OFF/ON time at SDO	-	0.5	5	μs
I _{OVpeak_SDO_HS}	Maximum possible peak reverse current at SDO HS before protection Turn Off	VSDO = 36 V; VIO = 3 V; limited by R _{DSON} only	90	250	mA
Communication	n Check	· ·			
t _{CC}	Communication Timeout	DIS/NDIS released after NRES release.	55	85	ms
t _{CC_INIT}	Deadline for the first communication engagement	DIS/NDIS released before NRES release.	110	165	ms

Table 28. SPI electrical characteristics

Figure 22. SPI timing diagram



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Figure 22 shows that the device has CPOL = 0 and CPHA = 1. During Reset, SDO is forced into a high impedance state and any inputs from SCLK and SDI are ignored.

5.9.5 SPI protocol

The SPI protocol features frames structured as follows:

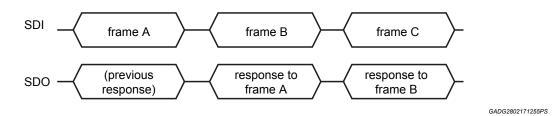
Table 29. SPI protocol

		Comm	and							D	ata					
	MSB															LSB
MOSI	C3	C2	C1	C0	R/W	D26	D25	D24	D23	D22	D21	D20	 D3	D2	D1	Р
MISO	C3	C2	C1	C0	R/W	R26	R25	R24	R23	R22	R21	R20	 R3	R2	R1	Р

The MSB of each frame will be shifted in/out first. Each frame is equipped with an odd parity bit (LSB).

The response is out of frame, so the response to Nth frame will be received when sending the (N+1)th frame.

Figure 23. Out of frame response



The response frame **0x00000000** will be issued in the following cases:

- After a reset event (POR or NRES assertion)
- Invalid command received (see Table 30. SPI MOSI list for the list of available commands)
- Number of SCK pulses not multiple of 32
- Parity error on the received command

Chip select (NCS) assertion without any following SCK pulse is ignored and doesn't generate any error. In order to ignore spurious transitions, NCS input is equipped with a deglitch filter t_{fNCS} .

5.10 SPI MOSI/MISO list

The following paragraph contains the SPI MOSI and MISO list. Each frame consists of 32 bits with odd parity. Protocol is out of frame. The following table contains links to SPI commands that can be sent on MOSI line, along with their description. The corresponding answers issued by L9945 on MISO line are also described and linked on the right columns.

Note:

All MISO default values have been scanned performing read only requests ("R/W" = 1).

MOSI	Request	Answer	MISO
COMMAND 0	Spread spectrum and diagnostic enable,OUT1-8 control, input selection and protection disable	Spread spectrum and diagnostic enable, input selection, protection disable and output voltage status	RESPONSE 0
COMMAND 1	OUT1 configuration and H-Bridge 1 diagnostic time	OUT1 configuration and H-Bridge 1 diagnostic time	RESPONSE 1
COMMAND 2	OUT2 configuration, H-Bridge 1 current limitation timing, BCF selection	OUT2 configuration, H-Bridge 1 current limitation timing, BCF selection	RESPONSE 2
COMMAND 3	OUT3 configuration, H-Bridge 1 current limitation enable and active freewheeling, gate charge/ discharge current override	OUT3 configuration, H-Bridge 1 current limitation enable and active freewheeling, gate charge/ discharge current override	RESPONSE 3
COMMAND 4	OUT4 configuration, P&H1 configuration, H-Bridge 1 enable	OUT4 configuration, P&H1 configuration, H-Bridge 1 enable	RESPONSE 4
COMMAND 5	OUT 5 configuration and H-Bridge 2 diagnostic time	OUT 5 configuration and H-Bridge 2 diagnostic time	RESPONSE 5
COMMAND 6	OUT6 configuration, H-Bridge 2 current limitation timing	OUT6 configuration, H-Bridge 2 current limitation timing	RESPONSE 6
COMMAND 7	OUT7 configuration, H-Bridge 2 current limitation enable and active freewheeling	OUT7 configuration, H-Bridge 2 current limitation enable and active freewheeling	RESPONSE 7
COMMAND 8	OUT8 configuration, P&H2 configuration, H-Bridge 2 enable	OUT8 configuration, P&H2 configuration, H-Bridge 2 enable	RESPONSE 8
COMMAND 9	Diagnostic read and diagnostic pulses	H-Bridge1-2 current limitation latches and channels diagnostic status	RESPONSE 9
COMMAND 10	BIST request and CC enable	BIST & HWSC result and device status	RESPONSE 10
COMMAND 11	Channel 1-4 control signal integrity	Channel 1-4 control signal integrity	RESPONSE 11
COMMAND 12	Channel 5-8 control signal integrity	Channel 5-8 control signal integrity	RESPONSE 12
COMMAND 13	Device status, battery and temperature monitor	Device status, battery and temperature monitor	RESPONSE 13

Table 30. SPI MOSI list

Note:

 $\Delta T = T_{jFET}$: T_j

 T_{jFET} = junction temperature of the external FET T_j = junction temperature of L9945.



5.10.1 COMMAND X frame partitioning

COMMAND 0

Frame partitioning

31	30	29	28	27	26	25	24	23	22	21	20	19	18	17	16	15	14	13	12	11	10	9	8	7	6	5	4	3	2	1	0
	(C		R/W	SPREAD_SPECTRUM	ENABLE_DIAGNOSTIC	SPI_INPUT_SEL_08	SPI_INPUT_SEL_07	SPI_INPUT_SEL_06	SPI_INPUT_SEL_05	SPI_INPUT_SEL_04	SPI_INPUT_SEL_03	SPI_INPUT_SEL_02	SPI_INPUT_SEL_01	PROT_DISABLE_08	PROT_DISABLE_07	PROT_DISABLE_06	PROT_DISABLE_05	PROT_DISABLE_04	PROT_DISABLE_03	PROT_DISABLE_02	PROT_DISABLE_01	SPI_ON_OUT_08	SPI_ON_OUT_07	SPI_ON_OUT_06	SPI_ON_OUT_05	SPI_ON_OUT_04	SPI_ON_OUT_03	SPI_ON_OUT_02	SPI_ON_OUT_01	PARITY

Description

Spread spectrum and diagnostic enable,OUT1-8 control, input selection and protection disable

[31:28] C: Command 0

0000

[27] R/W: Bit to read/write configuration

0: Write & request read

1: Request read only

[26] SPREAD_SPECTRUM: Activates or deactivates the spread spectrum functionality

0: Deactivated

1: Activated

- [25] ENABLE_DIAGNOSTIC: Enables or disables the diagnostics for all outputs. When set to "0" diagnostics for all outputs is "No diagnostic done".
 - 0: Diagnostic disable

1: Diagnostic enable

[24] SPI_INPUT_SEL_08: Driving mode selection bit (output driven by SPI or NON)

0: Output controlled via NONx

- 1: Output controlled via SPI
- [23] SPI_INPUT_SEL_07: Driving mode selection bit (output driven by SPI or NON)

0: Output controlled via NONx

1: Output controlled via SPI

[22] SPI_INPUT_SEL_06: Driving mode selection bit (output driven by SPI or NON)

0: Output controlled via NONx

1: Output controlled via SPI

[21] SPI_INPUT_SEL_05: Driving mode selection bit (output driven by SPI or NON)

0: Output controlled via NONx

1: Output controlled via SPI

- [20] SPI_INPUT_SEL_04: Driving mode selection bit (output driven by SPI or NON)0: Output controlled via NONx
 - 1: Output controlled via SPI

- [19] **SPI_INPUT_SEL_03**: Driving mode selection bit (output driven by SPI or NON)
 - 0: Output controlled via NONx
 - 1: Output controlled via SPI

- [18] SPI_INPUT_SEL_02: Driving mode selection bit (output driven by SPI or NON)0: Output controlled via NONx
 - 1: Output controlled via SPI
- [17] SPI_INPUT_SEL_01: Driving mode selection bit (output driven by SPI or NON)
 - 0: Output controlled via NONx
 - 1: Output controlled via SPI
- [16] PROT_DISABLE_08: Protection disable for CH8. As long as the bit is set, CH8 is kept actively OFF0: Output enabled
 - 1: Output OFF
- [15] PROT_DISABLE_07: Protection disable for CH7. As long as the bit is set, CH7 is kept actively OFF0: Output enabled
 - 1: Output OFF
- [14] PROT_DISABLE_06: Protection disable for CH6. As long as the bit is set, CH6is kept actively OFF0: Output enabled
 - 1: Output OFF
- [13] PROT_DISABLE_05: Protection disable for CH5. As long as the bit is set, CH5 is kept actively OFF0: Output enabled
 - 1: Output OFF
- [12] PROT_DISABLE_04: Protection disable for CH4. As long as the bit is set, CH4 is kept actively OFF0: Output enabled
 - 1: Output OFF
- [11] PROT_DISABLE_03: Protection disable for CH3. As long as the bit is set, CH3 is kept actively OFF0: Output enabled
 - 1: Output OFF
- [10] PROT_DISABLE_02: Protection disable for CH2. As long as the bit is set, CH2 is kept actively OFF0: Output enabled
 - 1: Output OFF
- [9] PROT_DISABLE_01: Protection disable for CH1. As long as the bit is set, CH1 is kept actively OFF0: Output enabled
 - 1: Output OFF
- [8] SPI_ON_OUT_08: SPI output control bit (switches ON/OFF the output)
 - 0: Output OFF
 - 1: Output ON
- [7] SPI_ON_OUT_07: SPI output control bit (switches ON/OFF the output)
 - 0: Output OFF
 - 1: Output ON
- [6] SPI_ON_OUT_06: SPI output control bit (switches ON/OFF the output)
 - 0: Output OFF
 - 1: Output ON
- [5] SPI_ON_OUT_05: SPI output control bit (switches ON/OFF the output)
 - 0: Output OFF
 - 1: Output ON



[4] SPI_ON_OUT_04: SPI output control bit (switches ON/OFF the output)

0: Output OFF

1: Output ON

[3] SPI_ON_OUT_03: SPI output control bit (switches ON/OFF the output)0: Output OFF

1: Output ON

[2] **SPI_ON_OUT_02**: SPI output control bit (switches ON/OFF the output)

0: Output OFF 1: Output ON

[1] **SPI_ON_OUT_01**: SPI output control bit (switches ON/OFF the output)

0: Output OFF

1: Output ON

[0] **PARITY**: Parity bit, based on even parity calculation

0: If the number of 1 is odd

1: If the number of 1 is even



Frame partitioning

31	3	80	29	28	27	26	25	24	23	22	21	20	19	18	17	16	15	14	13	12	11	10	9	8	7	6	5	4	3	2	1	0
		С	>		R <u>W</u>			HB1_TDIAG_EXT_CONFIG			OC_READ_01		OC_	_COI	NFIG	6_01				OC_BATT_COMP_01		TBLANK_OC_01		PROT_CONFIG_01	OC_DS_SHUNT_01	DIAG_I_CONFIG_01			N_P_CONFIG_01	LS_HS_CONFIG_01	EN_OUT_01	PARITY

Description:

OUT1 configuration and H-Bridge 1 diagnostic time

- [31:28] C: Command 1
 - 0001
 - [27] R/W: Bit to read/write configuration
 - 0: Write & request read
 - 1: Request read only

[25:26] HB1_DEAD_TIME: H-bridge1 dead time to avoid cross conduction

- 00: 1 µs
- 01: 2 µs
- 10: 4 µs
- 11: 8 µs
- [24] HB1_TDIAG_EXT_CONFIG: Selection of tdiag timers for H-bridge 1. This function only applies when HB1_config = 1

0: H-bridge tdiag timers for HB1. The programmed TDIAG_CONFIG_01 will be extended to CH2. CH3 and CH4.

1: Standard tdiag timers for HB1. The programmed TDIAG_CONFIG_01 is valid only for CH1, while CH2, CH3 and CH4 must be set individually.

[23:22] **TDIAG_CONFIG_01**:

H-bridge 1 OFF state diagnostic blanking/filter timer. This values are valid only when HB1_tdiag_ext_config = 0 & HB1_config = 1.

00: 11.2 µs

- 01: 28.9 µs
- 10: 40 µs
- 11: 51.2 µs

OFF state diagnostic blanking/filter timer for CH1. It is valid for HB1 only when HB1_tdiag_ext_config = 1 & HB1_config = 1

- 00: 25.6 µs
- 01: 61.2 µs
- 10: 105.6 µs
- 11: 150 µs
- [21] OC_READ_01: Selection of the OC threshold to read. Fixed threshold or actual threshold.
 - 0: Read fixed OC threshold
 - 1: Read actual OC threshold



- [20:15] **OC_CONFIG_01**: Selection of over current detection threshold. 6 bit to code for the OC detection threshold See Table 40
- [14:13] OC_TEMP_COMP_01: Over current detection with temperature compensation (see note of Table 30. SPI MOSI list)

00: No OC compensation

01: ΔT < 60 °C

10: ∆T < 40 °C

11: ΔT < 25 °C

[12] **OC_BATT_COMP_01**: Over current detection with battery compensation.

0: Battery compensation de-activated

1: Battery compensation activated

- [11:9] **TBLANK_OC_01**: When DSM is selected, it specifies the OC blanking time to allow VDS settling. When Rshunt is selected, it only determines the assertion of the 'No OC failure' diagnostic code (once expired).
 - 000: 11.1 µs
 - 001: 15.6 µs
 - 010: 20 µs
 - 011: 31.1 µs
 - 100: 42.2 µs
 - 101: 53.3 µs
 - 110: 97.8 µs
 - 111: 142.2 µs
 - [8] PROT_CONFIG_01: Output re-engagement strategy. Specifies how channel reactivation must be performed following an OC event. This bit has no effect for H-Bridge configuration. Behavior in case of HB is always as PROT_CONFIG_01 = '1'. Diagnostics latches have to be cleared in case of OC in order to re-activate the bridge.

0: output re-engagement with control signal switching event

1: output re-engagement after diagnostic readout and control signal switching event

- [7] OC_DS_SHUNT_01: Configures the output measure OC with shunt or by DSM
 - 0: OC with DSM
 - 1: OC with Shunt
- [6] DIAG_I_CONFIG_01: CH1 OL regulator output current capability
 - 0: 100 µA capability
 - 1: 1 mA capability
- [5:4] GCC_CONFIG_01: Selection of gate charge/discharge currents
 - 00: Lim by ext resistor
 - 01: 20 mA
 - 10: 5 mA
 - 11: 1 mA
 - [3] N_P_CONFIG_01: NMOS or PMOS option for HS configuration
 - 0: Output configured for NMOS
 - 1: Output configured for PMOS
 - [2] LS_HS_CONFIG_01: Configures the channel as LS or HS
 - 0: LS configuration
 - 1: HS configuration
 - [1] EN_OUT_01: Enable output 01
 - 0: Output disabled
 - 1: Output enabled



- [0] PARITY: Parity bit, based on even parity calculation
 - 0: If the number of 1 is odd
 - 1: If the number of 1 is even



Frame partitioning

3	1	30	29	28	27	26	25	24	23	22	21	20	19	18	17	16	15	14	13	12	11	10	9	8	7	6	5	4	3	2	1	0
		C	C		R/W	LIB1 TOFF		BATT_FACT_CONFIG	TDIAG CONFIG 02		OC_READ_02		oc_	_COI	NFIG	_02		OC TEMP COMP 03		OC_BATT_COMP_02		TBLANK_OC_02		PROT_CONFIG_02	OC_DS_SHUNT_02	DIAG_I_CONFIG_02	GCC CONFIG 02		N_P_CONFIG_02	LS_HS_CONFIG_02	EN_OUT_02	PARITY

Description:

Output configuration OUT2

- [31:28] C: Command 2
 - 0010
 - [27] **R/W**: Bit to read/write configuration
 - 0: Write & request read
 - 1: Request read only
- [26:25] HB1_TOFF: H-bridge1 off timer during current limitation
 - 00: 31 µs
 - 01: 48 µs
 - 10: 62.5 µs
 - 11: 125 µs
 - [24] BATT_FACT_CONFIG: Selection of the factor used in battery compensation
 - 0: Factor for CV
 - 1: Factor for PV
- [23:22] **TDIAG_CONFIG_02**: OFF state diagnostic blanking/filter timer for output 02. It has no effect if HB1_config =1 & HB1_tdiag_ext_config = 0
 - 00: 25.6 µs
 - 01: 61.2 µs
 - 10: 105.6 µs
 - 11: 150 µs
 - [21] **OC_READ_02**: Selection of the OC threshold to read. Fixed threshold or actual threshold.
 - 0: Read fixed OC threshold

1: Read actual OC threshold

- [20:15] **OC_CONFIG_02**: Selection of over current detection threshold. 6 bit to code for the OC detection threshold See Table 40
- [14:13] OC_TEMP_COMP_02: Over current detection with temperature compensation (see note of Table 30. SPI MOSI list) 00: No OC compensation
 - 01: ΔT < 60 °C
 - 10: ∆T < 40 °C
 - 11: ΔT < 25 °C

[12] OC_BATT_COMP_02: Over current detection with battery compensation

0: Battery compensation de-activated

1: Battery compensation activated

- [11:9] **TBLANK_OC_02**: When DSM is selected, it specifies the OC blanking time to allow VDS settling. When Rshunt is selected, it only determines the assertion of the 'No OC failure' diagnostic code (once expired).
 - 000: 11.1 µs
 - 001: 15.6 µs
 - 010: 20 µs
 - 011: 31.1 µs
 - 100: 42.2 µs
 - 101: 53.3 µs
 - 110: 97.8 µs
 - 111: 142.2 µs
 - [8] PROT_CONFIG_02: Output re-engagement strategy. Specifies how channel reactivation must be performed following an OC event. This bit has no effect for H-Bridge configuration. Behavior in case of HB is always as PROT_CONFIG_02 = '1'. Diagnostics latches have to be cleared in case of OC in order to re-activate the bridge.

0: output re-engagement with control signal switching event

1: output re-engagement after diagnostic readout and control signal switching event

- [7] OC_DS_SHUNT_02: Configures the output measure OC with shunt or by DSM
 - 0: OC with DSM
 - 1: OC with Shunt
- [6] DIAG_I_CONFIG_02: CH2 OL regulator output current capability
- 0: 100 µA capability
 - 1: 1 mA capability
- [5:4] GCC_CONFIG_02: Selection of gate charge/discharge currents
 - 00: Lim by ext resistor
 - 01: 20 mA
 - 10: 5 mA
 - 11: 1 mA
 - [3] N_P_CONFIG_02: NMOS or PMOS option for HS configuration
 - 0: Output configured for NMOS
 - 1: Output configured for PMOS
 - [2] LS_HS_CONFIG_02: Configures the channel as LS or HS
 - 0: LS configuration
 - 1: HS configuration
 - [1] EN_OUT_02: Enable output 02
 - 0: Output disabled
 - 1: Output enabled
 - [0] PARITY: Parity bit, based on even parity calculation
 - 0: If the number of 1 is odd
 - 1: If the number of 1 is even



Frame partitioning

3	1	30	29	28	27	26	25	24	23	22	21	20	19	18	17	16	15	14	13	12	11	10	9	8	7	6	5	4	3	2	1	0
		C	C		R/W	HB1_ILIM_EN	HB1_AFW	GCC_OVERRIDE_CONFIG			OC_READ_03		oc_	_COI	NFIG	i_03				OC_BATT_COMP_03		TBLANK_OC_03		PROT_CONFIG_03	OC_DS_SHUNT_03	DIAG_I_CONFIG_03			N_P_CONFIG_03	LS_HS_CONFIG_03	EN_OUT_03	PARITY

Description:

Output configuration OUT2

- [31:28] **C**: Command 3 0011
 - [27] R/W: Bit to read/write configuration
 - 0: Write & request read
 - 1: Request read only
 - [26] HB1_ILIM_EN: H-bridge1 current limit activation. CH3 OC threshold is used for current limitation, it is only valid for Shunt measurement
 - 0: Current limitation not active
 - 1: Current limitation active
 - [25] HB1_AFW: H-bridge1 active freewheel configuration on LS
 - 0: Passive freewheeling
 - 1: Active freewheeling
 - [24] GCC_OVERRIDE_CONFIG: Selection of the GCC override configuration upon OC detection. It has no effect if GCC[1:0] = '00' (current limited by external resistor)
 - 0: Selective override:
 - 1 mA --> 5 mA
 - 5 mA --> 20 mA
 - 1: Global override:
 - 1 mA --> 20 mA
 - 5 mA --> 20 mA
- [23:22] **TDIAG_CONFIG_03**: OFF state diagnostic blanking/filter timer for output 03. It has no effect if HB1_config =1 & HB1_tdiag_ext_config = 0
 - 00: 25.6 µs
 - 01: 61.2 µs
 - 10: 105.6 µs
 - 11: 150 µs
 - [21] OC_READ_03: Selection of the OC threshold to read. Fixed threshold or actual threshold.
 - 0: Read fixed OC threshold
 - 1: Read actual OC threshold
- [20:15] **OC_CONFIG_03**: Selection of over current detection threshold. 6 bit to code for the OC detection threshold See Table 40



- [14:13] OC_TEMP_COMP_03: Over current detection with temperature compensation (see note of Table 30. SPI MOSI list)
 - 00: No OC compensation
 - 01: ΔT < 60 °C
 - 10: ∆T < 40 °C
 - 11: ΔT < 25 °C
 - [12] OC_BATT_COMP_03: Over current detection with battery compensation
 - 0: Battery compensation de-activated
 - 1: Battery compensation activated
- [11:9] **TBLANK_OC_03**: When DSM is selected, it specifies the OC blanking time to allow VDS settling. When Rshunt is selected, it only determines the assertion of the 'No OC failure' diagnostic code (once expired).
 - 000: 11.1 µs
 - 001: 15.6 µs
 - 010: 20 µs
 - 011: 31.1 µs
 - 100: 42.2 µs
 - 101: 53.3 µs
 - 110: 97.8 µs
 - 111: 142.2 µs
 - [8] PROT_CONFIG_03: Output re-engagement strategy. Specifies how channel reactivation must be performed following an OC event. This bit has no effect for H-Bridge configuration. Behavior in case of HB is always as PROT_CONFIG_03 = '1'. Diagnostics latches have to be cleared in case of OC in order to re-activate the bridge.
 - 0: output re-engagement with control signal switching event
 - 1: output re-engagement after diagnostic readout and control signal switching event
 - [7] OC_DS_SHUNT_03: Configures the output measure OC with shunt or by DSM
 - 0: OC with DSM
 - 1: OC with Shunt
 - [6] DIAG_I_CONFIG_03: CH3 OL regulator output current capability
 - 0: 100 µA capability
 - 1: 1 mA capability
- [5:4] GCC_CONFIG_03: Selection of gate charge/discharge currents
 - 00: Lim by ext resistor
 - 01: 20 mA
 - 10: 5 mA
 - 11: 1 mA
 - [3] N_P_CONFIG_03: NMOS or PMOS option for HS configuration
 - 0: Output configured for NMOS
 - 1: Output configured for PMOS
 - [2] LS_HS_CONFIG_03: Configures the channel as LS or HS
 - 0: LS configuration
 - 1: HS configuration
 - [1] EN_OUT_03: Enable output 03
 - 0: Output disabled
 - 1: Output enabled



- [0] PARITY: Parity bit, based on even parity calculation
 - 0: If the number of 1 is odd
 - 1: If the number of 1 is even



Frame partitioning

3	1	30	29	28	27	26	25	24	23	22	21	20	19	18	17	16	15	14	13	12	11	10	9	8	7	6	5	4	3	2	1	0
		C	C		R/W	HB1_CONFIG	PH1_diag_strategy	PH1_CONFIG			OC_READ_04		OC_	_COI	NFIG	6_04				OC_BATT_COMP_04		TBLANK_OC_04		PROT_CONFIG_04	OC_DS_SHUNT_04	DIAG_I_CONFIG_04			N_P_CONFIG_04	LS_HS_CONFIG_04	EN_OUT_04	PARITY

Description:

OUT4 configuration, P&H1 configuration, H-Bridge 1 enable

[31:28] C: Command 4

0100

[27] $\mathbf{R}/\overline{\mathbf{W}}$: Bit to read/write configuration

0: Write & request read

- 1: Request read only
- [26] HB1_CONFIG: Configures CH1-CH2-CH3-CH4 for H-bridge1 operation
 - 0: H-bridge not configured

1: CH1-CH4 configured as H-bridge

- [25] PH1_DIAG_STRATEGY: OL masking strategy to prevent false OL assertion in P&H1 configuration
 - 0: "No OL/STG /STB" failure reported
 - 1: "No diagnostic done" reported
- [24] PH1_CONFIG: Configures CH1-CH4 for Peak and Hold1 operation
 - 0: Peak and Hold1 not configured
 - 1: Peak and Hold1 configured
- [23:22] **TDIAG_CONFIG_04**: OFF state diagnostic blanking/filter timer for output 04. It has no effect if HB1_config =1 & HB1_tdiag_ext_config = 0
 - 00: 25.6 µs
 - 01: 61.2 µs
 - 10: 105.6 µs
 - 11: 150 µs
 - [21] OC_READ_04: Selection of the OC threshold to read. Fixed threshold or actual threshold.
 - 0: Read fixed OC threshold
 - 1: Read actual OC threshold
- [20:15] **OC_CONFIG_04**: Selection of over current detection threshold. 6 bit to code for the OC detection threshold See Table 40
- [14:13] **OC_TEMP_COMP_04**: Over current detection with temperature compensation (see note of Table 30. SPI MOSI list) 00: No OC compensation
 - 01: ΔT < 60 °C
 - 10: ΔT < 40 °C
 - 11: ΔT < 25 °C

[12] OC_BATT_COMP_04: Over current detection with battery compensation

0: Battery compensation de-activated

1: Battery compensation activated

- [11:9] **TBLANK_OC_04**: When DSM is selected, it specifies the OC blanking time to allow VDS settling. When Rshunt is selected, it only determines the assertion of the 'No OC failure' diagnostic code (once expired).
 - 000: 11.1 µs
 - 001: 15.6 µs
 - 010: 20 µs
 - 011: 31.1 µs
 - 100: 42.2 µs
 - 101: 53.3 µs
 - 110: 97.8 µs
 - 111: 142.2 µs
 - [8] PROT_CONFIG_04: Output re-engagement strategy. Specifies how channel reactivation must be performed following an OC event. This bit has no effect for H-Bridge configuration. Behavior in case of HB is always as PROT_CONFIG_04 = '1'. Diagnostics latches have to be cleared in case of OC in order to re-activate the bridge.

0: output re-engagement with control signal switching event

1: output re-engagement after diagnostic readout and control signal switching event

- [7] OC_DS_SHUNT_04: Configures the output measure OC with shunt or by DSM
 - 0: OC with DSM
 - 1: OC with Shunt
- [6] DIAG_I_CONFIG_04: CH4 OL regulator output current capability
- 0: 100 µA capability
 - 1: 1 mA capability
- [5:4] GCC_CONFIG_04: Selection of gate charge/discharge currents
 - 00: Lim by ext resistor
 - 01: 20 mA
 - 10: 5 mA
 - 11: 1 mA
 - [3] N_P_CONFIG_04: NMOS or PMOS option for HS configuration
 - 0: Output configured for NMOS
 - 1: Output configured for PMOS
 - [2] LS_HS_CONFIG_04: Configures the channel as LS or HS
 - 0: LS configuration
 - 1: HS configuration
 - [1] EN_OUT_04: Enable output 04
 - 0: Output disabled
 - 1: Output enabled
 - [0] PARITY: Parity bit, based on even parity calculation
 - 0: If the number of 1 is odd
 - 1: If the number of 1 is even



Frame partitioning

3	31	30	29	28	27	26	25	24	23	22	21	20	19	18	17	16	15	14	13	12	11	10	9	8	7	6	5	4	3	2	1	0
		(C		R/W		- הנאח הנאח	HB2_TDIAG_EXT_CONFIG	TDIAG CONFIG 05		OC_READ_05		OC_	_COI	NFIG	6_05		OC TEMP COMP OF		OC_BATT_COMP_05		TBLANK_OC_05		PROT_CONFIG_05	OC_DS_SHUNT_05	DIAG_I_CONFIG_05			N_P_CONFIG_05	LS_HS_CONFIG_05	EN_OUT_05	PARITY

Description

OUT 5 configuration and H-Bridge 2 diagnostic time

- [31:28] C: Command 5
 - 0100
 - [27] R/W: Bit to read/write configuration
 - 0: Write & request read
 - 1: Request read only
- [26:25] HB2_DEAD_TIME: CH-bridge2 dead time to avoid cross conduction
 - 00: 1 µs
 - 01: 2 µs
 - 10: 4 µs
 - 11: 8 µs
 - [24] HB2_TDIAG_EXT_CONFIG: Selection of tdiag timers for H-bridge 2. This function only applies when HB2_config = 1 (command 8)

0: H-bridge tdiag timers for HB2. The programmed TDIAG_CONFIG_05 will be extended to

CH6, CH7 and CH8.

1: Standard tdiag timers for HB2. The programmed TDIAG_CONFIG_05 is valid only for CH5,

while CH6, CH7 and CH8 must be set individually.

[23:22] **TDIAG_CONFIG_05**:

H-bridge 2 OFF state diagnostic blanking/filter timer. This values are valid only when HB2_tdiag_ext_config = 0 & HB2_config = 1

- 00: 11.2 µs
- 01: 28.9 µs
- 10: 40 µs
- 11: 51.2 µs

OFF state diagnostic blanking/filter timer for output 05. It has no effect if HB2_config = 1 & HB2_tdiag_ext_config = 1

- 00: 25.6 µs
- 01: 61.2 µs
- 10: 105.6 µs
- 11: 150 µs



[21] OC_READ_05: Selection of the OC threshold to read. Fixed threshold or actual threshold.

0: Read fixed OC threshold

1: Read actual OC threshold

- [20:15] OC_CONFIG_05: Selection of over current detection threshold. 6 bit to code for the OC detection threshold See Table 40
- [14:13] OC_TEMP_COMP_05: Over current detection with temperature compensation (see note of Table 30. SPI MOSI list)

00: No OC compensation

01: ΔT < 60 °C

10: ∆T < 40 °C

11: ΔT < 25 °C

[12] OC_BATT_COMP_05: Over current detection with battery compensation

0: Battery compensation de-activated

1: Battery compensation activated

- [11:9] **TBLANK_OC_05**: When DSM is selected, it specifies the OC blanking time to allow VDS settling. When Rshunt is selected, it only determines the assertion of the 'No OC failure' diagnostic code (once expired).
 - 000: 11.1 µs
 - 001: 15.6 µs
 - 010: 20 µs
 - 011: 31.1 µs
 - 100: 42.2 µs
 - 101: 53.3 µs
 - 110: 97.8 µs
 - 111: 142.2 µs
 - [8] PROT_CONFIG_05: Output re-engagement strategy. Specifies how channel reactivation must be performed following an OC event. This bit has no effect for H-Bridge configuration. Behavior in case of HB is always as PROT_CONFIG_05 = '1'. Diagnostics latches have to be cleared in case of OC in order to re-activate the bridge.

0: output re-engagement with control signal switching event

- 1: output re-engagement after diagnostic readout and control signal switching event
- [7] OC_DS_SHUNT_05: Configures the output measure OC with shunt or by DSM

0: OC with DSM

1: OC with Shunt

- [6] DIAG_I_CONFIG_05: CH5 OL regulator output current capability
 - 0: 100 µA capability
 - 1: 1 mA capability
- [5:4] GCC_CONFIG_05: Selection of gate charge/discharge currents
 - 00: Lim by ext resistor
 - 01: 20 mA
 - 10: 5 mA
 - 11: 1 mA
 - [3] N_P_CONFIG_05: NMOS or PMOS option for HS configuration
 - 0: Output configured for NMOS
 - 1: Output configured for PMOS
 - [2] LS_HS_CONFIG_05: Configures the channel as LS or HS
 - 0: LS configuration
 - 1: HS configuration



- [1] EN_OUT_05: Enable output 05
 - 0: Output disabled

57

- 1: Output enabled
- [0] PARITY: Parity bit, based on even parity calculation
 - 0: If the number of 1 is odd
 - 1: If the number of 1 is even



Frame partitioning

31	30	29	28	27	26	25	24	23	22	21	20	19	18	17	16	15	14	13	12	11	10	9	8	7	6	5	4	3	2	1	0
	(С		R/W	LD3 TOEE		NOT_USED_FIXED_PATTERN	TDIAG CONFIG 06		OC_READ_06		oc_	_COI	NFIG	§_06		OC TEMP OG		OC_BATT_COMP_06		TBLANK_OC_06		PROT_CONFIG_06	OC_DS_SHUNT_06	DIAG_I_CONFIG_06			N_P_CONFIG_06	LS_HS_CONFIG_06	EN_OUT_06	PARITY

Description

OUT2 configuration, H-Bridge 2 current limitation timing

[31:28] **C**: Command 6

0110

- [27] R/W: Bit to read/write configuration
 - 0: Write & request read
 - 1: Request read only
- [26:25] HB2_TOFF: H-bridge2 off timer during current limitation
 - 00: 31 µs
 - 01: 48 µs
 - 10: 62.5 µs
 - 11: 125 µs
 - [24] FIXED_PATTERN

```
0
```

[23:22] **TDIAG_CONFIG_06**: OFF state diagnostic blanking/filter timer for output 06. It has no effect if HB2_config =1 & HB2_tdiag_ext_config = 0.

- 00: 25.6 µs
- 01: 61.2 µs
- 10: 105.6 µs
- 11: 150 µs
- [21] OC_READ_06: Selection of the OC threshold to read. Fixed threshold or actual threshold.
 - 0: Read fixed OC threshold
 - 1: Read actual OC threshold
- [20:15] **OC_CONFIG_06**: Selection of over current detection threshold. 6 bit to code for the OC detection threshold See Table 40
- [14:13] **OC_TEMP_COMP_06**: Over current detection with temperature compensation (see note of Table 30. SPI MOSI list) 00: No OC compensation
 - 01: ΔT < 60 °C
 - 10: ΔT < 40 °C
 - 11: ΔT < 25 °C

[12] OC_BATT_COMP_06: Over current detection with battery compensation

0: Battery compensation de-activated

1: Battery compensation activated

- [11:9] **TBLANK_OC_06**: When DSM is selected, it specifies the OC blanking time to allow VDS settling. When Rshunt is selected, it only determines the assertion of the 'No OC failure' diagnostic code (once expired).
 - 000: 11.1 µs
 - 001: 15.6 µs
 - 010: 20 µs
 - 011: 31.1 µs
 - 100: 42.2 µs
 - 101: 53.3 µs
 - 110: 97.8 µs
 - 111: 142.2 µs
 - [8] PROT_CONFIG_06: Output re-engagement strategy. Specifies how channel reactivation must be performed following an OC event. This bit has no effect for H-Bridge configuration. Behavior in case of HB is always as PROT_CONFIG_06 = '1'. Diagnostics latches have to be cleared in case of OC in order to re-activate the bridge.

0: output re-engagement with control signal switching event

1: output re-engagement after diagnostic readout and control signal switching event

- [7] OC_DS_SHUNT_06: Configures the output measure OC with shunt or by DSM
 - 0: OC with DSM
 - 1: OC with Shunt
- [6] DIAG_I_CONFIG_06: CH6 OL regulator output current capability
- 0: 100 µA capability
 - 1: 1 mA capability
- [5:4] GCC_CONFIG_06: Selection of gate charge/discharge currents
 - 00: Lim by ext resistor
 - 01: 20 mA
 - 10: 5 mA
 - 11: 1 mA
 - [3] N_P_CONFIG_06: NMOS or PMOS option for HS configuration
 - 0: Output configured for NMOS
 - 1: Output configured for PMOS
 - [2] LS_HS_CONFIG_06: Configures the channel as LS or HS
 - 0: LS configuration
 - 1: HS configuration
 - [1] EN_OUT_06: Enable output 06
 - 0: Output disabled
 - 1: Output enabled
 - [0] PARITY: Parity bit, based on even parity calculation
 - 0: If the number of 1 is odd
 - 1: If the number of 1 is even



Frame partitioning

31	30) 29	28	27	26	25	24	23	22	21	20	19	18	17	16	15	14	13	12	11	10	9	8	7	6	5	4	3	2	1	0
		С		R/W	HB2_ILIM_EN	HB2_AFW	FIXED_PATTERN	TDIAG CONFIG 07		OC_READ_07		OC_	_COI	NFIG	6_07		OC TEMP COMP 07		OC_BATT_COMP_07		TBLANK_OC_07		PROT_CONFIG_07	OC_DS_SHUNT_07	DIAG_I_CONFIG_07	CC CONFIG 07		N_P_CONFIG_07	LS_HS_CONFIG_07	EN_OUT_07	PARITY

Description

OUT7 configuration, H-Bridge 2 current limitation enable and active freewheeling

[31:28] C: Command 7

0111

- [27] R/W: Bit to read/write configuration
 - 0: Write & request read
 - 1: Request read only
- [26] HB2_ILIM_EN: H-bridge2 current limit activation. CH7 OC threshold is used for current limitation, only valid with Shunt measurement
 - 0: Current limitation not active
 - 1: Current limitation active
- [25] HB2_AFW: H-bridge2 active freewheel configuration on LS
 - 0: Passive freewheeling
 - 1: Active freewheeling
- [24] FIXED_PATTERN

0

- [23:22] **TDIAG_CONFIG_07**: OFF state diagnostic blanking/filter timer for output 07. It has no effect if HB2_config = 1 & HB2_tdiag_ext_config = 0.
 - 00: 25.6 µs
 - 01: 61.2 µs
 - 10: 105.6 µs
 - 11: 150 µs
 - [21] OC_READ_07: Selection of the OC threshold to read. Fixed threshold or actual threshold.

0: Read fixed OC threshold

1: Read actual OC threshold

[20:15] **OC_CONFIG_07**: Selection of over current detection threshold. 6 bit to code for the OC detection threshold

See Table 40

[14:13] **OC_TEMP_COMP_07**: Over current detection with temperature compensation (see note of Table 30. SPI MOSI list) 00: No OC compensation

01: ΔT < 60 °C

- 10: ΔT < 40 °C
- 11: ΔT < 25 °C

[12] OC_BATT_COMP_07: Over current detection with battery compensation

0: Battery compensation de-activated

1: Battery compensation activated

- [11:9] **TBLANK_OC_07**: When DSM is selected, it specifies the OC blanking time to allow VDS settling. When Rshunt is selected, it only determines the assertion of the 'No OC failure' diagnostic code (once expired).
 - 000: 11.1 µs
 - 001: 15.6 µs
 - 010: 20 µs
 - 011: 31.1 µs
 - 100: 42.2 µs
 - 101: 53.3 µs
 - 110: 97.8 µs
 - 111: 142.2 µs
 - [8] PROT_CONFIG_07: Output re-engagement strategy. Specifies how channel reactivation must be performed following an OC event. This bit has no effect for H-Bridge configuration. Behavior in case of HB is always as PROT_CONFIG_07 = '1'. Diagnostics latches have to be cleared in case of OC in order to re-activate the bridge.

0: output re-engagement with control signal switching event

1: output re-engagement after diagnostic readout and control signal switching event

- [7] OC_DS_SHUNT_07: Configures the output measure OC with shunt or by DSM
 - 0: OC with DSM
 - 1: OC with Shunt
- [6] DIAG_I_CONFIG_07: CH7 OL regulator output current capability
- 0: 100 µA capability
 - 1: 1 mA capability
- [5:4] GCC_CONFIG_07: Selection of gate charge/discharge currents
 - 00: Lim by ext resistor
 - 01: 20 mA
 - 10: 5 mA
 - 11: 1 mA
 - [3] N_P_CONFIG_07: NMOS or PMOS option for HS configuration
 - 0: Output configured for NMOS
 - 1: Output configured for PMOS
 - [2] LS_HS_CONFIG_07: Configures the channel as LS or HS
 - 0: LS configuration
 - 1: HS configuration
 - [1] EN_OUT_07: Enable output 07
 - 0: Output disabled
 - 1: Output enabled
 - [0] PARITY: Parity bit, based on even parity calculation
 - 0: If the number of 1 is odd
 - 1: If the number of 1 is even



Frame partitioning

3	1	30	29	28	27	26	25	24	23	22	21	20	19	18	17	16	15	14	13	12	11	10	9	8	7	6	5	4	3	2	1	0
		(C		R/W	HB2_CONFIG	PH2_diag_strategy	PH2_CONFIG			OC_READ_08		OC_	_COI	NFIG	6_08				OC_BATT_COMP_08		TBLANK_OC_08		PROT_CONFIG_08	OC_DS_SHUNT_08	DIAG_I_CONFIG_08			N_P_CONFIG_08	LS_HS_CONFIG_08	EN_OUT_08	PARITY

Description:

OUT8 configuration, P&H2 configuration, H-Bridge 2 enable

[31:28] C: Command 8

1000

[27] $\mathbf{R}/\overline{\mathbf{W}}$: Bit to read/write configuration

0: Write & request read

- 1: Request read only
- [26] HB2_CONFIG: Configures CH5-CH6-CH7-CH8 for H-bridge2 operation
 - 0: Not H-bridge configured
 - 1: CH5-CH8 configured as H-bridge
- [25] PH2_DIAG_STRATEGY: OL masking strategy to prevent false OL assertion in P&H2 configuration
 - 0: "No OL/STG /STB" failure reported
 - 1: "No diagnostic done" reported
- [24] PH2_CONFIG: Configures CH2-CH3 for Peak and Hold2 operation
 - 0: Peak and Hold2 not configured
 - 1: Peak and Hold2 configured
- [23:22] **TDIAG_CONFIG_08**: OFF state diagnostic blanking/filter timer for output 08. It has no effect if HB2_config = 1 & HB2_tdiag_ext_config = 0.
 - 00: 25.6 µs
 - 01: 61.2 µs
 - 10: 105.6 µs
 - 11: 150 µs
 - [21] OC_READ_08: Selection of the OC threshold to read. Fixed threshold or actual threshold.
 - 0: Read fixed OC threshold
 - 1: Read actual OC threshold
- [20:15] **OC_CONFIG_08**: Selection of over current detection threshold. 6 bit to code for the OC detection threshold See Table 40
- [14:13] **OC_TEMP_COMP_08**: Over current detection with temperature compensation (see note of Table 30. SPI MOSI list) 00: No OC compensation
 - 01: ΔT < 60 °C
 - 10: ΔT < 40 °C
 - 11: ΔT < 25 °C

[12] OC_BATT_COMP_08: Over current detection with battery compensation

0: Battery compensation de-activated

1: Battery compensation activated

- [11:9] **TBLANK_OC_08**: When DSM is selected, it specifies the OC blanking time to allow VDS settling. When Rshunt is selected, it only determines the assertion of the 'No OC failure' diagnostic code (once expired).
 - 000: 11.1 µs
 - 001: 15.6 µs
 - 010: 20 µs
 - 011: 31.1 µs
 - 100: 42.2 µs
 - 101: 53.3 µs
 - 110: 97.8 µs
 - 111: 142.2 µs
 - [8] PROT_CONFIG_08: Output re-engagement strategy. Specifies how channel reactivation must be performed following an OC event. This bit has no effect for H-Bridge configuration. Behavior in case of HB is always as PROT_CONFIG_08 = '1'. Diagnostics latches have to be cleared in case of OC in order to re-activate the bridge.

0: output re-engagement with control signal switching event

1: output re-engagement after diagnostic readout and control signal switching event

- [7] OC_DS_SHUNT_08: Configures the output measure OC with shunt or by DSM
 - 0: OC with DSM
 - 1: OC with Shunt
- [6] DIAG_I_CONFIG_08: CH8 OL regulator output current capability
- 0: 100 µA capability
 - 1: 1 mA capability
- [5:4] GCC_CONFIG_08: Selection of gate charge/discharge currents
 - 00: Lim by ext resistor
 - 01: 20 mA
 - 10: 5 mA
 - 11: 1 mA
 - [3] N_P_CONFIG_08: NMOS or PMOS option for HS configuration
 - 0: Output configured for NMOS
 - 1: Output configured for PMOS
 - [2] LS_HS_CONFIG_08: Configures the channel as LS or HS
 - 0: LS configuration
 - 1: HS configuration
 - [1] EN_OUT_08: Enable output 08
 - 0: Output disabled
 - 1: Output enabled
 - [0] PARITY: Parity bit, based on even parity calculation
 - 0: If the number of 1 is odd
 - 1: If the number of 1 is even



Frame partitioning

3	1	30	29	28	27	26	25	24	23	22	21	20	19	18	17	16	15	14	13	12	11	10	9	8	7	6	5	4	3	2	1	0
		C	C		R/W				FIXE	ED_F	νΑΤΤ	ERN				DIAG_OFF_PULSE_08	DIAG_OFF_PULSE_07	DIAG_OFF_PULSE_06	DIAG_OFF_PULSE_05	DIAG_OFF_PULSE_04	DIAG_OFF_PULSE_03	DIAG_OFF_PULSE_02	DIAG_OFF_PULSE_01	DIAG_ON_PULSE_08	DIAG_ON_PULSE_07	DIAG_ON_PULSE_06	DIAG_ON_PULSE_05	DIAG_ON_PULSE_04	DIAG_ON_PULSE_03	DIAG_ON_PULSE_02	DIAG_ON_PULSE_01	PARITY



Diagnostic pulses

[31:28] C: Command 9

1001

- [27] R/W: Bit to read/write configuration
 0: Write & request read
 1: Request read only
- [26:17] FIXED_PATTERN
 - 0101010101
 - [16] DIAG_OFF_PULSE_08: Diagnostic OFF pulse request on CH80: no pulse
 - 1: OFF pulse
 - [15] DIAG_OFF_PULSE_07: Diagnostic OFF pulse request on CH70: no pulse
 - 1: OFF pulse
 - [14] **DIAG_OFF_PULSE_06**: Diagnostic OFF pulse request on CH6
 - 0: no pulse
 - 1: OFF pulse
 - [13] DIAG_OFF_PULSE_05: Diagnostic OFF pulse request on CH50: no pulse
 - 1: OFF pulse
 - [12] DIAG_OFF_PULSE_04: Diagnostic OFF pulse request on CH40: no pulse
 - 1: OFF pulse
 - [11] DIAG_OFF_PULSE_03: Diagnostic OFF pulse request on CH30: no pulse

1: OFF pulse

- [10] **DIAG_OFF_PULSE_02**: Diagnostic OFF pulse request on CH20: no pulse
 - 1: OFF pulse



- [9] DIAG_OFF_PULSE_01: Diagnostic OFF pulse request on CH10: no pulse
 - 1: OFF pulse
- [8] DIAG_ON_PULSE_08: Diagnostic ON pulse request on CH80: no pulse
 - 1: ON pulse
- [7] DIAG_ON_PULSE_07: Diagnostic ON pulse request on CH70: no pulse
 - 1: ON pulse
- [6] DIAG_ON_PULSE_06: Diagnostic ON pulse request on CH60: no pulse
 - 1: ON pulse
- [5] **DIAG_ON_PULSE_05**: Diagnostic ON pulse request on CH5
 - 0: no pulse
 - 1: ON pulse
- [4] DIAG_ON_PULSE_04: Diagnostic ON pulse request on CH40: no pulse
 - 1: ON pulse
- [3] **DIAG_ON_PULSE_03**: Diagnostic ON pulse request on CH3
 - 0: no pulse
 - 1: ON pulse
- [2] DIAG_ON_PULSE_02: Diagnostic ON pulse request on CH20: no pulse
 - . 1: ON pulse
- [1] DIAG_ON_PULSE_01: Diagnostic ON pulse request on CH1
 - 0: no pulse
 - 1: ON pulse
- [0] PARITY: Parity bit, based on even parity calculation
 - 0: If the number of 1 is odd
 - 1: If the number of 1 is even



Frame partitioning

31	3	30	29	28	27	26	25	24	23	22	21	20	19	18	17	16	15	14	13	12	11	10	9	8	7	6	5	4	3	2	1	0
		С	;		R/W									FIXE	D_F	PATT	ERN										_	CONFIG CC		FIXED PATTERN		PARITY

Description:

BIST request and CC enable

- [31:28] **C**: Command 10
 - 1010
 - [27] R/W: Bit to read/write configuration0: Write & request read
 - 1: Request read only
- [6:5] **BIST_RQ**: Request for BIST and HWSC sequence
 - 00: not allowed => behavior as for "no request"
 - 01: request
 - 10: no request
 - 11: not allowed => behavior as for "no request"
- [4:3] **CONFIG_CC**: Activation or deactivation of communication check
 - 00: not allowed => previous configuration will be maintained
 - 01: CC active
 - 10: CC inactive
 - 11: not allowed => previous configuration will be maintained
- [2:1] FIXED_PATTERN
 - 10
 - [0] **PARITY**: Parity bit, based on even parity calculation
 - 0: If the number of 1 is odd
 - 1: If the number of 1 is even



			С	0	MN	AN	D	11																				I	Fixe	d fr	ame
24	20	20	20	07	00	05	24	00	00	04	20	10	10	47	10	45		10	10	44	10	0	0	7	0	F	4	0	0	4	0
31	30	29	20	21	20	25	24	23	22	21	20	19	10	17	10	15	14	13	12	11	10	9	0	/	0	c	4	3	2	1	0
														0.4		AAA	^ ^														
														UX	DAA	AAA	AA														
Des	crip	otior	1:				C	Chan	nel	1-4 (conti	rol s	igna	l int	egrit	y															
			С	0	ЛМ	AN	D	12																				I	Fixe	d fr	ame
31	30	29	28	27	26	25	24	23	22	21	20	19	18	17	16	15	14	13	12	11	10	9	8	7	6	5	4	3	2	1	0
														0x	CAA	AAA	AB														
								N		- 0																					
Des	crip	otior						Chan	nei	5-8 (conti	OI S	igna	ii int	egrii	y															
			С	0	MN	AN	D	13																				I	Fixe	d fr	ame
31	30	29	28	27	26	25	24	23	22	21	20	19	18	17	16	15	14	13	12	11	10	9	8	7	6	5	4	3	2	1	0
		1			1	1				1			1	0x	DAA	AAA	AA	1							1	1		1			

Description:

Device status, battery and temperature monitor



5.10.2 RESPONSE X frame partitioning

RESPONSE 0

Frame partitioning

3	31	30	29	28	27	26	25	24	23	22	21	20	19	18	17	16	15	14	13	12	11	10	9	8	7	6	5	4	3	2	1	0
		(C		R/W	SPREAD_SPECTRUM	ENABLE_DIAGNOSTIC	SPI_INPUT_SEL_08	SPI_INPUT_SEL_07	SPI_INPUT_SEL_06	SPI_INPUT_SEL_05	SPI_INPUT_SEL_04	SPI_INPUT_SEL_03	SPI_INPUT_SEL_02	SPI_INPUT_SEL_01	PROT_DISABLE_08	PROT_DISABLE_07	PROT_DISABLE_06	PROT_DISABLE_05	PROT_DISABLE_04	PROT_DISABLE_03	PROT_DISABLE_02	PROT_DISABLE_01		OU	TPU	T_Vo	OLTA	\GE[8:1]		PARITY

Description

Spread spectrum and diagnostic enable, input selection, protection disable and output voltage status. Initial OUTPUT_VOLTAGE field value depends on load.

[31:28] C: Response to command 0

Reset: 0000

Reset Condition: -

- [27] R/W: Bit to read/write configuration
 - 0: Write & request read
 - 1: Request read only

Reset: 1

Reset Condition: POR, NRES

- [26] SPREAD_SPECTRUM: Active or deactive the spread spectrum functionality
 - 0: Inactive

1: Active

Reset: 0

Reset Condition: POR, NRES

[25] ENABLE_DIAGNOSTIC: Enable or disable the diagnostics for all outputs. When i to "0" diagnostics for all outputs is "Not Diag Done"

0: Diagnostic disable

1: Diagnostic enable

Reset: 0

Reset Condition: POR, NRES

[24] SPI_INPUT_SEL_08: Driving mode selection bit (output driven by SPI or NON)

0: Output control by NONx

1: Output control by SPI

Reset: 0

Reset Condition: POR, NRES

[23]	SPI_INPUT_SEL_07: Driving mode selection bit (output driven by SPI or NON)
	0: Output control by NONx
	1: Output control by SPI
	Reset: 0
	Reset Condition: POR, NRES
[22]	SPI_INPUT_SEL_06: Driving mode selection bit (output driven by SPI or NON)
	0: Output control by NONx
	1: Output control by SPI
	Reset: 0
	Reset Condition: POR, NRES
[21]	SPI_INPUT_SEL_05: Driving mode selection bit (output driven by SPI or NON)
	0: Output control by NONx
	1: Output control by SPI
	Reset: 0
	Reset Condition: POR, NRES
[20]	SPI_INPUT_SEL_04: Driving mode selection bit (output driven by SPI or NON)
	0: Output control by NONx
	1: Output control by SPI
	Reset: 0
	Reset Condition: POR, NRES
[19]	SPI_INPUT_SEL_03: Driving mode selection bit (output driven by SPI or NON)
	0: Output control by NONx
	1: Output control by SPI
	Reset: 0
	Reset Condition: POR, NRES
[18]	SPI_INPUT_SEL_02: Driving mode selection bit (output driven by SPI or NON)
	0: Output control by NONx
	1: Output control by SPI
	Reset: 0
	Reset Condition: POR, NRES
[17]	SPI_INPUT_SEL_01: Driving mode selection bit (output driven by SPI or NON)
	0: Output control by NONx
	1: Output control by SPI
	Reset: 0
	Reset Condition: POR, NRES
[16]	PROT_DISABLE_08 : Protection disable for CH8. As long as the bit is set, CH8 is kept actively OFF
	0: Output enabled
	1: Output OFF
	Reset: 0
	Reset Condition: POR, NRES
[15]	PROT_DISABLE_07 : Protection disable for CH7. As long as the bit is set, CH7 is kept actively OFF
	0: Output enabled
	1: Output OFF
	Reset: 0
	Reset Condition: POR, NRES

57



[14] PROT_DISABLE_06: Protection disable for CH6. As long as the bit is set, CH6 is kept actively OFF 0: Output enabled 1: Output OFF Reset: 0 Reset Condition: POR, NRES [13] PROT_DISABLE_05: Protection disable for CH5. As long as the bit is set, CH5 is kept actively OFF 0: Output enabled 1: Output OFF Reset: 0 Reset Condition: POR, NRES [12] PROT_DISABLE_04: Protection disable for CH4. As long as the bit is set, CH4 is kept actively OFF 0: Output enabled 1: Output OFF Reset: 0 Reset Condition: POR, NRES [11] PROT_DISABLE_03: Protection disable for CH3. As long as the bit is set, CH3 is kept actively OFF 0: Output enabled 1: Output OFF Reset: 0 Reset Condition: POR, NRES [10] PROT_DISABLE_02: Protection disable for CH2. As long as the bit is set, CH2 is kept actively OFF 0: Output enabled 1: Output OFF Reset: 0 Reset Condition: POR, NRES [9] PROT_DISABLE_01: Protection disable for CH1. As long as the bit is set, CH1 is kept actively OFF 0: Output enabled 1: Output OFF Reset: 0 Reset Condition: POR, NRES [8:1] OUTPUT_VOLTAGE: Output voltage compared to LVT threshold (Low-Side) 0: $V_{OUT} < V_{LVT}$ output ON 1: V_{OUT} > V_{LVT} output OFF Reset: Initial OUTPUT_VOLTAGE field value depends on load Reset Condition: POR, NRES Output voltage compared to VOL threshold (High-Side) 0: VOUT < VOL output OFF 1: VOUT > VOL output ON

Reset: Initial OUTPUT_VOLTAGE field value depends on load

Reset Condition: POR, NRES

Note: The OUTPUT_VOLTAGE[8:1] field value depends on external HW configuration. By default, all channels are configured as LS NMOS. Hence, the default value of this field follows such interpretation.



- [0] PARITY: Parity bit, based on even parity calculation
 - 0: If the number of 1 is odd
 - 1: If the number of 1 is even



Frame partitioning

31	3	30	29	28	27	26	25	24	23	22	21	20	19	18	17	16	15	14	13	12	11	10	9	8	7	6	5	4	3	2	1	0
		С	;		R/W			HB1_TDIAG_EXT_CONFIG			OC_READ_01		OC_	_CO	NFIG	6_01				OC_BATT_COMP_01		T_BLANK_OC_01		PROT_CONFIG_01	OC_DS_SHUNT_01	DIAG_I_CONFIG_01			N_P_CONFIG_01	LS_HS_CONFIG_01	EN_OUT_01	PARITY

Description:

OUT1 configuration and H-Bridge 1 diagnostic time

Reset:

0x1EC00001

- [31:28] C: Response to command 1
 - Reset: 0001
 - Reset Condition: -
 - [27] R/W: Bit to read/write configuration
 - 0: Write & request read
 - 1: Request read only
 - Reset: 1

Reset Condition: POR, NRES

[26:25] HB1_DEAD_TIME: H-bridge 1 dead time to avoid cross conduction

- 00: 1 µs
- 01: 2 µs
- 10: 4 µs
- 11: 8 µs
- Reset: 11

Reset Condition: POR, NRES

[24] HB1_TDIAG_EXT_CONFIG: Selection of tdiag timers for H-bridge 1. This function only applies when HB1_config = 1

0: H-bridge tdiag timers for HB1. The programmed TDIAG_CONFIG_01 will be extended to

CH2, CH3 and CH4

1: Standard tdiag timers for HB1. The programmed TDIAG_CONFIG_01 is valid only for CH1,

while CH2, CH3 and CH4 must be set individually.

Reset: 0

Reset Condition: POR, NRES

[23:22] **TDIAG_CONFIG_01:**

H-bridge 1 OFF state diagnostic blanking/filter timer. This values are valid only when HB1_tdiag_ext_config = 0 & HB1_config = 1 00: 11.2 μs 01: 28.9 μs

- 10: 40 µs
- 11: 51.2 µs

OFF state diagnostic blanking/filter timer for CH1. It is valid for HB1 only when HB1_tdiag_ext_config = 1 & HB1_config = 1 00: 25.6 µs

- 01: 61.2 µs
- 10: 105.6 µs
- 11: 150 µs
- Reset: 11

Reset Condition: POR, NRES

[21] **OC_READ_01**: Selection of the OC threshold to read. Fixed threshold or actual threshold

- 0: Read fixed OC threshold
- 1: Read actual OC threshold
- Reset: 0
- Reset Condition: POR, NRES

[20:15] OC_CONFIG_01: Selection of over current detection threshold. 6 bit to code for the OC detection threshold

- See Table 40
- Reset: 000000

Reset Condition: POR, NRES

[14:13] OC_TEMP_COMP_01: Over current detection with temperature compensation (see note of Table 30. SPI MOSI list)

- 00: No OC compensation 01: ΔT < 60 °C
- 10: ∆T < 40 °C
- 11: ∆T < 25 °C

Reset: 00

Reset Condition: POR, NRES

[12] OC_BATT_COMP_01: Over current detection with battery compensation

0: Battery compensation de-activated

1: Battery compensation activated

Reset: 0



000: 11.1 μs 001: 15.6 μs 010: 20 μs 011: 31.1 μs 100: 42.2 μs 101: 53.3 μs 110: 97.8 μs 111: 142.2 μs Reset: 000 Reset Condition: POR, NRES

[11:9] TBLANK_OC_01: When DSM is selected, it specifies the OC blanking time to allow VDS settling. When Rshunt is selected, it

[8] **PROT_CONFIG_01**: Output re-engagement strategy. Specifies how channel reactivation must be performed following an OC event

0: output re-engagement with control signal switching event

1: output re-engagement after diagnostic readout and control signal switching event

only determines the assertion of the 'No OC failure' diagnostic code (once expired).

Reset: 0

Reset Condition: POR, NRES

[7] OC_DS_SHUNT_01: Configures the output measure OC with shunt or by DSM

0: OC with DSM

1: OC with Shunt

Reset: 0

Reset Condition: POR, NRES

[6] DIAG_I_CONFIG_01: CH1 OL regulator output current capability

0: 100 µA capability

1: 1 mA capability

Reset: 0

Reset Condition: POR, NRES

[5:4] GCC_CONFIG_01: Selection of gate charge/discharge currents

00: Lim by ext resistor

01: 20 mA

10: 5 mA

11: 1 mA

Reset: 00

Reset Condition: POR, NRES

[3] **N_P_CONFIG_01**: NMOS or PMOS option for HS configuration

0: LS configuration

1: HS configuration

Reset: 0

Reset Condition: POR, NRES

[2] $LS_HS_CONFIG_01$: Configures the channel as LS or HS

0: LS configuration

1: HS configuration

Reset: 0



[1] EN_OUT_01: Enable output 01

0: Output disabled

1: Output enabled

Reset: 0

57

Reset Condition: POR, NRES

[0] PARITY: Parity bit, based on even parity calculation

0: If the number of 1 is odd

1: If the number of 1 is even

Reset: 1



Frame partitioning

31 30 29 28	3 27	26 25	24	23 22	21	20 19 18 1	7 16 15	14 13	12	11 1	09	8	7	6	54	3	2	1	0
С	R/W	HB1_TOFF	BATT_FACT_CONFIG	TDIAG_CONFIG_02	OC_READ_02	OC_CONF	-IG_02	OC_TEMP_COMP_02	OC_BATT_COMP_02			PROT_CONFIG_02	OC_DS_SHUNT_02	DIAG_I_CONFIG_02	GCC_CONFIG_02	N_P_CONFIG_02	LS_HS_CONFIG_02	EN_OUT_02	PARITY
Description:			0	UT2 co	nfigu	ration, H-Bridg	ge 1 curre	ent limita	ation	timing	, BCF	sele	ectio	n					
Reset:			0:	<2EC00	001														
	Rese Rese	esponse t t: 0010 t Conditio Bit to rea	on: -			n													
	0: Wr 1: Re Rese	ite & request rea	uest i ad on	read ly		וונ													
[26:25]	HB1_ 00: 3 01: 4 10: 6 11: 12 Rese	_ TOFF : Η 1 μs 8 μs 2.5 μs 25 μs	I-brid	ge1 off ti	mer d	luring current lir	nitation												
[24]	BATT 0: Fa 1: Fa Rese	[_FACT_ ctor for C ctor for P	CON	FIG: Sel	ectior	n of the factor us	sed in batte	ery comp	ensat	ion									
[23:22]	TDIA HB1_ 00: 2: 01: 6 10: 1 11: 1 Rese	G_CONF _tdiag_ex 5.6 μs 1.2 μs 05.6 μs 50 μs	FIG_(t_cor	92 : OFF s	state	diagnostic blank	king/filter ti	mer for o	utput	02. lt f	nas no	effec	t if H	IB1_d	config =	1&			





[21] OC_READ_02: Selection of the OC threshold to read. Fixed threshold or actual threshold

0: Read fixed OC threshold

1: Read actual OC threshold

Reset: 0

Reset Condition: POR, NRES

[20:15] OC_CONFIG_02: Selection of over current detection threshold. 6 bit to code for the OC detection threshold

See Table 40

Reset: 000000

Reset Condition: POR, NRES

- [14:13] **OC_TEMP_COMP_02**: Over current detection with temperature compensation (see note of Table 30. SPI MOSI list) 00: No OC compensation
 - 01: ΔT < 60 °C
 - 10: ΔT < 40 °C

11: ΔT < 25 °C

Reset: 00

Reset Condition: POR, NRES

[12] OC_BATT_COMP_02: Over current detection with battery compensation

0: Battery compensation de-activated

1: Battery compensation activated

Reset: 0

Reset Condition: POR, NRES

- [11:9] **TBLANK_OC_02**: When DSM is selected, it specifies the OC blanking time to allow VDS settling. When Rshunt is selected, it only determines the assertion of the 'No OC failure' diagnostic code (once expired).
 - 000: 11.1 µs
 - 001: 15.6 µs
 - 010: 20 µs
 - 011: 31.1 µs
 - 100: 42.2 µs
 - 101: 53.3 µs

110: 97.8 µs

111: 142.2 µs

Reset: 000

Reset Condition: POR, NRES

[8] **PROT_CONFIG_02**: Output re-engagement strategy. Specifies how channel reactivation must be performed following an OC event

0: output re-engagement with control signal switching event

1: output re-engagement after diagnostic readout and control signal switching event

Reset: 0

Reset Condition: POR, NRES

[7] OC_DS_SHUNT_02: Configures the output measure OC with shunt or by DSM

0: OC with DSM

1: OC with Shunt

Reset: 0



[6] DIAG_I_CONFIG_02: CH2 OL regulator output current capability

0: 100 µA capability

1: 1 mA capability

Reset: 0

[]

Reset Condition: POR, NRES

[5:4] GCC_CONFIG_02: Selection of gate charge/discharge currents

00: Lim by ext resistor

01: 20 mA

10: 5 mA

11: 1 mA

Reset: 00

Reset Condition: POR, NRES

[3] **N_P_CONFIG_02**: NMOS or PMOS option for HS configuration

- 0: LS configuration
- 1: HS configuration

Reset: 0

Reset Condition: POR, NRES

[2] LS_HS_CONFIG_02: Configures the channel as LS or HS

0: LS configuration

1: HS configuration

Reset: 0

Reset Condition: POR, NRES

- [1] EN_OUT_02: Enable output 02
 - 0: Output disabled
 - 1: Output enabled

Reset: 0

Reset Condition: POR, NRES

[0] **PARITY**: Parity bit, based on even parity calculation

0: If the number of 1 is odd

1: If the number of 1 is even

Reset: 1



Frame partitioning

З	31	30	29	28	27	26	25	24	23	22	21	20	19	18	17	16	15	14	13	12	11	10	9	8	7	6	5	4	3	2	1	0
		(C		R/W	HB1_ILIM_EN	HB1_AFW	GCC_OVERRIDE_CONFIG			OC_READ_03		oc_	_CO1	NFIG	6_03				OC_BATT_COMP_03		T_BLANK_OC_03		PROT_CONFIG_03	OC_DS_SHUNT_03	DIAG_I_CONFIG_03			N_P_CONFIG_03	LS_HS_CONFIG_03	EN_OUT_03	PARITY

Description:

OUT3 configuration, H-Bridge 1 current limitation enable and active freewheeling, gate charge/ discharge current override

Reset

0x3BC00000

[31:28] C: Reponse to command 3

Reset: 0011

Reset Condition: POR, NRES

- [27] $\mathbf{R}/\overline{\mathbf{W}}$: Bit to read/write configuration
 - 0: Write & request read

1: Request read only

Reset: 1

Reset Condition: POR, NRES

[26] HB1_ILIM_EN: H-bridge1 current limit activation. CH3 OC threshold is used for current limitation, it is only valid for Shunt measurement

0: Current limitation not active

1: Current limitation active

Reset: 0

Reset Condition: POR, NRES

[25] HB1_AFW: H-bridge1 active freewheel configuration on LS

0: Freewheel low

1: Active freewheeling

Reset: 1



[24] GCC_OVERRIDE_CONFIG: GCC configuration of the channel, regardless of its channels configuration (LS.HS,H-bridge) must be override to a higher GCC configuration upon OC detection. GCC configuration will remain active until next (NON+SPI) internal turn off transition, in which case the override will be cleared

0: GCC override function upon OC detection:

 $1 \text{ mA} \rightarrow 5 \text{ mA}$

 $5 \text{ mA} \rightarrow 20 \text{ mA}$

1: GCC override function upon OC detection:

 $1 \text{ mA} \rightarrow 20 \text{ mA}$

 $5 \text{ mA} \rightarrow 20 \text{ mA}$

Reset: 1

Reset Condition: POR, NRES

- [23:22] **TDIAG_CONFIG_03**: OFF state diagnostic blanking/filter timer for output 03. It has no effect if HB1_config =1 & HB1_tdiag_ext_config = 0
 - 00: 25.6 µs
 - 01: 61.2 µs
 - 10: 105.6 µs
 - 11: 150 µs
 - Reset: 11

Reset Condition: POR, NRES

- [21] OC_READ_03: Selection of the OC threshold to read. Fixed threshold or actual threshold
 - 0: Read fixed OC threshold
 - 1: Read actual OC threshold

Reset: 0

Reset Condition: POR, NRES

- [20:15] OC_CONFIG_03: Selection of over current detection threshold. 6 bit to code for the OC detection threshold
 - See Table 40

Reset: 000000

Reset Condition: POR, NRES

[14:13] **OC_TEMP_COMP_03**: Over current detection with temperature compensation (see note of Table 30. SPI MOSI list) 00: No OC compensation

01: ΔT < 60 °C

- 10: ΔT < 40 °C
- 11: ΔT < 25 °C

Reset: 00

Reset Condition: POR, NRES

[12] OC_BATT_COMP_03: Over current detection with battery compensation

0: Battery compensation de-activated

1: Battery compensation activated

Reset: 0



000: 11.1 µs

001: 15.6 µs 010: 20 µs 011: 31.1 µs 100: 42.2 µs 101: 53.3 µs 110: 97.8 µs 111: 142.2 µs Reset: 000 Reset Condition: POR, NRES [8] PROT_CONFIG_03: Output re-engagement strategy. Specifies how channel reactivation must be performed following an OC event 0: output re-engagement with control signal switching event 1: output re-engagement after diagnostic readout and control signal switching event Reset: 0 Reset Condition: POR, NRES [7] OC_DS_SHUNT_03: Configures the output measure OC with shunt or by DSM 0: OC with DSM 1: OC with Shunt Reset: 0 Reset Condition: POR, NRES [6] DIAG_I_CONFIG_03: CH3 OL regulator output current capability 0: 100 µA capability 1: 1 mA capability Reset: 0 Reset Condition: POR, NRES [5:4] GCC_CONFIG_03: Selection of gate charge/discharge currents 00: Lim by ext resistor 01: 20 mA 10: 5 mA 11: 1 mA Reset: 00 Reset Condition: POR, NRES [3] N_P_CONFIG_03: NMOS or PMOS option for HS configuration 0: LS configuration 1: HS configuration Reset: 0

[11:9] TBLANK_OC_03: When DSM is selected, it specifies the OC blanking time to allow VDS settling. When Rshunt is selected, it

only determines the assertion of the 'No OC failure' diagnostic code (once expired).

- Reset Condition: POR, NRES
- [2] LS_HS_CONFIG_03: Configures the channel as LS or HS
 - 0: LS configuration
 - 1: HS configuration
 - Reset: 0
 - Reset Condition: POR, NRES



- [1] EN_OUT_03: Enable output 03
 - 0: Output disabled
 - 1: Output enabled

Reset: 0

57

Reset Condition: POR, NRES

[0] PARITY: Parity bit, based on even parity calculation

0: If the number of 1 is odd

1: If the number of 1 is even

Reset: 0



Frame partitioning

3	31	30	29	28	27	26	25	24	23	22	21	20	19	18	17	16	15	14	13	12	11	10	9	8	7	6	5	4	3	2	1	0
		(C		R/W	HB1_CONFIG	PH1_DIAG_STRATEGY	PH1_CONFIG			OC_READ_04		OC_	_COI	NFIG	6_04		OC TEMP ON		OC_BATT_COMP_04		T_BLANK_OC_04		PROT_CONFIG_04	OC_DS_SHUNT_04	DIAG_I_CONFIG_04			N_P_CONFIG_04	LS_HS_CONFIG_04	EN_OUT_04	PARITY

Description:

OUT4 configuration, P&H1 configuration, H-Bridge 1 enable

Reset:

0x48C00001

- [31:28] C: Response to command 4
 - Reset: 0100

Reset Condition: POR, NRES

- [27] R/W: Bit to read/write configuration
 - 0: Write & request read
 - 1: Request read only

Reset: 1

Reset Condition: POR, NRES

[26] HB1_CONFIG: Configures CH1-CH2-CH3-CH4 for H-bridge1 operation

0: Not H-bridge configured

1: CH1-CH4 configured as H-bridge

Reset: 0

Reset Condition: POR, NRES

[25] PH1_DIAG_STRATEGY: OL masking strategy to prevent false OL assertion in P&H1 configuration

0: "No OL/STG /STB" failure reported

1: "No diagnostic done" reported

Reset: 0

Reset Condition: POR, NRES

- [24] PH1_CONFIG: Configures CH1-CH4 for Peak and Hold1 configuration
 - 0: Peak and Hold1 not configured

1: Peak and Hold1 configured

Reset: 0

[23:22] TDIAG_CONFIG_04: OFF state diagnostic blanking/filter timer for output 04. It has no effect if HB1_config =1 & HB1_tdiag_ext_config = 0
00: 25.6 μs
01: 61.2 μs
10: 105.6 μs
11: 150 μs
Reset: 11
Reset Condition: POR, NRES

[21] OC_READ_04: Selection of the OC threshold to read. Fixed threshold or actual threshold

0: Read fixed OC threshold

1: Read actual OC threshold

Reset: 0

Reset Condition: POR, NRES

[20:15] OC_CONFIG_04: Selection of over current detection threshold. 6 bit to code for the OC detection threshold

See Table 40

Reset: 000000

Reset Condition: POR, NRES

[14:13] OC_TEMP_COMP_04: Over current detection with temperature compensation (see note of Table 30. SPI MOSI list)

00: No OC compensation 01: ΔT < 60 °C 10: ΔT < 40 °C 11: ΔT < 25 °C Reset: 00

Reset Condition: POR, NRES

[12] **OC_BATT_COMP_04**: Over current detection with battery compensation

0: Battery compensation de-activated

1: Battery compensation activated

Reset: 0

Reset Condition: POR, NRES

- [11:9] **TBLANK_OC_04**: When DSM is selected, it specifies the OC blanking time to allow VDS settling. When Rshunt is selected, it only determines the assertion of the 'No OC failure' diagnostic code (once expired).
 - 000: 11.1 μs 001: 15.6 μs 010: 20 μs 011: 31.1 μs 100: 42.2 μs 101: 53.3 μs 110: 97.8 μs 111: 142.2 μs Reset: 000





- [8] PROT_CONFIG_04: Output re-engagement strategy. Specifies how channel reactivation must be performed following an OC event
 - 0: output re-engagement with control signal switching event
 - 1: output re-engagement after diagnostic readout and control signal switching event

Reset: 0

57/

Reset Condition: POR, NRES

- [7] OC_DS_SHUNT_04: Configures the output measure OC with shunt or by DSM
 - 0: OC with DSM
 - 1: OC with Shunt

Reset: 0

- Reset Condition: POR, NRES
- [6] DIAG_I_CONFIG_04: CH4 OL regulator output current capability
 - 0: 100 µA capability
 - 1: 1 mA capability

Reset: 0

Reset Condition: POR, NRES

[5:4] GCC_CONFIG_04: Selection of gate charge/discharge currents

- 00: Lim by ext resistor
- 01: 20 mA
- 10: 5 mA
- 11: 1 mA
- Reset: 00

Reset Condition: POR, NRES

- [3] N_P_CONFIG_04: NMOS or PMOS option for HS configuration
 - 0: LS configuration
 - 1: HS configuration

Reset: 0

Reset Condition: POR, NRES

- [2] LS_HS_CONFIG_04: Configures the channel as LS or HS
 - 0: LS configuration
 - 1: HS configuration

Reset: 0

Reset Condition: POR, NRES

- [1] EN_OUT_04: Enable output 04
 - 0: Output disabled
 - 1: Output enabled

Reset: 0

Reset Condition: POR, NRES

- [0] PARITY: Parity bit, based on even parity calculation
 - 0: If the number of 1 is odd

1: If the number of 1 is even

Reset: 0



Frame partitioning

3	1	30	29	28	27	26	25	24	23	22	21	20	19	18	17	16	15	14	13	12	11	10	9	8	7	6	5	4	3	2	1	0
		C	C		R/W			HB2_TDIAG_EXT_CONFIG	TDIAG CONFIG 05		OC_READ_05		oc_	_COI	NFIG	i_05		OC TEMP OF		OC_BATT_COMP_05		T_BLANK_OC_05		PROT_CONFIG_05	OC_DS_SHUNT_05	DIAG_I_CONFIG_05			N_P_CONFIG_05	LS_HS_CONFIG_05	EN_OUT_05	PARITY

Description

OUT 5 configuration and H-Bridge 2 diagnostic time

Reset:

- [31:28] C: Response to command 5
 - Reset: 0101
 - Reset Condition: POR, NRES
 - [27] R/W: Bit to read/write configuration
 - 0: Write & request read
 - 1: Request read only
 - Reset: 1

Reset Condition: POR, NRES

[26:25] HB2_DEAD_TIME: H-bridge2 dead time to avoid cross conduction

0x5EC00000

- 00: 1 µs
- 01: 2 µs
- 10: 4 µs
- 11: 8 µs
- Reset: 11
- Reset Condition: POR, NRES
- [24] **HB2_TDIAG_EXT_CONFIG**: Selection of tdiag timers for H-bridge 2. This function only applies when HB2_config = 1 (command 8)

0: H-bridge tdiag timers for HB2. The programmed TDIAG_CONFIG_05 will be extended to

CH6, CH7 and CH8.

1: Standard tdiag timers for HB2. The programmed TDIAG_CONFIG_05 is valid only for CH5,

while CH6, CH7 and CH8 must be set individually

Reset: 0

Reset Condition: POR, NRES

[23:22] TDIAG_CONFIG_05:

H-bridge 2 OFF state diagnostic blanking/filter timer. This values are valid only when HB2_tdiag_ext_config = 0 & HB2_config = 1 00: 11.2 μs 01: 28.9 μs

- 01. 20.9 µ
- 10: 40 μs 11: 51.2 μs
- 11. 01.2

OFF state diagnostic blanking/filter timer for CH5. It is valid for HB1 only when HB2_tdiag_ext_config = 1 & HB2_config = 1 00: 25.6 µs

- 01: 61.2 µs
- 10: 105.6 µs
- 11: 150 µs
- Reset: 11

Reset Condition: POR, NRES

[21] **OC_READ_05**: Selection of the OC threshold to read. Fixed threshold or actual threshold

- 0: Read fixed OC threshold
- 1: Read actual OC threshold
- Reset: 0
- Reset Condition: POR, NRES

[20:15] OC_CONFIG_05: Selection of over current detection threshold. 6 bit to code for the OC detection threshold

- See Table 40
- Reset: 000000

Reset Condition: POR, NRES

[14:13] OC_TEMP_COMP_05: Over current detection with temperature compensation (see note of Table 30. SPI MOSI list)

00: No OC compensation 01: $\Delta T < 60 \ ^{\circ}C$

- 10: ΔT < 40 °C
- 11: ΔT < 25 °C

Reset: 00

Reset Condition: POR, NRES

[12] OC_BATT_COMP_05: Over current detection with battery compensation

0: Battery compensation de-activated

1: Battery compensation activated

Reset: 0



000: 11.1 µs

001: 15.6 µs 010: 20 µs 011: 31.1 µs 100: 42.2 µs 101: 53.3 µs 110: 97.8 µs 111: 142.2 µs Reset: 000 Reset Condition: POR, NRES [8] PROT_CONFIG_05: Output re-engagement strategy. Specifies how channel reactivation must be performed following an OC event 0: output re-engagement with control signal switching event 1: output re-engagement after diagnostic readout and control signal switching event Reset: 0 Reset Condition: POR, NRES [7] OC_DS_SHUNT_05: Configures the output measure OC with shunt or by DSM 0: OC with DSM 1: OC with Shunt Reset: 0 Reset Condition: POR, NRES [6] DIAG_I_CONFIG_05: CH5 OL regulator output current capability 0: 100 µA capability 1: 1 mA capability Reset: 0 Reset Condition: POR, NRES [5:4] GCC_CONFIG_05: Selection of gate charge/discharge currents 00: Lim by ext resistor 01: 20 mA 10: 5 mA 11: 1 mA Reset: 00 Reset Condition: POR, NRES [3] N_P_CONFIG_05: NMOS or PMOS option for HS configuration 0: LS configuration 1: HS configuration Reset: 0

[11:9] TBLANK_OC_05: When DSM is selected, it specifies the OC blanking time to allow VDS settling. When Rshunt is selected, it

only determines the assertion of the 'No OC failure' diagnostic code (once expired).

- Reset Condition: POR, NRES
- [2] LS_HS_CONFIG_05: Configures the channel as LS or HS
 - 0: LS configuration
 - 1: HS configuration
 - Reset: 0
 - Reset Condition: POR, NRES



- [1] EN_OUT_05: Enable output 05
 - 0: Output disabled
 - 1: Output enabled

Reset: 0

57

Reset Condition: POR, NRES

[0] PARITY: Parity bit, based on even parity calculation

0: If the number of 1 is odd

1: If the number of 1 is even

Reset: 0



Frame partitioning

3	1	30	29	28	27	26	25	24	23	22	21	20	19	18	17	16	15	14	13	12	11	10	9	8	7	6	5	4	3	2	1	0
		(C		R/W	HB3 TOFE		FIXED_PATTERN	TOIAC CONFIC OF		OC_READ_06		OC_	_COI	NFIG	i_06		OC TEMP COMP 06		OC_BATT_COMP_06		T_BLANK_OC_06		PROT_CONFIG_06	OC_DS_SHUNT_06	DIAG_I_CONFIG_06			N_P_CONFIG_06	LS_HS_CONFIG_06	EN_OUT_06	PARITY

Description:

OUT6 configuration, H-Bridge 2 current limitation timing

Reset:

0x6EC00000

- [31:28] C: Response to command 6 Reset: 0101
 - Reset Condition: POR, NRES
 - [27] R/W: Bit to read/write configuration
 - 0: Write & request read
 - 1: Request read only
 - Reset: 1

Reset Condition: POR, NRES

- [26:25] HB2_TOFF: H-bridge2 off timer during current limitation
 - 00: 31 µs
 - 01: 48 µs
 - 10: 62.5 µs
 - 11: 125 µs
 - Reset: 11

Reset Condition: POR, NRES

[24] FIXED_PATTERN

Reset: 0

Reset Condition: POR, NRES

- [23:22] **TDIAG_CONFIG_06**: OFF state diagnostic blanking/filter timer for CH6. It is valid for HB1 only when HB2_tdiag_ext_config = 1 & HB2_config = 1
 - 00: 25.6 μs 01: 61.2 μs
 - 10: 105.6 µs

11: 150 µs

Reset: 11





[21] OC_READ_06: Selection of the OC threshold to read. Fixed threshold or actual threshold

0: Read fixed OC threshold

1: Read actual OC threshold

Reset: 0

Reset Condition: POR, NRES

[20:15] OC_CONFIG_06: Selection of over current detection threshold. 6 bit to code for the OC detection threshold

See Table 40

Reset: 000000

Reset Condition: POR, NRES

- [14:13] **OC_TEMP_COMP_06**: Over current detection with temperature compensation (see note of Table 30. SPI MOSI list) 00: No OC compensation
 - 01: ΔT < 60 °C
 - 10: ∆T < 40 °C

11: ΔT < 25 °C

Reset: 00

Reset Condition: POR, NRES

[12] OC_BATT_COMP_06: Over current detection with battery compensation

0: Battery compensation de-activated

1: Battery compensation activated

Reset: 0

Reset Condition: POR, NRES

- [11:9] **TBLANK_OC_06**: When DSM is selected, it specifies the OC blanking time to allow VDS settling. When Rshunt is selected, it only determines the assertion of the 'No OC failure' diagnostic code (once expired).
 - 000: 11.1 µs
 - 001: 15.6 µs
 - 010: 20 µs
 - 011: 31.1 µs
 - 100: 42.2 µs
 - 101: 53.3 µs

110: 97.8 µs

111: 142.2 µs

Reset: 000

Reset Condition: POR, NRES

[8] **PROT_CONFIG_06**: Output re-engagement strategy. Specifies how channel reactivation must be performed following an OC event

0: output re-engagement with control signal switching event

1: output re-engagement after diagnostic readout and control signal switching event

Reset: 0

Reset Condition: POR, NRES

[7] OC_DS_SHUNT_06: Configures the output measure OC with shunt or by DSM

0: OC with DSM

1: OC with Shunt

Reset: 0



[6] DIAG_I_CONFIG_06: CH6 OL regulator output current capability

0: 100 µA capability

1: 1 mA capability

Reset: 0

L1

Reset Condition: POR, NRES

[5:4] GCC_CONFIG_06: Selection of gate charge/discharge currents

00: Lim by ext resistor

01: 20 mA

10: 5 mA

11: 1 mA

Reset: 00

Reset Condition: POR, NRES

[3] **N_P_CONFIG_06**: NMOS or PMOS option for HS configuration

- 0: LS configuration
- 1: HS configuration

Reset: 0

Reset Condition: POR, NRES

[2] LS_HS_CONFIG_06: Configures the channel as LS or HS

0: LS configuration

1: HS configuration

Reset: 0

Reset Condition: POR, NRES

- [1] EN_OUT_06: Enable output 06
 - 0: Output disabled
 - 1: Output enabled

Reset: 0

Reset Condition: POR, NRES

[0] PARITY: Parity bit, based on even parity calculation

0: If the number of 1 is odd

1: If the number of 1 is even

Reset: 0



Frame partitioning

31 30 29 2	3 27	26	25	24	23 22	21	20	19 1	8 17	' 16	6 15	14	13	12	11	10	9	8	7	6	5	4	3	2	1	0
С	R/W	HB2_ILIM_EN	HB2_AFW	FIXED_PATTERN	TDIAG_CONFIG_07	OC_READ_07		oc_c	ONFI	G_0	7	OC_TEMP_COMP_07		OC_BATT_COMP_07		T_BLANK_OC_07		PROT_CONFIG_07	OC_DS_SHUNT_07	DIAG_I_CONFIG_07	GCC CONFIG 07		N_P_CONFIG_07	LS_HS_CONFIG_07	EN_OUT_07	PARITY
Description:				0	UT7 coi	nfigu	ratio	on, H-ł	Bridg	e 2	curre	ent lim	ita	tion	ena	ble a	and	activ	/e fr	eew	heeli	ing				
Reset:				0	x7AC00	000																				
	Rese Rese R/W : 0: Wr 1: Re Rese	t: 01 t Cor Bit to ite & eques t: 1	11 nditic o rea requ st rea	on: P id/wr uest i ad on	ıly	S urati	on																			
[26]					OR, NRE pridge2 c		t lim	it activa	ation.	CH7		thresh	old	is us	sed f	or cu	rren	t limi	tatio	n. it i	s only	v va	lid fo	r Shi	unt	
	meas	suren	nent																	, -		-				
					n not activ n active	ve																				
	Rese			latior	ractive																					
			nditic	n: P	OR, NRE	s																				
[25]					ge2 active		whe	el conf	iqurat	tion	on LS															
	- 0: Fre				, ,				0																	
	1: Ac	tive f	reew	/heel	ing																					
	Rese	t: 1																								
	Rese	t Cor	nditic	n: P	OR, NRE	S																				
[24]	FIXE	D_P/	ATTE	RN																						
	Rese	t: 0																								
	Rese	t Cor	nditic	on: P	OR, NRE	S																				
[23:22])7 : OFF s nfig = 0	state	diag	nostic ł	blanki	ing/fi	ilter tii	ner fo	r oı	utput	07.	It has	s no	effec	ct if ⊦	IB2_	confi	g =1	&			
	00: 2	5.6 µ	IS																							
	01: 6	1.2 µ	IS																							
	10: 1	05.6	μs																							
	11: 1		6																							
	Rese																									
	Rese	t Cor	nditic	on: P	OR, NRE	S																				





[21] OC_READ_07: Selection of the OC threshold to read. Fixed threshold or actual threshold

0: Read fixed OC threshold

1: Read actual OC threshold

Reset: 0

Reset Condition: POR, NRES

[20:15] OC_CONFIG_07: Selection of over current detection threshold. 6 bit to code for the OC detection threshold

See Table 40

Reset: 000000

Reset Condition: POR, NRES

- [14:13] **OC_TEMP_COMP_07**: Over current detection with temperature compensation (see note of Table 30. SPI MOSI list) 00: No OC compensation
 - 01: ΔT < 60 °C
 - 10: ∆T < 40 °C

11: ΔT < 25 °C

Reset: 00

Reset Condition: POR, NRES

[12] OC_BATT_COMP_07: Over current detection with battery compensation

0: Battery compensation de-activated

1: Battery compensation activated

Reset: 0

Reset Condition: POR, NRES

- [11:9] **TBLANK_OC_07**: When DSM is selected, it specifies the OC blanking time to allow VDS settling. When Rshunt is selected, it only determines the assertion of the 'No OC failure' diagnostic code (once expired).
 - 000: 11.1 µs
 - 001: 15.6 µs

010: 20 µs

- 011: 31.1 µs
- 100: 42.2 µs
- 101: 53.3 µs

110: 97.8 µs

111: 142.2 µs

Reset: 000

Reset Condition: POR, NRES

[8] **PROT_CONFIG_07**: Output re-engagement strategy. Specifies how channel reactivation must be performed following an OC event

0: output re-engagement with control signal switching event

1: output re-engagement after diagnostic readout and control signal switching event

Reset: 0

Reset Condition: POR, NRES

[7] OC_DS_SHUNT_07: Configures the output measure OC with shunt or by DSM

0: OC with DSM

1: OC with Shunt

Reset: 0



[6] DIAG_I_CONFIG_07: CH7 OL regulator output current capability

0: 100 µA capability

1: 1 mA capability

Reset: 0

[]

Reset Condition: POR, NRES

[5:4] GCC_CONFIG_07: Selection of gate charge/discharge currents

00: Lim by ext resistor

01: 20 mA

10: 5 mA

11: 1 mA

Reset: 00

Reset Condition: POR, NRES

[3] N_P_CONFIG_07: NMOS or PMOS option for HS configuration

- 0: LS configuration
- 1: HS configuration

Reset: 0

Reset Condition: POR, NRES

[2] LS_HS_CONFIG_07: Configures the channel as LS or HS

0: LS configuration

1: HS configuration

Reset: 0

Reset Condition: POR, NRES

- [1] EN_OUT_07: Enable output 07
 - 0: Output disabled
 - 1: Output enabled

Reset: 0

Reset Condition: POR, NRES

[0] **PARITY**: Parity bit, based on even parity calculation

0: If the number of 1 is odd

1: If the number of 1 is even

Reset: 0



Frame partitioning

З	31	30	29	28	27	26	25	24	23	22	21	20	19	18	17	16	15	14	13	12	11	10	9	8	7	6	5	4	3	2	1	0
		C	C		R/W	HB2_CONFIG	PH2_DIAG_STRATEGY	PH2_CONFIG	TDIAG CONFIG 08		OC_READ_08		OC_	_COI	NFIG	i_08		OC TEMP ON		OC_BATT_COMP_08		T_BLANK_OC_08		PROT_CONFIG_08	OC_DS_SHUNT_08	DIAG_I_CONFIG_08			N_P_CONFIG_08	LS_HS_CONFIG_08	EN_OUT_08	PARITY

Description

OUT8 configuration, P&H2 configuration, H-Bridge 2 enable

Reset:

0x88C00001

- [31:28] C: Response to command 8
 - Reset: 1000
 - Reset Condition: POR, NRES
 - [27] R/W: Bit to read/write configuration
 - 0: Write & request read
 - 1: Request read only
 - Reset: 1

Reset Condition: POR, NRES

- [26] HB2_CONFIG: Configures CH5-CH6-CH7-CH8 for H-bridge2 operation
 - 0: Not H-bridge configured
 - 1: CH5-CH8 configured as H-bridge
 - Reset: 0

Reset Condition: POR, NRES

- [25] PH2_DIAG_STRATEGY: OL masking strategy to prevent false OL assertion in P&H2 configuration
 - 0: "No OL/STG /STB" failure reported
 - 1: "No diagnostic done" reported
 - Reset: 0

Reset Condition: POR, NRES

- [24] PH2_CONFIG: Configures CH5-CH8 for Peak and Hold2 configuration
 - 0: Peak and Hold2 not configured
 - 1: Peak and Hold2 configured

Reset: 0



[23:22] TDIAG_CONFIG_08: OFF state diagnostic blanking/filter timer for output 02. It has no effect if HB1_config =1 & HB1_tdiag_ext_config = 0 00: 25.6 μs 01: 61.2 μs

- 10: 105.6 µs
- 11: 150 µs
- Reset: 11

Reset Condition: POR, NRES

[21] **OC_READ_08**: Selection of the OC threshold to read. Fixed threshold or actual threshold

0: Read fixed OC threshold

1: Read actual OC threshold

Reset: 0

Reset Condition: POR, NRES

[20:15] **OC_CONFIG_08**: Selection of over current detection threshold. 6 bit to code for the OC detection threshold

See Table 40

Reset: 000000

Reset Condition: POR, NRES

[14:13] OC_TEMP_COMP_08: Over current detection with temperature compensation (see note of Table 30. SPI MOSI list)

00: No OC compensation 01: ΔT < 60 °C 10: ΔT < 40 °C 11: ΔT < 25 °C Reset: 00

Reset Condition: POR, NRES

[12] **OC_BATT_COMP_08**: Over current detection with battery compensation

0: Battery compensation de-activated

1: Battery compensation activated

Reset: 0

000: 11.1 μs 001: 15.6 μs 010: 20 μs

Reset Condition: POR, NRES

[11:9] **TBLANK_OC_08**: When DSM is selected, it specifies the OC blanking time to allow VDS settling. When Rshunt is selected, it only determines the assertion of the 'No OC failure' diagnostic code (once expired).

DS12275 - Rev 7



- [8] PROT_CONFIG_08: Output re-engagement strategy. Specifies how channel reactivation must be performed following an OC event
 - 0: output re-engagement with control signal switching event
 - 1: output re-engagement after diagnostic readout and control signal switching event

Reset: 0

57/

Reset Condition: POR, NRES

- [7] OC_DS_SHUNT_08: Configures the output measure OC with shunt or by DSM
 - 0: OC with DSM
 - 1: OC with Shunt

Reset: 0

- Reset Condition: POR, NRES
- [6] DIAG_I_CONFIG_08: CH8 OL regulator output current capability
 - 0: 100 µA capability
 - 1: 1 mA capability
 - Reset: 0

Reset Condition: POR, NRES

[5:4] GCC_CONFIG_08: Selection of gate charge/discharge currents

- 00: Lim by ext resistor
- 01: 20 mA
- 10: 5 mA
- 11: 1 mA
- Reset: 00

Reset Condition: POR, NRES

- [3] N_P_CONFIG_08: NMOS or PMOS option for HS configuration
 - 0: LS configuration
 - 1: HS configuration
 - Reset: 0

Reset Condition: POR, NRES

- [2] LS_HS_CONFIG_08: Configures the channel as LS or HS
 - 0: LS configuration
 - 1: HS configuration

Reset: 0

Reset Condition: POR, NRES

- [1] EN_OUT_08: Enable output 08
 - 0: Output disabled
 - 1: Output enabled

Reset: 0

Reset Condition: POR, NRES

- [0] PARITY: Parity bit, based on even parity calculation
 - 0: If the number of 1 is odd

1: If the number of 1 is even

Reset: 0



Frame partitioning

31 30	0 2	9 2	28	27	26	25	24	23	22	21	20	19	18	17	16	15	14	13	12	11	10	9	8	7	6	5	4	3	2	1	0
					⊵	⊵	2	2-2	2	12	4	2	2	~	~_ _	-	ا ۲	- -	<u>+</u>	~ _	-	-	0	0_7	0	0	0	0	0	0	≻
	С			RW	HB2_ILIM	HB1_ILIM	DIAG_08_2	DIAG_07_2	DIAG_06_	DIAG_05_2	DIAG_04	DIAG_03	DIAG_02_	DIAG_01_2	DIAG_08_1	DIAG_07_1	DIAG_06_1	DIAG_05_	DIAG_04_1	DIAG_03_	DIAG_02_1	DIAG_01_1	DIAG_08_0	DIAG_07_0	DIAG_06_0	DIAG_05_0	DIAG_04_0	DIAG_03_0	DIAG_02_0	DIAG_01_0	PARITY
					면	면	DIA	DIA	DIA	DIA	DIA	DIA	DIA	DIA	DIA	DIA	DIA	DIA	DIA	DIA	DIA	DIA	DIA	DIA	DIA	DIA	DIA	DIA	DIA	DIA	5
																		1	,		,	1				1					
Descr	ipti	on:					С	OUT	8 coi	nfigu	uratio	on, I	P&H	2 cc	onfigi	urati	on,	H-B	ridg	e 2 e	enat	ble									
Reset	:						0	x99	FFFI	FFE																					
	[31	:28]	C	: Re	espoi	nse t	:o co	mma	and 9	1																					
			F	Rese	t: 10	01																									
			F	Rese	t Coi	nditio	on: P	OR,	NRE	S																					
		[27]	R	R/W :	Bit t	o rea	ad/wr	rite c	onfig	urati	on																				
			0	: Wr	ite &	requ	uest	read																							
			1	: Re	ques	st rea	ad or	nly																							
			F	Rese	t: 1																										
			F	Rese	t Co	nditio	on: P	OR,	NRE	S																					
		[26]							Curre		nitati	on la	atch																		
									activ	е																					
						t limi	tatio	n act	ive																						
				Rese																											
									out F																						
		[25]					-		Curre		nitati	on la	atch																		
									activ	е																					
						t limi	tatio	n act	ive																						
				Rese			_																								
									out F																						
[24	4, 16	5, 8]							nform		n for	CH8																			
									g_8[()]:																					
							failur	e																							
						failu																									
							B fai	liure																							
						failu failur																									
							e failur	~																							
									failu	re																					
							nosti																								
					t: 11 [.]	-	10311	c uoi																							
							on: R	lead	out F	POR	NR	ES																			
									5011	014																					



[23, 15, 7] DIAG_07: Diagnostic information for CH7 diag_7[2] diag_7[1] diag_7[0]: 0 0 0: OC pin failure 0 0 1: OC failure 0 1 0: STG/STB failure 0 1 1: OL failure 1 0 0: no failure 1 0 1: No OC failure 1 1 0: No OL/STG/STB failure 1 1 1: no diagnostic done Reset: 111 Reset Condition: Read out POR, NRES [22, 14, 6] **DIAG_06**: Diagnostic information for CH6 diag_6[2] diag_6[1] diag_6[0]: 0 0 0: OC pin failure 0 0 1: OC failure 0 1 0: STG/STB failure 0 1 1: OL failure 1 0 0: no failure 1 0 1: No OC failure 1 1 0: No OL/STG/STB failure 1 1 1: no diagnostic done Reset: 111 Reset Condition: Read out POR, NRES [21, 13, 5] **DIAG_05**: Diagnostic information for CH5 diag_5[2] diag_5[1] diag_5[0]: 0 0 0: OC pin failure 0 0 1: OC failure 0 1 0: STG/STB failure 0 1 1: OL failure 1 0 0: no failure 1 0 1: No OC failure 1 1 0: No OL/STG/STB failure 1 1 1: no diagnostic done Reset: 111 Reset Condition: Read out POR, NRES



[20, 12, 4] DIAG_04: Diagnostic information for CH4 diag_4[2] diag_4[1] diag_4[0]: 0 0 0: OC pin failure 0 0 1: OC failure 0 1 0: STG/STB failure 0 1 1: OL failure 1 0 0: no failure 1 0 1: No OC failure 1 1 0: No OL/STG/STB failure 1 1 1: no diagnostic done Reset: 111 Reset Condition: Read out POR, NRES [19, 11, 3] DIAG_03: Diagnostic information for CH3 diag_3[2] diag_3[1] diag_3[0]: 0 0 0: OC pin failure 0 0 1: OC failure 0 1 0: STG/STB failure 0 1 1: OL failure 1 0 0: no failure 1 0 1: No OC failure 1 1 0: No OL/STG/STB failure 1 1 1: no diagnostic done Reset: 111 Reset Condition: Read out POR, NRES [18, 10, 2] **DIAG_02**: Diagnostic information for CH2 diag_2[2] diag_2[1] diag_2[0]: 0 0 0: OC pin failure 0 0 1: OC failure 0 1 0: STG/STB failure 0 1 1: OL failure 1 0 0: no failure 1 0 1: No OC failure 1 1 0: No OL/STG/STB failure 1 1 1: no diagnostic done Reset: 111 Reset Condition: Read out POR, NRES



- [17, 9, 1] **DIAG_01**: Diagnostic information for CH1
 - diag_1[2] diag_1[1] diag_1[0]:
 - 0 0 0: OC pin failure
 - 0 0 1: OC failure
 - 0 1 0: STG/STB failure
 - 0 1 1: OL failure
 - 1 0 0: no failure
 - 1 0 1: No OC failure
 - 1 1 0: No OL/STG/STB failure
 - 1 1 1: no diagnostic done
 - Reset: 111
 - Reset Condition: Read out POR, NRES
 - [0] PARITY: Parity bit, based on even parity calculation
 - 0: If the number of 1 is odd
 - 1: If the number of 1 is even
 - Reset: 0
 - Reset Condition: -



Frame partitioning

31	30	29	28	27	26	25	24	23	22	21	20	19	18	17	16	15	14	13	12	11	10	9	8	7	6	5	4	3	2	1	0
	С	;		R/W	EN6_LATCH	EN6_STATE	OV_DIS_LATCH	UV_DIS_STATE	UV_DIS_LATCH	DIS_STATE	DIS_LATCH	NDIS_STATE	NDIS_LATCH	NDIS_OUT_LATCH	CONFIG_CC_STATE	CC_LATCH	BIST_DONE	BIST_DIS	HWSC_DONE	HWSC_DIS	OV_VDD5_STATE	OV_VDD5_LATCH	UV_VDD5_STATE	UV_VDD5_LATCH	N_POR_LATCH	NRES_LATCH	VCP_UV_STATE	VCP_UV_LATCH	VPS_STATE	VPS_LATCH	PARITY

Description:

BIST & HWSC result and device status

Note: the value of DIS, NDIS and EN6 related bit depends on how the microcontroller drives such pins. The value of POR and NRES related bit depends on which event caused the logic reset. The value of BIST and HWSC related bit depends on which event caused the logic reset: self test sequence is not performed in case of POR. In addition, the value of BIST_DONE and HWSC_DONE bit depends on the status of self test sequence at the time instant where the read event occurs. The CC_LATCH is set in case the first SPI communication occurs after the watchdog timer expired. The UV_DIS_LATCH and UV_VDD5_LATCH might be set at startup, depending on the VDD5 ramp slope. It is strongly recommended to perform two consecutive SPI read via COMMAND 10 in order to verify that the relevant faults (eventually latched during startup) are cleared.

- [31:28] C: Response to command 10
 - Reset: 1010

Reset Condition: -

[27] $\mathbf{R}/\overline{\mathbf{W}}$: Bit to read/write configuration

0: Write & request read

1: Request read only

Reset: 1

Reset Condition: POR, NRES

[26] EN6_LATCH: Shows if a deactivation via EN6 pin was detected since last read out (EN6 = LOW)

0: no disable via EN6 detected

1: disable via EN6 detected

Reset: X

Reset Condition: Read out POR

[25] EN6_STATE: Shows if channel 6 is currently disabled by the EN6 input

0: EN disabled

1: EN enabled

Reset: 0

Reset Condition: -

[24] OV_DIS_LATCH: Bit set to 1 (OV filtering expired) if VDD5 overvoltage disable was triggered since last read out (shows also if OV occurs during Reset)

0: no OV disable condition detected

1: OV disable condition detected

Reset: 0



1001	UN DIO OTATE: Oberra 16the device is summative in VDDE understational lists
[23]	UV_DIS_STATE: Shows if the device is currently in VDD5 under voltage disable
	0: Currently no UV condition
	1: UV condition active
	Reset: 0
1001	Reset Condition: Read out POR, NRES
[22]	UV_DIS_LATCH: Bit set to 1 (UV filter expired) if VDD5 under voltage disable was triggered
	0: no UV condition detected
	1: UV condition detected
	Reset: 0
10.41	Reset Condition: Read out POR
[21]	DIS_STATE : Shows if the device is currently disabled by the DIS input signal
	0: DIS inactive
	1: DIS active
	Reset: X
	Reset Condition: -
[20]	DIS_LATCH: Shows if DIS was applied since last read out. Bit set to 1 by DIS input set HIGH
	0: No DIS detected
	1: DIS detected
	Reset: X
	Reset Condition: Read out POR
[19]	NDIS_STATE: Shows if the device is currently disabled by the NDIS input signal
	0: NDIS active
	1: NDIS inactive
	Reset: X
	Reset Condition: -
[18]	NDIS_LATCH: Shows if NDIS was applied since last read out. Bit set to 1 by NDIS input = LOW
	0: No NDIS detected
	1: NDIS detected
	Reset: X
	Reset Condition: Read out POR
[17]	NDIS_OUT_LATCH: Shows NDIS was used as output and internally pulled down.
	0: No internal NDIS activation
	1: Internal NDIS activation
	Reset: X
	Reset Condition: Read out POR
[16]	CONFIG_CC_STATE : Shows if communication check functionality is activated or deactivated
	0: CC inactive
	1: CC active
	Reset: X
	Reset Condition: Read out POR
[15]	CC_LATCH: Shows if CC failed since last read out. Bit set to 1 if communication check failed
	0: no CC failure detected
	1: CC failure detected
	Reset: X
	Reset Condition: Read out POR



[14]	BIST_DONE: BIST status
	0: not done/ongoing
	1: BIST finished
	Reset: X
	Reset Condition: POR, NRES
[13]	BIST_DIS: BIST disable event latch
	0: BIST passed
	1: BIST failed
	Reset: X
	Reset Condition: POR, NRES
[12]	HWSC_DONE: HWSC status
	0: not done/ongoing
	1: HWSC finished
	Reset: X
	Reset Condition: POR, NRES
[11]	HWSC_DIS: HWSC disable event latch
	0: HWSC passed
	1: HWSC failed
	Reset: X
	Reset Condition: POR, NRES
[10]	OV_VDD5_STATE: Current state of the VDD5 over voltage comparator output, no digital filter
	0: currently no OV condition on VDD5
	1: OV condition active on VDD5
	Reset: 0
	Reset Condition: -
[9]	OV_VDD5_LATCH: Bit set to 1 if a VDD5 over voltage was detected by OV VDD5 comparator (even if OV filter not expired)
	0: no VDD5 fast transient OV detected
	1: fast VDD5 transient OV detected
	Reset: 0
	Reset Condition: Read out POR, NRES
[8]	UV_VDD5_STATE: Current state of the VDD5 under voltage comparator output, no digital filter
	0: currently no UV condition on VDD5
	1: UV condition active on VDD5
	Reset: 0
	Reset Condition: -
[7]	UV_VDD5_LATCH: Bit set to 1 if a VDD5 under voltage was detected by UV VDD5 comparator (even if UV filter not expired)
	0: no fast VDD5 UV transient detected

1: fast VDD5 UV transient detected

Reset: 0

Reset Condition: Read out POR, NRES

[6] N_POR_LATCH: Shows if a POR_VDD5 on the int. 5V supply for channel occurred since last read out 0: No POR on VDD5 detected (state after readout)

Reset Condition: Cleared: Read out

1: POR on VDD5 detected (state after event)

Reset: X

Reset: X

Reset Condition: Set to default: POR

[5] NRES_LATCH: Shows if NRES was applied since last readout bit set to 1 by NRES input is LOW

0: No NRES detected

1: NRES detected

Reset: X

Reset Condition: Read out POR, NRES

[4] VCP_UV_STATE: Returns the output status of the VGBHI undervoltage comparator

0: VPS > VVPS UV outputs enabled

1: VPS < VVPS_UV outputs disabled

Reset: 0

Reset Condition: -

[3] VCP_UV_LATCH: Returns if a VCP_UV was detected since last read out

0: No VCP_UV detected

1: VCP_UV detected

Reset: 0

Reset Condition: Read out POR, NRES

[2] VPS_STATE: Feedback of the voltage at the VPS pin: if VPS pin smaller VVPS_UV the external MOSFETs are disabled

0: VPS > VVPS_UV outputs enabled

1: VPS < VVPS_UV outputs disabled

Reset: 0

Reset Condition: -

[1] VPS_LATCH: Returns if a low VPS voltage was detected since last read out

0: No VPS low detected

1: VPS low detected

Reset: 0

Reset Condition: Read out POR, NRES

[0] PARITY: Parity bit, based on even parity calculation

0: If the number of 1 is odd

1: If the number of 1 is even

Reset: 0

Reset Condition: -



RESPONSE 11

Frame partitioning

31 30 29 28	3 27	2	6 25	5 2	24	23	22	21	20	19	18	17	16	15	14	13	12 11 10	98	76	54	3	2 1	0
С	RW		FIX	ED	_P/	ΑΤΤ	ERN	1	V4	٨3	V2	5	C4	C3	C2	C	PUPD4	PUPD3		PUPD2	F	PUPD1	PARITY
Description:					Cł	nan	nel	1-4	cont	rol s	signa	al int	egri	y									
Reset:					0x	βA	BEC	0000	I														
[31:28]	Rese	et: 1				nma	and 1	1															
[27]	R/W : 0: Wi	: Bi rite equ	t to re & rec est re	ad/ ques	wrii st re	ead	-	jurat	on														
[26:21]	FIXE Rese	Reset Condition: POR, NRES FIXED_PATTERN: Fixed pattern Reset: 010101																					
[20:17]	V4 obtai The v 0: Dr 1: Dr (Low 0: Dr	.1: inin valı rain rain /-Si rain	g the ue of t volta volta de wit	oit m sta this ge l ge l th N ge l	non tus bit low higl NFE low	itor of t dep (Vt h (V T)	s the the o pend DRAII / _{DRA}	e exte outpu Is on _N < V _{IN} > '	t dur the (LVT) VLVT	ing r chan -> tr) -> t -> tra	norm inel c ansis rans	al op config stor (istor tor C	erati gurat ON OFF	on ion:	explo	iting	the internal d	iagnostic co	ompa	rators. It is	s use	ful for	
[16:13]	(High Rese Rese C4	h-S et: ^ et C .1 : mai	conditi	ion: oit c ON	PC om	DR, DR, OF	PFET NRE es th F	T) ES						SUT	xx, N	IONx	and SPI_inp	ut_sel_xx to	o dete	ermine if th	וe x-1	th chann	el is
	1: ou Rese	utpu et: (it com	ıma	inde	ed (NC	ES															



[12:10] PUPD4...1: Pull up / Pull down status of CHx

- [9:7] This field consists of 3 bit encoding the current status of the gate charge / discharge current sources for the x-th channel. The
- [6:4] code depends on the output configuration:

[3-1] High-Side with PFET:

L1

- 100: I_{PD} ON and I_{PU} OFF -> transistor ON
- 010: I_{PD} OFF and I_{PU} ON -> transistor OFF
- 000: IPD OFF and IPU OFF -> output in three-state
- Others: integrity of the output control is compromised

High-Side/Low-Side with NFET:

- 010: I_{PD} ON and I_{PU} OFF -> transistor OFF
- 001: I_{PD} OFF and I_{PU} ON -> transistor ON
- 000: I_{PD} OFF and I_{PU} OFF -> output in three-state
- Others: integrity of the output control is compromised

Reset: 0000

Reset Condition: -

[0] **PARITY**: Parity bit, based on even parity calculation

0: If the number of 1 is odd

1: If the number of 1 is even

Reset: 0

Reset Condition: -



RESPONSE 12

Frame partitioning

31 30 29 28	3 27 26 2	5 24	23 22	21	20	19	18	17	16	15	14	13	12 11 10	987	654	3 2 1	0
С	FIX	(ED_F	PATTERN	1	V8	77	V6	V5	C8	C7	C6	C5	PUPD8	PUPD7	PUPD6	PUPD5	PARITY
Description:		С	hannel	5-8	cont	rol s	igna	al int	egrit	t y							
Reset		0:	xCABE	0001													
[31:28]	C : Response Reset: 1100 Reset Condit		mmand 1	12													
[27]	R/W: Bit to re 0: Write & re 1: Request re Reset: 1	quest i ead on	read nly		on												
[26:21]	FIXED_PATT Reset: 01010	leset Condition: POR, NRES IXED_PATTERN: Fixed pattern leset: 010101 leset Condition: POR, NRES															
[20:17]		oit moi status this bi	nitors the s of the c it depend	e exte outpu Is on	t duri	ing r chan	norm	al op config	erati gurat	on	explo	iting	the internal d	iagnostic con	nparators. It is	useful for	
	1: Drain volta (Low-Side wi 0: Drain volta	th NFI	ET)														
	1: Drain volta (High-Side w Reset: 1111	ith NF	ET/PFE	Г)	V _{OL})	-> tr	ansi	stor (ON								
[16:13]	commanded	oit con ON or	nbines th r OFF		ntrol	sign	als S	SPI_(ON_(OUT	xx, N	ION×	and SPI_inp	ut_sel_xx to c	determine if th	e x-th channe	el is
	0: output con 1: output con Reset: 0000 Reset Condit	nmand	ded ON	ES													



[10:12] PUPD8...5: Pull up / Pull down status of CHx

- [9:7] This field consists of 3 bit encoding the current status of the gate charge / discharge current sources for the x-th channel. The
- [6:4] code depends on the output configuration:

[3-1] High-Side with PFET:

L1

- 100: I_{PD} ON and I_{PU} OFF -> transistor ON
- 010: I_{PD} OFF and I_{PU} ON -> transistor OFF
- 000: IPD OFF and IPU OFF -> output in three-state
- Others: integrity of the output control is compromised

High-Side/Low-Side with NFET:

- 010: I_{PD} ON and I_{PU} OFF -> transistor OFF
- 001: I_{PD} OFF and I_{PU} ON -> transistor ON
- 000: I_{PD} OFF and I_{PU} OFF -> output in three-state
- Others: integrity of the output control is compromised

Reset: 0000

Reset Condition: POR, NRES

[0] **PARITY**: Parity bit, based on even parity calculation

0: If the number of 1 is odd

1: If the number of 1 is even

Reset: 0

Reset Condition: -



RESPONSE 13

Frame partitioning

31 30 29 28	3 27 26 2	25 24	23	22	21	20 19	18	17	16	15	14	13	12	11	10	9	8	7	6	5	4	3	2	1	0
С	RW	FIXED_PATTERN	NDIS_PROT_LATCH	OT_STATE	SD0_OV_LATCH			TI	EMP	AD(C							,	VPS_	_ADC	>				PARITY
Description		D)evic	e sta	atus	, battery	/ and	l ten	nper	ature	e mo	onito	or												
Reset		Х	(
	C : Respons Reset: 1101 Reset Conc	1	mmai	nd 1:	2																				
	0: Write & r 1: Request Reset: 1	Bit to read/write configuration ite & request read iquest read only t: 1 t Condition: POR, NRES																							
		set Condition: POR, NRES (ED_PATTERN: Fixed pattern																							
	Reset: 010		. Fixe	u pa	llem																				
	Reset Conc																								
[23]	NDIS_PRO reactivation	T_LAT				1 if the p	rotec	tion	on N	DIS p	oin w	as a	ictiva	ated	while	e ND	IS w	as b	eing	interi	nally	pulle	ed do	own,	
	0: no OV co																								
	1: OV cond	lition on	NDIS	S det	ecte	d																			
	Reset: 0																								
	Reset Conc																								
	OT_STATE						ator o	utpu	t																
	0: no OV co																								
	1: OV cond Reset: 0		300	Juere	ected	1																			
	Reset Conc	dition: -																							
	SDO_OV_L		Sho	ws if	an ()V in SD	() nir	was	s det	ected	l sinr	re la	st re	ad o	ut										
	0: no OV cc						o pii	i mac	0 000	00100		0010	0110	au o	at										
	1: OV cond																								
	Reset: 0																								
	Reset Cond	dition: R	lead o	out P	POR																				



[20:11] **TEMP_ADC**: Returns the actual temperature measured by the internal temperature sensor of the device. 10 bit to code for the actual temperature of the device

See Temperature ADC.

Reset: X

Reset Condition: POR, NRES

[10:1] VPS_ADC: Returns the actual VPS voltage measured by the internal voltage sensor of the device. 10 bit to code for the actual VPS voltage

See VPS ADC

Reset: X

Reset Condition: POR, NRES

[0] **PARITY**: Parity bit, based on even parity calculation

0: If the number of 1 is odd

1: If the number of 1 is even

Reset: X

Reset Condition: -

6 Safety & diagnostics

This chapter contains all the information regarding safety and diagnostic features. All the external and internal disable sources are described. The Built-In Self-Test (BIST), HardWare Self-Check (HWSC) and the Communication Check (CC) watchdog are also explained. The diagnostics implemented for monitoring the output status and protecting the external FETs are described.

All the information regarding the effects of disable sources and diagnostics on the output pre-drivers is summarized in Section 6.6.

6.1 Disable sources

There are several disable sources implemented in order to guarantee safety and correct functionality of the output pre-drivers.

6.1.1 DIS & NDIS pins

For safety purposes, L9945 features two disable pins that can be driven by an external microcontroller:

- DIS: is a positive asserted disable input with internal pull up. When DIS is asserted, all channels except 7 and 8 are actively turned off. DIS status can be monitored reading DIS_STATE bit via SPI. If DIS has been asserted, the event is latched in the DIS_LATCH, cleared on SPI readout. Outputs are automatically reengaged when DIS is released.
- NDIS: is a negative asserted disable input/output with internal pull down. Refer to Figure 24.
 - When used as input, a negative assertion implies an active shut off of all the outputs except channels 7 and 8. NDIS status can be monitored reading NDIS_STATE bit via SPI. If NDIS has been asserted, the event is latched in the NDIS_LATCH, cleared on SPI readout. Outputs are automatically reengaged when NDIS is released.
 - L9945 uses this pin as **output** every time an over/under voltage is detected on VDD5 supply. The
 purpose is to provide a feedback on the VDD5 status to the external microcontroller. This functionality
 is enabled only if NRES is set high. If NDIS is internally pulled down, the event is latched in
 NDIS_out_LATCH, cleared on SPI readout.

In case of overvoltage (VDD5 > V_{VDD5} OV for t > t_{VDD5} OV) NDIS is pulled-down immediately.

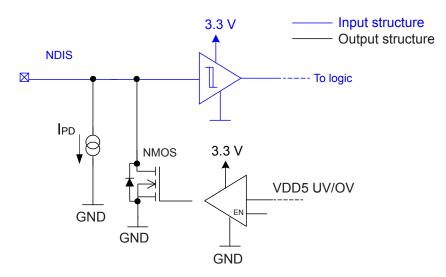
In case of undervoltage (VDD5 < V_{VDD5_UV} for t > t_{VDD5_UV1}) NDIS is pulled-down after tVDD5_UV2.

Note: For timings and electrical characteristics related to VDD5 refer to Table 8.

When configured as H-Bridge, channels 7 and 8 are handled like other channels and are disabled in case of DIS/NDIS assetion.

When used as output, NDIS is protected against overvoltage. In case NDIS is internally activated low and the voltage at NDIS pin exceeds VNDIS_OV, for a time longer than tNDIS_OV + tNDIS_OV_react, the protection is activated by switching OFF the pull down structure on NDIS pin. Once the protection is activated it will stay active until the next NDIS internal activation event. NDIS overvoltage event is latched into **NDIS_PROT_LATCH**, cleared via SPI readout.





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Table 31. NDIS OV protection electrical characteristics

Symbol	Parameter	Test condition	Min.	Тур.	Max.	Unit
V _{NDIS_OV}	NDIS OV disable threshold	Low Side ON	0.8	-	1.0	V
t _{NDIS_OV}	NDIS OV deglitch filter time	-	2.2	2.5	2.7	μs
t _{NDIS_OV_react}	NDIS OV Comparator reaction time	-	100	-	700	ns

6.1.2 VDD5 Overvoltage/Undervoltage

VDD5 is internally monitored to detect overvoltage/undervoltage conditions:

- In case VDD5 ≥ V_{VDD5_OV}, an internal OV disable is generated after the filter time t_{VDD5_OV}. Such an event is latched in OV_DIS_LATCH, cleared on SPI readout. In case of overvoltage all outputs except channel 7 and 8 are actively turned off until the next SPI diagnostic readout. Overvoltage comparator status can be monitored reading OV_VDD5_STATE bit via SPI. If the comparator output goes high due to a transient overvoltage, the OV_VDD5_LATCH is set, even if the filter time tVDD5_OV hasn't expired. This latch is cleared on SPI readout and doesn't imply an output disable.
- In case V_{POR} ≤ VDD5 ≤ V_{VDD5_UV}, an internal UV disable is generated after the filter time t_{VDD5_UV1}. Such an event is latched in UV_DIS_LATCH, cleared on SPI readout. Once UV disable is activated it will stay active at least for tVDD5_UV1 after UV condition disappears. In case of undervoltage all outputs except channel 7 and 8 are actively turned off. If UV condition disappears, outputs are automatically re-engaged. Undervoltage comparator output can be monitored by reading UV_DIS_STATE via SPI.

In case VDD5 \leq V_{POR} an internal POR is generated and the device is reset. Such an event is latched in **n_POR_LATCH** and can be cleared via SPI readout.

Note: Refer to Table 8 for the electrical characteristics and the parameters regarding VDD5 overvoltage and undervoltage detection.

When configured as H-Bridge, channels 7 and 8 are handled like other channels and are disabled in case of VDD5 UV/OV.

6.1.3 BIST & HWSC

The device features a Built-In Self-Test (BIST) and a HardWare Self-Check (HWSC).

For functional safety considerations, internal disable structures must operate always correctly and reliably. To accomplish this, the disable sources paths and the VDD5 overvoltage detection block are self-checked by L9945:

- BIST covers the digital domain of disable-related functions;
- HWSC covers the analog domain of the VDD5 overvoltage comparator.

In case of BIST or HWSC failure, all channels except 7 and 8 are disabled. BIST is always followed by HWSC to ensure full coverage of digital and analog domains. The sequence is performed in less than 3 ms, and is run:

- After each NRES release (POR assertion does not imply BIST & HWSC sequence execution);
- On demand, programming the **BIST_RQ** bit via SPI.

Note: Due to device configuration reset during BIST, the procedure must be executed prior to channel configuration applied.

The procedure starts with BIST. During BIST execution:

- The **BIST_DONE** latch is set low;
- All output drivers (including 7 and 8) are three-stated;
- All the device registers are reset, except SPI latches (UV/OV events, disable events, etc.).

BIST checks the correct function of the disable logic to the gate drive of the outputs:

- Switch OFF paths from DIS, NDIS, EN6, including the bidirectional NDIS output;
- Switch OFF path from Communication Check;
- Switch OFF path from HWSC/BIST;
- Switch OFF path from OV/UV detection block.

BIST also checks that the implemented timers can be stopped (e.g. communication check timeout). The BIST DONE latch is set high once BIST has terminated.

- In case the procedure detects an error, the BIST_DIS latch is set and all outputs, except 7 and 8, are kept actively turned off. Channels 7 and 8 are kept in three-state.
- In case BIST detected no error, the outputs are kept in three-state

HWSC follows BIST and checks the functionality of VDD5 overvoltage detection mechanism. HWSC lasts t_{HWSC_DUR} . During such interval, the outputs 1-6 are kept OFF actively by asserting the **HWSC_DIS** internal signal; channels 7-8 are still in three-state, since the BIST executed previously. After t_{HWSC_DUR} has expired, the **HWSC_DONE** latch is set high and the self check result will be available via SPI reading the HWSC_DIS signal status. Two cases can occur:

- HWSC failed: the signal HWSC_DIS is kept high and disables (actively) all the outputs except 7 and 8;
- HWSC passed: the signal HWSC_DIS is set low and the disable is released.

If both BIST and HWSC are successful, BIST_DIS and HWSC_DIS disable signals are released and the outputs can be configured and enabled normally. If one among BIST and HWSC failed, channels 1-6 are kept disabled, regardless of the configuration applied; channels 7-8 can still be enabled.

BIST and HWSC sequence is stopped in case of a reset condition:

- NRES set low;
- POR.

When configured as H-Bridge, channels 7 and 8 are handled like other channels and are disabled in case of BIST/HWSC failure.

Note:

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Figure 25. BIST & HWSC sequence

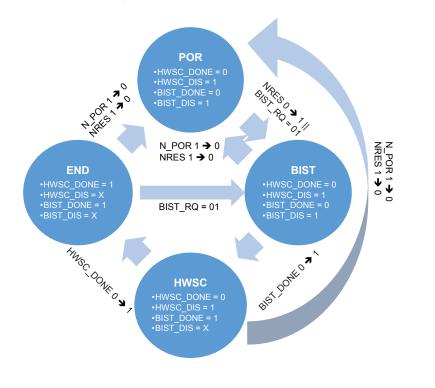


Table 32. HWSC timing characteristics

Symbol	Parameter	Min.	Max.	Unit
thwsc_dur	HWSC duration time	100	160	μs

6.1.4 VPS undervoltage

In case **VPS** is lower than V_{VPS_UV} for $t_{VPS_react} + t_{LBD_FIL}$, a battery undervoltage is detected, all outputs are actively turned off and the **VPS_LATCH** is set high (cleared on SPI readout). The undervoltage comparator output can be monitored by reading **VPS_STATE** bit via SPI. Outputs are re-engaged when undervoltage condition disappears.

Table 33. VPS UV detection electrical characteristics

Symbol	Parameter	Min.	Max.	Unit
V _{VPS_UV}	VPS low battery detection threshold	3.5	3.8	V
t _{VPS_react}	VPS Comparator output reaction time for L->H and H->L transition	100	700	ns
t _{LBD_FIL}	Filter time for VPS low battery detection	0.5	5	μs

6.1.5 Charge pump undervoltage

In case **VGBHI** is lower than V_{CP_UV} for t_{CP_UV} , a charge pump undervoltage is detected, all outputs are actively turned off and the **VCP_UV_LATCH** is set high (cleared on SPI readout). The undervoltage comparator output can be monitored by reading **VCP_UV_STATE** bit via SPI. Outputs are re-engaged when undervoltage condition disappears.



Table 34. Charge pump undervoltage detection electrical characteristics

Symbol	Parameter	Test condition	Min.	Max.	Unit
V _{CP_UV}	Under voltage threshold	Referenced to VVPS	VVPS + 3.9	VVPS + 5.1	V
Vh _{CP_UV}	Under voltage hysteresis	Referenced to VVPS	250	-	mV
t _{CP_UV}	Digital filter of UV shutdown	-	10	30	μs

6.1.6 SPI enable bit

Each channel can be enabled/disabled independently by programming the **en_OUT_xx** SPI bit. If such bit is set low, the corresponding channel is three-stated. By default, all channels are three-stated and must be enabled setting en_OUT_xx high after having properly configured them in the same SPI register. Output control signal is ignored as long as en_OUT_xx is low.

6.1.7 Protection disable bit

L9945 offers additional SPI bit for disabling channels via SPI: **prot_disable_xx**. Although such bit can disable each channel separately, the main purpose of prot_disable_xx is to allow a fast disabling of all channels through a single SPI frame. In fact, all prot_disable_xx bit are part of the same SPI command. In case prot_disable_xx is set high, the corresponding channel is actively turned off. Output control signal is ignored as long as prot_disable_xx is low.

6.1.8 EN6 input

Channel 6 is designed for being used in safety relevant applications. For such reason, an additional enable input, EN6, has been provided. If EN6 is set low, channel 6 is actively turned off and the **EN6_LATCH** is set high (cleared on SPI readout). Channel 6 control signal is ignored as long as EN6 is low.

6.1.9 NRES assertion

In case of NRES assertion, all outputs are actively turned off and the **NRES_LATCH** is set (cleared on SPI readout). Since channel configuration is reset, output re-engagement must be executed manually.

6.1.10 Communication Check (CC)

Communication Check (CC) starts to work as soon as the disable inputs NDIS/DIS are released. With this condition the CC timer is started. Depending on the status of NDIS/DIS at the release of NRES, two possible scenarios can occur:

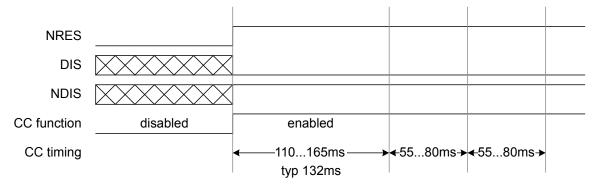
- NDIS/DIS are released after NRES release, once the external microcontroller power-up routine is completed. In this case, CC starts with t_{CC} time frame (see Figure 26)
- NDIS/DIS are released before NRES release. In this case, once NRES is deasserted, CC starts with t_{CC_INIT} time frame, in order to allow the external microcontroller completing the power-up routine. Then, it switches to t_{CC} (see Figure 27)

Figure 26. NDIS/DIS release after NRES release: t_{CC} is selected as watchdog starting timer value

NRES					
DIS					
NDIS					
CC function	disabled	enabled			
CC timing			∢ 5580ms→	← 5580ms→	
		typ 66ms	1	GAPG010	2161044CFT



Figure 27. NDIS/DIS release before NRES release: t_{CC} is selected as watchdog starting timer value. Then, CC timer switches to t_{CC} .



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The distinction between t_{CC} and t_{CC_INIT} applies only at the beginning of CC. After the first valid SPI frame, CC always operates with t_{CC} deadline.

In case of no valid communication the CC timer will expire and disable all related outputs. With the next valid communication the outputs are enabled. Each correct communication restarts the CC timer. If a CC failure is detected, all channels except 7 and 8 are actively turned off and the **CC_LATCH** is set high (cleared on SPI readout).

The CC can be deactivated by programming the **CONFIG_CC** field via SPI. By default CC is active. CC status can be monitored by reading the **config_CC_STATE** SPI bit.

Note: When configured as H-Bridge, channels 7 and 8 are handled like other channels and are disabled in case of CC failure.

Table 35. CC timings

Symbol	Parameter	Min.	Max.	Unit
t _{CC}	Communication Timeout	55	85	ms
t _{CC_INIT}	Deadline for the first communication engagement in case DIS/NDIS are released before NRES release.	110	165	ms

6.2 Diagnostics overview

The device performs two types of diagnostics for each output channel:

- ON state diagnostics: overcurrent (OC) detection;
- OFF state diagnostics: open load (OL), short to ground (STG), and short to battery (STB) detection.

Diagnostic can be enabled/disabled by programming the ENABLE_DIAGNOSTIC bit.

The AN "L9945_Diagnostics_Explained" covers all the main aspects of diagnostics and helps choosing the correct values for the tblank_oc and tdiag filter times.

Diagnostic report for all channels is readable via SPI, after having issued the **0x9AAA0001** frame. The diagnostic status of each channel is encoded in 3 bit (**diag_xx**[2-0]), as shown in the table below.

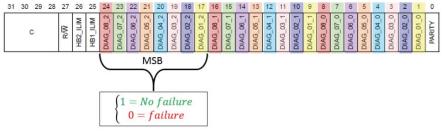
Table 36. Diagnostic codes

Channel Status	diag_xx[2-0]	Priority
OC pin failure (see note below)	000	1
OC failure	001	2
STG/STB failure	010	3
OL failure	011	4
No failure	100	5
No OC failure	101	6
No OL/STG/STB failure	110	7
No diagnostic done	111	8

Note:

The OC pin failure, corresponding to the code "000" is available only for channels operating in Peak & Hold. This code is unused in other configurations. Refer to Section 5.6.2 in order to understand how this diagnostic is performed.

Figure 28. Diagnostic codes quick look



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For an immediate fault detection, the MSB of the diagnostic code can be evaluated, as shown in Figure 28. An MSB equal to zero indicates that a failure occurred.

By default, all channels will report the "No diagnostic done" message. Such message is also reported in case diagnostic has been disabled. The diagnostic status follows a priority concept: if more than one event occurs on a channel, only the one with the highest priority will be encoded in the diag_xx[2-0] bit. Priority codes are related to the severity of the fault. OC failures have the highest priority.

The diagnostic latches are reset in case of SPI readout, POR or NRES. After a reset event, diagnostic filters are reset to prevent false detection.

Figure 29 shows an equivalent Finite State Machine (FSM) that helps understanding diagnostic priority.

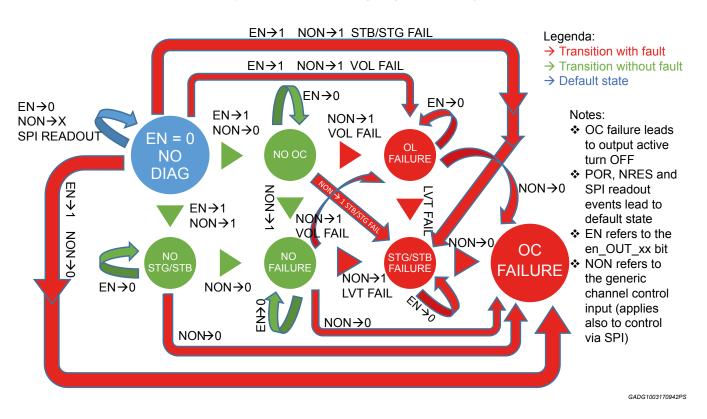


Figure 29. FSM describing diagnostic priority

Note: In case a diagnostic event occurs during SPI readout, such event is latched and provided with the next diagnostic request.

6.3 ON state diagnostics

The following diagnostic codes can be set during the output ON state:

- The diagnostic code corresponding to normal operation while in ON state is "No OC failure" (101);
- The "No failure" (100) code will be reported only once, after an OFF->ON transition, assuming that "No OL/STG/STB failure" latch was set while in OFF state and "No OC failure" is detected;
- The "OC failure" (001) or "OC pin failure" (000) codes will be reported in case of overcurrent detection.

L9945 protects the external FET against overcurrent (OC) during the ON phase. The device features an analog comparator with a programmable overcurrent threshold. Sensing is performed measuring the voltage drop on an external element and comparing it to the programmed threshold. Such threshold can be compensated against battery and temperature variations for specific applications.

6.3.1 Behavior in case of OC detection

If an OC event is detected, the output is actively shut off and the "OC failure" message is encoded in the diag_xx[2-0] bit. To prevent FET damage, in case the normal operation gate charge/discharge currents are low (1 mA or 5 mA), the device selects a higher shut off current among the ones available through **GCC_config_xx**. By programming the **GCC_override_config**, it is possible to select the entity of current increase in case of OC, as shown in the table below. These settings are in common between all channels.

Table 37. Selection of fast shutdown currents in case of OC detection

GCC_override_config	I _{PU} or I _{PD} [mA]
0	1 → 5
0	$5 \rightarrow 20$

GCC_override_config	l _{PU} or l _{PD} [mA]
1	1 → 20
	$5 \rightarrow 20$

Note: IPU is used to shut down PMOS, while IPD shuts down NMOS.

The GCC override configuration is applied as soon as an OC event is detected. The original GCC configuration is restored once diagnostics have been read.

6.3.2 Output re-engagement strategy after an OC event

After an OC event, the affected output must be manually re-engaged. There are two reactivation strategies, configurable via SPI bit **prot_config_xx**:

- Output re-engagement with control signal switching event (default);
- · Output re-engagement after diagnostic readout and control signal switching event.

In case of H-Bridge configuration, the prot_config_xx has no effect. Re-engagement is always performed after diagnostic readout.

Note: Control signal can be either NONx or SPI_ON_OUTxx, depending on SPI_INPUT_SEL_xx bit

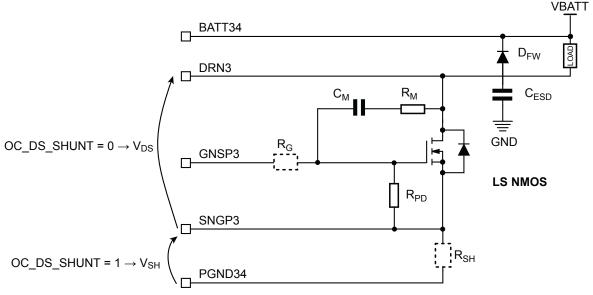
6.3.3 OC sensing strategy

OC detection is performed by sensing the voltage either on an external shunt resistor or between the drain and the source of the external FET. Detection strategy can be selected on each channel independently by programming the **OC_DS_Shunt_xx** bit as follows:

Table 38. OC sensing strategy

OC_DS_Shunt_xx	OC sensing strategy
0	Drain To Source Measurement (DSM)
1	Shunt Measurement

Figure 30. Overcurrent sensing method (example on a LS NMOS)



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The following behaviors correspond to the different sensing methods (refer to Figure 31):

In case Rshunt is selected, the V_{sense} behavior during the OFF==>ON transition corresponds to an ascending transient. In case the FET current crosses the OC threshold with a positive slope, t_{BLANK_OC} is stopped and t_{OC} is started. The OC detection will be mainly based on t_{FIL_ON} and t_{OC} parameters. The former is a deglitch filter to avoid small overshoots on the shunt resistor due to inductive effects, while the latter represents the actual OC blanking time. An OC event lasting t_{FIL_ON}+t_{OC} will be detected and the output switched OFF: the programmed t_{BLANK_OC} will have no effect on the OC reaction time. Only in case Peak & Hold configuration is selected and the OC event occurs while t_{BLANK_OC} is still running, an '**OC pin failure' (000)** will be reported instead of simple 'OC failure' (001). However, reaction time won't be affected.
 In case DSM is selected, the V_{sense} behavior during the OFF==>ON transition corresponds to a falling transient. Once t_{BLANK_OC} has expired, the VDS will be compared to the OC threshold and, if greater, the output will be shut OFF. Hence, t_{BLANK_OC} must be sized to allow VDS settling. In order to ensure maximum FET protection against critical OC events during blanking time, an OC threshold crossing with a positive slope will stop the tblank_oc and engage the t_{OC} filter.

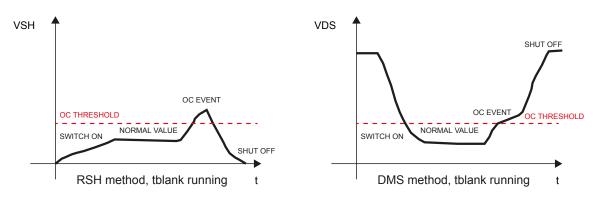


Figure 31. Rshunt and DSM method diagram

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6.3.4 OC threshold selection

The voltage corresponding to the OC threshold can be selected independently for each channel programming the **OC_config_xx** bit. Such threshold is highly flexible: it is encoded on 6 bits (64 available values) and falls in the [50 - 1000] mV range.

	Table 39. Overcurrent threshold selection	electrical p	arameters	
bl	Parameter	Min.	Typ.	Max.

Symbol	Parameter	Min.	тур.	Max.	Unit
V _{OC_RANGE}	Range	50	-	1000	mV
OC_RES	Resolution	-	6	-	Bit
t _{SETTLING}	Threshold settling Time	5	-	18	μs

Refer to Table 40 for the encoding tables for LS and HS configurations. Overcurrent threshold must be programmed according to the Eq. (3):

Eq. (3): Overcurrent threshold

$$V_{OC} = R_{OC} \times I_{OC}$$

(3)

where V_{OC} is the value programmed in the **OC_config_xx** bit, IOC is the maximum current for the given application and R_{OC} can be either R_{SH} (shunt resistor) or R_{DSon} (DSM).

Note: For H-Bridge configuration, refer to Overcurrent detection strategies for H-Bridge and Current limitation for H-Bridge to understand how OC thresholds can be programmed and exploited also for current limitation feature.

		LS	H	HS	
OC_config_xx[5-0]	Min.	Max.	Min.	Max.	Unit
0	53	67	53	69	mV
1	68	82	68	85	mV
2	83	97	83	101	mV
3	97	113	99	117	mV
4	113	128	113	133	mV
5	128	143	129	150	mV
6	142	158	144	166	mV
7	157	173	159	182	mV
8	172	188	172	198	mV
9	186	204	189	214	mV
10	201	220	204	231	mV
11	216	235	219	247	mV
12	231	250	234	263	mV
13	246	266	248	279	mV
14	261	281	264	295	mV
15	275	296	278	311	mV
16	290	311	290	326	mV
17	305	327	305	341	mV
18	320	343	320	356	mV
19	334	358	338	375	mV
20	349	374	351	391	mV
21	364	389	367	407	mV
22	379	405	382	423	mV
23	393	420	397	439	mV
24	408	436	412	455	mV
25	423	451	427	471	mV
26	438	467	442	488	mV
27	453	482	456	504	mV
28	467	498	472	520	mV
29	482	513	486	536	mV
30	497	529	501	552	mV
31	512	544	515	568	mV
32	526	559	525	579	mV
33	541	575	545	595	mV
34	556	590	560	612	mV
35	570	606	575	628	mV
36	585	621	590	644	mV
37	600	637	604	660	mV

Table 40. OC threshold selection



		LS	HS		11
OC_config_xx[5-0]	Min.	Max.	Min.	Max.	– Unit
38	614	653	619	676	mV
39	629	668	634	693	mV
40	644	684	649	708	mV
41	658	699	663	724	mV
42	673	715	679	740	mV
43	688	730	693	756	mV
44	702	746	708	772	mV
45	717	761	723	788	mV
46	732	777	738	804	mV
47	746	792	753	821	mV
48	761	808	767	836	mV
49	776	823	782	852	mV
50	791	839	797	868	mV
51	806	854	812	885	mV
52	820	870	827	900	mV
53	835	885	842	916	mV
54	849	900	856	933	mV
55	864	916	871	949	mV
56	878	931	886	964	mV
57	893	947	900	981	mV
58	908	962	916	997	mV
59	922	977	930	1013	mV
60	937	992	946	1029	mV
61	951	1008	960	1045	mV
62	967	1023	975	1061	mV
63	982	1038	987	1078	mV

6.3.5

5 OC detection timings

ON state diagnostics timings are listed in the following table.

Table 41. OC detection timings

Symbol	Parameter	Condition	Min.	Тур.	Max.	Unit		
	CC blanking filter:	ti			10	11.1	12.2	μs
		tblank_oc = 001	14	15.6	17.1	μs		
		tblank_oc = 010	18	20	22	μs		
to any oo		tblank_oc = 011	28	31.1	34.2	μs		
^t BLANK_OC	It doesn't mask the OC failure. It only determines the assertion of the "No OC failure" diagnostic code.	tblank_oc = 100	39	42.2	46.5	μs		
	tb	tblank_oc = 101	48	53.3	58.7	μs		
		t	tblank_oc = 110	88	97.8	107.6	μs	
		tblank_oc = 111	128	142.2	156.5	μs		

5/	

Symbol	Parameter	Condition	Min.	Тур.	Max.	Unit
t _{FIL_ON}	OC deglitch filter time	-	0.6	-	1	μs
t _{OC}	OC Detection filter time	-	2	-	3	μs

6.3.6 Temperature compensation for OC threshold

L9945 offers the possibility to compensate the OC threshold against temperature variations. Such feature can be enabled independently on each channel.

The device is able to monitor the internal junction temperature T_j through on board Temperature ADC. Given the estimated temperature variation between L9945 junction and the external FET junction

Eq. (4): Estimated temperature variation for the compensation algorithm

$$\Delta T = T_{jFET} - T_j$$

(4)

(5)

An internal algorithm measures T_j and is able to compensate V_{OC} against RDSon variations induced by T_{jFET} . The latter can be estimated according to the given application and operating scenario.

Temperature compensation can be enabled by programming the **OC_Temp_comp_xx** bit according to the following table:

OC_Temp_comp_xx	Function			
00 Temperature compensation deactivated				
01 Temperature compensation active for estimated $\Delta T < 60$ °C. TCF is saturated at '1' for $T_j \ge T_{j_SAT} = 83$ °C.				
10	Temperature compensation active for estimated $\Delta T < 40$ °C. TCF is saturated at '1' for $T_j \ge T_{j_SAT} = 96$ °C.			
11 Temperature compensation active for estimated $\Delta T < 25$ °C. TCF is saturated at '1' f T _j \geq T _{j_SAT} = 108 °C.				

Table 42. Temperature compensation

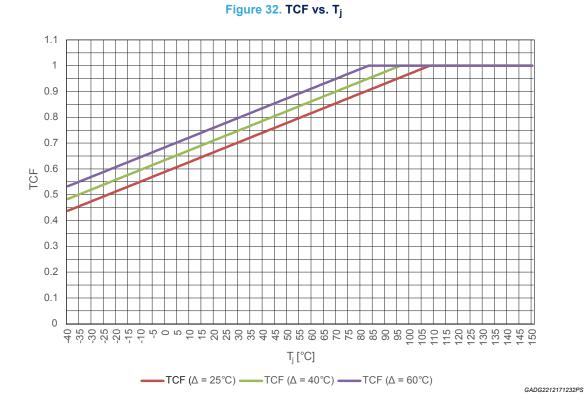
In case temperature compensation is enabled, the overcurrent threshold must be programmed according to Eq. (3), where R_{OC} is the RDSon of the external FET evaluated for T_{jFET} = 150 °C.

The internal algorithm compensates the OC threshold based on a multiplicative factor:

Eq. (5): Temperature Compensation Factor (TCF)

$$V_{OC_comp} = TCF \times V_{OC}$$

TCF = 1 when $T_j \ge T_{j_SAT}$, and it's decremented with a constant slope of 0.38 %/°C for $T_j < T_{j_SAT}$.



Note: This feature is recommended only in case of DSM, because the compensation algorithm is based on RDSon variations. The external FET must have a characteristic RDSon vs. T_{jFET} that matches the 0.38 %/°C slope. In case of shunt measurement, the algorithm may show performances worse than the uncompensated strategy.

6.3.7 Battery compensation for OC threshold

L9945 offers the possibility to compensate the OC threshold against battery variations. This feature can be enabled when driving a resistive output load R_L , and helps preventing the load resistance from dropping below a minimum threshold R_{Lmin} . Given Eq. (3), the I_{OC} can be evaluated as the current flowing when the battery is at its maximum operating value (18 V for passenger vehicles or 36 V for commercial vehicles) and the load resistance assumes its minimum allowed value R_{Lmin} :

Eq. (6): Overcurrent detection in case of resistive load

$$I_{OC} \simeq \frac{V_{BATT\max}}{R_{L\min}} \to V_{OC} = R_{OC} \times \frac{V_{BATT\max}}{R_{L\min}}$$
(6)

Eq. (6) assumes that $R_L >> R_{OC}$. The sensing resistance ROC can be either the shunt resistor or the R_{DSon} . Referring to Figure 34 and Figure 35, the device measures:

Eq. (7): Overcurrent sensing in case of resistive load

$$V_{SENSE} = R_{OC} \times I_{LOAD} = R_{OC} \times \frac{V_{BATT}}{R_L}$$
(7)

The device is able to monitor the battery voltage on the VPS pin through the on board **VPS** ADC. This information can be used to compensate the VOC with respect to V_{BATT} variations. Therefore, the OC detection occurs only when $V_{SENSE} = V_{OC}$ due to a R_L variation.

The internal algorithm compensates the OC threshold based on a multiplicative factor:

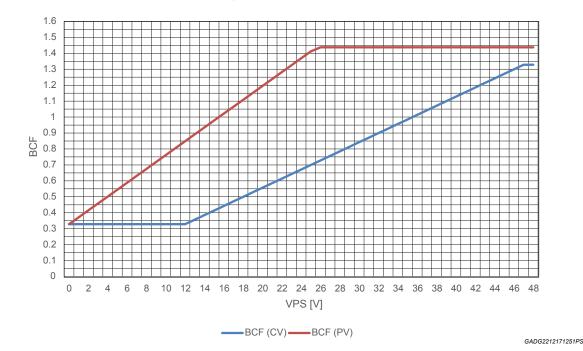
Eq. (8): Battery Compensation Factor (BCF)

$$V_{OCcomp} = BCF \times V_{OC}$$

(8)

The battery compensation feature can be activated independently on each channel by programming the **OC_Batt_comp_xx** bit. Two different BCF have been implemented for Passenger Vehicle (PV) and Commercial Vehicle (CV) applications. The BCF can be selected by programming the **Batt_fact_config** bit (refer to Figure 33).

Figure 33. BCF vs.VPS



Note: Because the algorithm is based on the assumption made for Eq. (6), the battery compensation feature is recommended only in case of resistive load. Usage either in case of different load types or in case of small resistive loads may lead to performances worse than the uncompensated strategy.

V

6.3.8 Reading the compensated OC threshold

In general, the overcurrent threshold can be evaluated as follows:

Eq. (9): Overcurrent threshold compensation formula

$$OCcomp = BCF \times TCF \times V_{OC}$$

(9)

Where V_{OC} is the value programmed in the **OC_config_xx** bit, BCF is the battery compensation factor and TCF is the temperature compensation factor. When a compensation feature is disabled, its compensation factor is set to 1 (no effect on V_{OC}).

Note: It is recommended to enable battery and temperature compensation simultaneously only in case of resistive load with DSM. Different usage may lead to performances worse than the uncompensated strategy. When configuring the device, the **OC_read_xx** can be used to select whether reading the programmed threshold

VOC or the compensated one V_{OCcomp}.

6.3.9 OC detection schematics

Figure 34 shows the OC detection implementation in case of LS configuration. It can also be applied to the HS scenario with NFET (see description). In case DSM is selected RSH must not be mounted and the pins SNGPx and PGNDxx must be shorted.

Figure 35 shows the OC detection implementation in case of HS configuration with PMOS. In case DSM is selected RSH must not be mounted and the pins GNSPx and BATTxx must be shorted.

57/

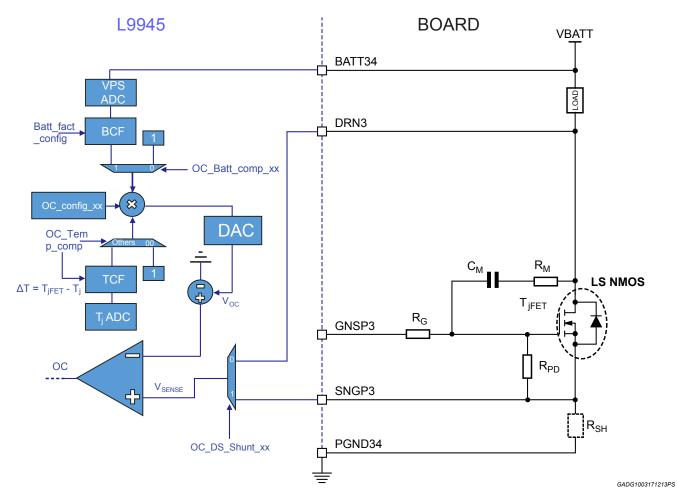


Figure 34. OC detection through DSM or Shunt Measurement in Low Side configuration

Note: V_{OC} compensation against temperature and battery variations is shown in Figure 34. In case of High Side configuration with NMOS, RSH and the LOAD must be swapped, and the OC_DS_Shunt_xx signal is negated.

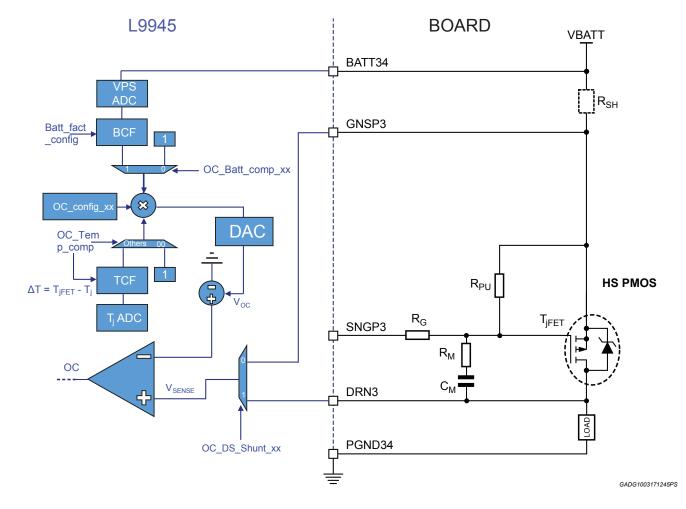


Figure 35. OC detection through DSM or Shunt Measurement in High Side configuration with PMOS

Note: V_{OC} compensation against temperature and battery variations is shown in Figure 35.

6.4 OFF state diagnostics

The following diagnostic codes can be set during the output OFF state:

- The diagnostic code corresponding to normal operation while in OFF state is "No OL/STG/STB failure" (110);
- The "No failure" (100) code will be reported only once, after an ON->OFF transition, assuming that "No OC failure" latch was set while in ON state;
- The "OL failure" (011) or "STG/STB failure" (010) codes will be reported respectively in case of open load and short to ground/battery failures.

Short To Battery (**STB**), Open Load (**OL**) and Short To Ground (**STG**) are part of the OFF state diagnostics. L9945 measures the voltage on the output node V_{out} to determine if the output is shorted to battery/ground (respectively for HS/LS configurations) or if the output node is floating (open load). Depending on channel configuration, different faults can be detected:

- LS diagnostics
 - V_{out} < V_{LVT} indicates a STG (see Figure 36)
 - V_{LVT} < V_{out} < V_{OL} indicates an OL
 - V_{out} > V_{OL} is a normal condition for LS configuration

57/



- HS diagnostics
 - V_{out} > V_{OL} indicates a STB (see Figure 36)
 - V_{LVT} < V_{out} < V_{OL} indicates an OL
 - V_{out} < V_{LVT} is a normal condition for HS configuration

Refer to Table 36 for the diagnostic codes corresponding to the STB/STG and OL faults.

Refer to Section 6.4.2 for the V_{OL} and V_{LVT} thresholds value.

When an OL or STB/STG fault is detected, the corresponding diagnostic code is latched, but no action is taken on the outputs.

Note: V_{out} corresponds to DRNx pin for LS NMOS and HS PMOS configurations, while it's SNGPx pin for HS NMOS configuration.

6.4.1 Settling and deglitch filter times

A filter time t_{DIAG} has been implemented to allow settling of the output node voltage (V_{out}) before the comparison to the diagnostic thresholds.

When an output is switched OFF, the t_{DIAG} filter time is started. When the filter expires, V_{out} is compared to the V_{LVT} and V_{OL} thresholds to determine the output diagnostic status (see Figure 36).

The filter time t_{DIAG} can be programmed as follows:

tdiag_config_xx	Value	Unit							
Values	Values available for all configurations								
00	00 25.6 µs								
01	61.2	μs							
10	105.6	μs							
11	150	μs							
Additional values available for H-Bridg	e configuration (refer to H-Bridge OF	F state diagnostic timings)							
00	11.2	μs							
01	28.9	μs							
10	40	μs							
11	51.2	μs							

Table 43. Diagnostic filter time selection for OFF state

While in the OFF state, the t_{DIAG} filter is reset and restarts if one of the following condition occurs:

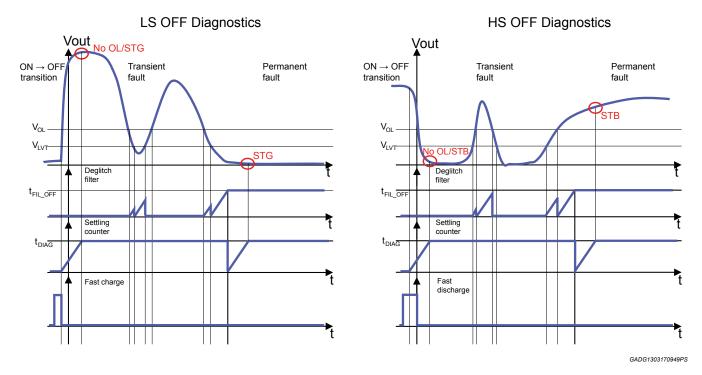
- LS configuration
 - V_{LVT} crossed with a negative slope (possible STG),
 - V_{OL} crossed with a negative slope (possible OL),
- HS configuration
 - V_{LVT} crossed with a positive slope (possible OL),
 - V_{OL} crossed with a positive slope (possible STB).

To avoid glitches on threshold crossing, a deglitch filter with t_{FIL_OFF} timeout has been implemented. The deglitch filter time t_{FIL_OFF} is fixed (see Figure 36):

Table 44. Deglitch filter time for OFF state diagnostics

Symbol	Parameter	Min.	Max.	Unit
	Deglitch filter time for OFF state diagnostics	0.3	0.5	μs

Figure 36. Deglitch and settling filter times for OFF state diagnostics: (left) STG detection on LS; (right) STB detection on HS



Vout corresponds to DRNx pin for LS NMOS and HS PMOS configurations, while it's SNGPx pin for HS NMOS Note: configuration.

6.4.2 **Diagnostic thresholds**

The diagnostic thresholds are fixed, as shown in the table below. They have been designed in tracking, thus both spreading in the same direction.

Table 45. OFF state diagnostic thresholds

Symbol	Parameter	Min.	Max.	Unit
V _{LVT}	Threshold for: • STG detection in LS config (V _{out} < V _{LVT}) • OL detection in HS/LS config (V _{LVT} < V _{out} < V _{OL})	1.9	2.3	V
V _{OL}	Threshold for: • STB detection in HS config (V _{out} > V _{OL}) • OL detection in HS/LS config (V _{LVT} < V _{out} < V _{OL})	2.8	3.4	V

Vout corresponds to DRNx pin for LS NMOS and HS PMOS configurations, while it's SNGPx pin for HS NMOS Note: configuration.

6.4.3 Internal regulator for open load (OL) detection

Each channel features an internal regulator with limited current capability that regulates the output node voltage V_{out} around V_{OUT_OL} , which falls in the middle of the [V_{LVT} ; V_{OL}] range. OL regulators are always ON, independently on the ENABLE_DIAGNOSTIC bit value.

Table 46. Open Load output voltage

Symbol	Parameter	Min.	Тур.	Max.	Unit
V _{OUT_OL}	V _{out} node voltage in case of open load	2.25	2.5	2.75	V

Note:

V_{out} corresponds to DRNx pin for LS NMOS and HS PMOS configurations, while it's SNGPx pin for HS NMOS configuration.

Regulator current capability IDIAG can be programmed via **diag i config xx** bit as follows:

diag_i_config_xx	Min.	Max.	Unit
0	60	100	μA
1	0.6	1	mA

Table 47. Vout regulator current capability IDIAG

A higher current capability allows compensating the leakage of external devices (FET, recirculation diodes, etc.) The current limitation feature allows distinguishing between OL and STB/STG faults:

- In case of open load, the regulator is able to drive Vout around VOUT OL and the OL fault is flagged;
- In case of STB/STG fault, due to the limited current capability, the regulator has no effect on V_{out}. Therefore, output node voltage stays below V_{LVT} (STG on LS) or above V_{OL} (STB on HS).

Refer to Figure 37 and Figure 39 for OL regulator operation in HS configuration. Refer to Figure 38 and Figure 39 for OL regulator operation in LS configuration.

6.4.4 Fast charge/discharge currents

In order to reliably detect a fault, the V_{out} voltage must be stable before the settling time t_{DIAG} expires.

In case of STB/STG faults, high current capability of battery and ground supplies guarantee fast Vout settling.

In case of open load, Vout must be brought in the [V_{LVT}; V_{OL}] range before t_{DIAG} expires in order to guarantee fault detection. L9945 implements internal fast charge/discharge currents in order to allow settling of V_{out} in a time suitable for detection:

- When HS transistor is switched OFF, a fast discharge current I_{FAST_DIS} rapidly decreases V_{out} down to V_{OL} to help the OL regulator detect an eventual open load fault (see Figure 37 and Figure 39). I_{FAST_DIS} is enabled in case:
 - The HS channel has been just switched OFF;
 - The settling time t_{DIAG} is still running;
 - V_{out} is above V_{OL}.
- When LS transistor is switched OFF, a fast charge current I_{FAST_CHG} rapidly increases V_{out} up to V_{LVT} to help the OL regulator detect an eventual open load fault (see Figure 38 and Figure 39). I_{FAST_CHG} is enabled in case:
 - The LS channel has been just switched OFF;
 - The settling time t_{DIAG} is still running;
 - Vout is below V_{LVT}.

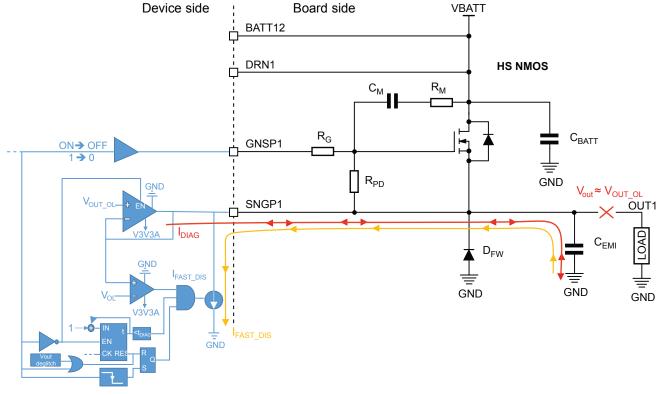
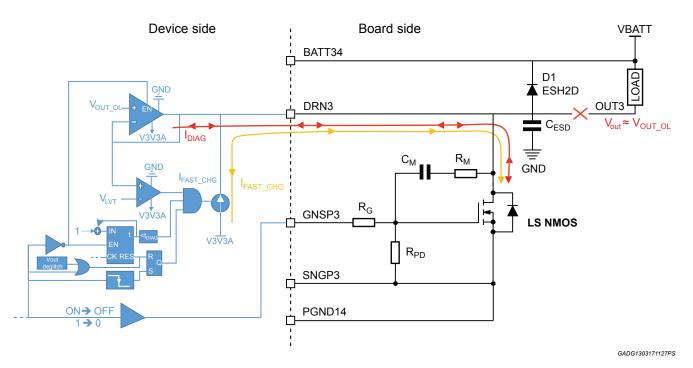


Figure 37. OFF state output regulator for OL detection. Example of operation on HS

GADG1303171115PS

Figure 38. OFF state output regulator for OL detection. Example of operation on LS



57



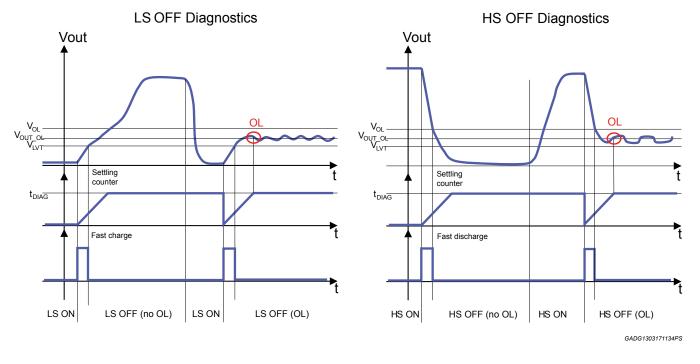


Figure 39. Fast charge/discharge currents for OL detection: (left) OL detection on LS; (right) OL detection on HS

The table below reports the electrical characteristics of the fast charge/discharge current generators.

Table 48. Fast charge/discharge current generator electrical characteristics

Symbol	Parameter	Min.	Max.	Unit
IFAST_CHG	V_{out} node fast charge current used in case of LS NMOS	2.4	3.8	mA
I _{FAST_DIS_P}	V_{out} node fast discharge current used in case of HS PMOS	8	13	mA
I _{FAST_DIS_N}	\mathbf{V}_{out} node fast discharge current used in case of HS NMOS	9	15	mA

Note: V_{out} corresponds to DRNx pin for LS NMOS and HS PMOS configurations, while it's SNGPx pin for HS NMOS configuration.

6.5 Silent diagnostic pulses for static loads

L9945 features ON/OFF diagnostic pulses of fixed duration for monitoring channels that are in a steady state. Two type of pulses are available:

- OFF pulse: turns off the selected channel for a t_{PULSE_OFF} interval. To be used for OL and STG/STB detection. It is effective only if T_{diag} < 100 µs.
- ON pulse: turns on the selected channel for a t_{PULSE_ON} interval. To be used for OC detection. It is effective only if T_{blank oc} < 80 μs.

Once a diagnostic pulse is over, the output control is released and channel can be driven either by NONx pins or SPI (as programmed).

Diagnostic pulses can be sent by programming the **DIAG_ON_PULSE_xx** and **DIAG_OFF_PULSE_xx** bit in the COMMAND 9 frame. Pulse requests are latched and are reset once pulse execution is completed.

For each channel:

A diagnostic pulse request must not be sent until the previous one is completed. If a pulse request incomes
when pulse latches are still set, it will be ignored.



If both OFF and ON pulses are requested in the same SPI frame, the behavior depends on the output state:

If the output is currently being kept OFF, an ON pulse will be generated

- If the output is currently being kept ON, an OFF pulse will be generated

Diagnostic pulses requests are ignored in case of H-Bridge configuration. The table below lists the diagnostic pulses related timings.

Table 49. Diagnostic pulses timings

Symbol	Parameter	Min.	Max.	Unit
tPULSE_ON	ON pulse duration	80	120	μs
t _{PULSE_OFF}	OFF pulse duration	100	150	μs

6.6 Summary of disable sources and faults

The table below gathers all the disable sources and the fault events and summarizes their effects on the outputs.

Event	CH1 – CH5	CH6	СН7 – СН8
DIS assertion (Section 6.1.1)	Actively OFF ^A	Actively OFF ^A	No Effect
NDIS assertion (Section 6.1.1)	Actively OFF ^A	Actively OFF ^A	No Effect
VDD5 overvoltage (Section 6.1.2)	Actively OFF ^M	Actively OFF ^M	No Effect
VDD5 undervoltage (Section 6.1.2)	Actively OFF ^A	Actively OFF ^A	No Effect
BIST on going (Section 6.1.3)	Three-State	Three-State	Three-State
BIST failed (Section 6.1.3)	Actively OFF ^M	Actively OFF ^M	Three-State ^M
HWSC on going (Section 6.1.3)	Actively OFF	Actively OFF	Three-State
HWSC failed (Section 6.1.3)	Actively OFF ^M	Actively OFF ^M	Three-State ^M
/PS undervoltage (Section 6.1.4)	Actively OFF ^A	Actively OFF ^A	Actively OFF ^A
Charge Pump undervoltage (Section 6.1.5)	Actively OFF ^A	Actively OFF ^A	Actively OFF ^A
Disable via SPI (en_OUT_xx) (Section 6.1.6)	Three-State ^M	Three-State ^M	Three-State ^M
Disable via SPI (prot_disable_xx) (Section 6.1.7)	Actively OFF ^M	Actively OFF ^M	Actively OFF ^M
EN6 set low (Section 6.1.8)	No Effect	Actively OFF ^A	No Effect
NRES assertion (Section 6.1.9)	Actively OFF ^M	Actively OFF ^M	Actively OFF ^M
CC failed (Section 6.1.10)	Actively OFF ^M	Actively OFF ^M	No Effect
DC failure (Section 6.3.1)	Actively OFF ^M	Actively OFF ^M	Actively OFF ^M
STG failure (Section 6.4)	No Effect	No Effect	No Effect
STB failure (Section 6.4)	No Effect	No Effect	No Effect
DL failure (Section 6.4)	No Effect	No Effect	No Effect
DN pulse request (Section 6.5)	Actively ON ^A	Actively ON ^A	Actively ON ^A
DFF pulse request (Section 6.5)	Actively OFF ^A	Actively OFF ^A	Actively OFF ^A

Table 50. Summary of disable sources and faults

Syntax: A = Automatic Re-Engagement, M = Manual Re-Engagement

When configured as H-Bridge, CH7 and CH8 are treated like CH1-CH5.

Note:

6.7 Signal integrity check

For signal integrity purposes, the device offers the possibility of verifying the correct propagation and effects of the control signals. The integrity of the output signals can be monitored via SPI issuing the following frames:

- Frame 1 = 0xBAAAAAAA: channels 1 to 4 integrity report
- Frame 2 = 0xCAAAAAAB: channels 5 to 8 integrity report

The response frame consists of 32 bit containing the following fields:

Table 51. Response frames to signal integrity requests

			Response Frame														
		31-28	27	26-21	20	19	18	17	16	15	14	13	12-10	9-7	6-4	3-1	0
Frame issued	Fr1	1011	1	010101	V4	V3	V2	V1	C4	C3	C2	C1	PUPD4	PUPD3	PUPD2	PUPD1	Р
Frame issued	Fr2	1100	1	010101	V8	V7	V6	V5	C8	C7	C6	C5	PUPD8	PUPD7	PUPD6	PUPD5	Р

Note:

The SPI protocol is out of frame, meaning that the response to the current message will be issued on the following frame.

Field description of Table 51 is listed below:

- P: Parity bit, based on even parity calculation
- PUPDx: Pull up / Pull down status. This field consists of 3 bit encoding the current status of the gate charge / discharge current sources (IPU and IPD in Figure 12) for the xth channel. The code depends on the output configuration:

High-Side with PFET

- 100 : IPD ON and IPU OFF→ transistor ON
- 010 : IPD OFF and IPU ON → transistor OFF
- 000 : IPD OFF and IPU OFF \rightarrow output in three-state
- Others : integrity of the output control is compromised

High-Side/Low-Side with NFET

- 010 : IPD ON and IPU OFF → transistor OFF
- 001 : IPD OFF and IPU ON → transistor ON
- 000: IPD OFF and IPU OFF → output in three-state
- Others : integrity of the output control is compromised
- Cx: Output control signal. This flag combines the control signals SPI_ON_OUTxx, NONx and SPI_input_sel_xx to feedback if the xth channel is commanded ON or OFF
 - 1 : output commanded ON
 - 0 : output commanded OFF
- Vx: Channel status. This flag provides feedback about the external FET output voltage (DRNx pin in case of LS NMOS or HS PMOS, SNGPx pin in case of HS NMOS) through the internal diagnostic comparators (refer to Section 6.4 for further information about diagnostics). The value of this bit depends on the channel configuration:

High-Side with NFET/PFET

- 1 : Output voltage high (Vout > VOL) \rightarrow transistor ON
- 0 : Output voltage low (Vout < VOL) \rightarrow transistor OFF

Low-Side with NFET

- 1 : Drain voltage high (Vout > VLVT) \rightarrow transistor OFF
- 0 : Drain voltage low (Vout < VLVT) \rightarrow transistor ON

Note:

This information is not intended to replace diagnostics and must be used only to verify the control signal integrity. Refer to Section 6.2 in order to understand how output diagnostic is performed and which are the fault codes.

7 Package information

In order to meet environmental requirements, ST offers these devices in different grades of ECOPACK packages, depending on their level of environmental compliance. ECOPACK specifications, grade definitions and product status are available at: www.st.com. ECOPACK is an ST trademark.

7.1 TQFP64 (10x10x1 mm exp. pad down) package information

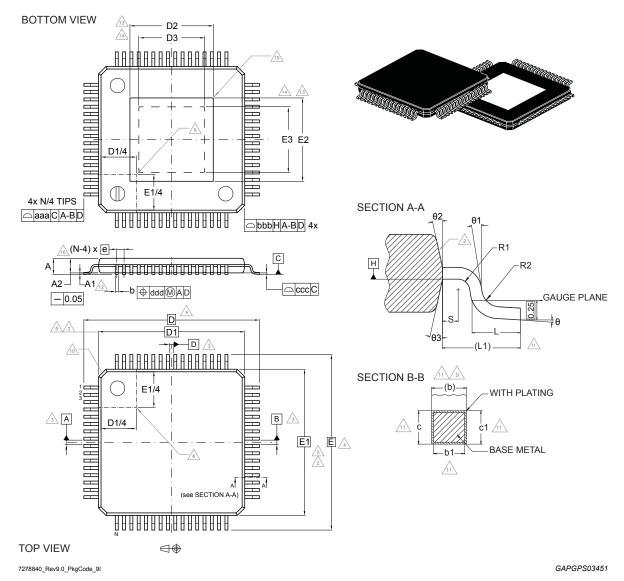


Figure 40. TQFP64 (10x10x1 mm exp. pad down) package outline



Ref	Min.	Тур.	Max.	Note (see # in Notes below)
θ	0°	3.5°	7°	-
θ1	0°	-	-	-
θ2	11°	12°	13°	-
θ3	11°	12°	13°	-
А	-	-	1.2	15
A1	0.05	-	0.15	12
A2	0.95	1	1.05	15
b	0.17	0.22	0.27	9, 11
b1	0.17	0.2	0.23	11
С	0.09	-	0.2	11
c1	0.09	-	0.16	11
D	-	12.00 BSC	-	4
D1	-	10.00 BSC	-	5, 2
D2	-	-	6.4	13
D3	4.8	-	-	14
е	-	0.50 BSC	-	-
E	-	12.00 BSC	-	4
E1(*)	-	10.00 BSC	-	5, 2
E2	-	-	6.4	13
E3	4.8	-	-	14
L	0.45	0.6	0.75	-
L1	-	1.00 REF	-	-
Ν	-	64	-	16
R1	0.08	-	-	-
R2	0.08	-	0.2	-
S	0.2	-	-	-
	Тс	plerance of form and positi	ion	
aaa	-	0.2	-	
bbb	-	0.2	-	1 7
CCC	-	0.08	-	1, 7
ddd	-	0.08	-	

Table 52. TQFP64 (10x10x1 mm exp. pad down) package mechanical data

Notes

- 1. Dimensioning and tolerancing schemes conform to ASME Y14.5M-1994.
- 2. The Top package body size may be smaller than the bottom package size up to 0.15 mm.
- 3. Datum A-B and D to be determined at datum plane H.
- 4. To be determined at seating datum plane C.
- 5. Dimensions D1 and E1 do not include mold flash or protrusions. Allowable mold flash or protrusions is "0.25 mm" per side. D1 and E1 are Maximum plastic body size dimensions including mold mismatch.

- 6. Details of pin 1 identifier are optional but must be located within the zone indicated.
- 7. All Dimensions are in millimeters.
- 8. No intrusion allowed inwards the leads.
- 9. Dimension "b" does not include dambar protrusion. Allowable dambar protrusion shall not cause the lead width to exceed the maximum "b" dimension by more than 0.08 mm. Dambar cannot be located on the lower radius or the foot. Minimum space between protrusion and an adjacent lead is 0.07 mm for 0.4 mm and 0.5 mm pitch packages.
- 10. Exact shape of each corner is optional.
- 11. These dimensions apply to the flat section of the lead between 0.10 mm and 0.25 mm from the lead tip.
- 12. A1 is defined as the distance from the seating plane to the lowest point on the package body.
- 13. Dimensions D2 and E2 show the maximum exposed metal area on the package surface where the exposed pad is located (if present). It includes all metal protrusions from exposed pad itself.
- 14. Dimensions D3 and E3 show the minimum solderable area, defined as the portion of exposed pad which is guaranteed to be free from resin flashes/bleeds, bordered by internal edge of inner groove.
- 15. The optional exposed pad is generally coincident with the top or bottom side of the package and not allowed to protrude beyond that surface.
- 16. "N" is the number of terminal positions for the specified body size.

Date	Revision	Changes
01-Sep-2017	1	Initial release.
		Updated:
		Figure 4;
		Fixed typos in RESPONSE 5, RESPONSE 11 and RESPONSE 12 registers;
		Table 41;
		Fixed typo in Section 6.4.1;
17-Jan-2018	2	Description;
17-341-2010	2	Replaced in the whole datasheet the term "Starter Relay" by "safety relevant load";
		Changed Figure 25;
		Section 6.3.6 Temperature compensation for OC threshold;
		Section 6.3.7 Battery compensation for OC threshold;
		Figure 36;
		Package information
21-May-2018	3	Added Note (1) to Table 17;
21-Way-2010	5	Updated Section 5.5.3 H-bridge dead time.
15-Nov-2018	4	Updated Table 5. Thermal behavior.
		Updated Table 42. Temperature compensation;
25-Jun-2019	5	Updated Figure 32. TCF vs. T _j ;
		Minor text changes.
03-Sep-2019	6	Added Note to Table 19. Output response in case of DIR transition
26 San 2010	7	Removed watermark Restricted;
26-Sep-2019	7	Minor text changes.

Table 53. Document revision history

Contents

1	Bloc	k diagr	am	3							
2	Applications										
	2.1	High-S	Side / Low-Side, with configurable FET type (N channel or P channel)	4							
	2.2	Peak &	& Hold	6							
	2.3	H-Brid	ge	7							
3	Devi	ice pins	3	9							
	3.1	Pinout		9							
	3.2	Pin na	mes and functions	9							
4	Proc	duct ele	ctrical and thermal characteristics	13							
	4.1	Absolu	Ite maximum ratings	13							
	4.2	Latch-up trials									
	4.3	ESD p	erformance	14							
	4.4	Therm	al behavior	16							
		4.4.1	Temperature ADC	17							
	4.5	Range	e of functionality								
5	Fund	ctional	description	19							
	5.1	5.1 General description									
	5.2	Supply	/ concept	19							
		5.2.1	VDD5 supply block	19							
		5.2.2	VPS supply block	20							
		5.2.3	VPS ADC	21							
		5.2.4	Charge pump (VGBHI)	21							
		5.2.5	VIO supply pin & SDO pin characteristics	22							
	5.3	Reset		23							
	5.4	Output	t pre-drivers								
		5.4.1	Available configurations	24							
		5.4.2	Default configuration and output enable	24							
		5.4.3	Output control	24							
		5.4.4	Gate charge/discharge currents	25							



	5.4.5	Internal and external clamping
	5.4.6	Electrical characteristics
5.5	H-bridg	ge
	5.5.1	H-Bridge driving modes
	5.5.2	H-Bridge diagnostics
	5.5.3	H-bridge dead time
	5.5.4	H-bridge disabling
	5.5.5	Overcurrent detection strategies for H-Bridge
	5.5.6	Current limitation for H-Bridge
	5.5.7	H-Bridge OFF state diagnostic timings
5.6	Peak &	Hold
	5.6.1	Peak & Hold driving mode
	5.6.2	Peak & Hold diagnostics
	5.6.3	ON state diagnostics
	5.6.4	OFF state diagnostics
5.7	Interna	Il oscillator
	5.7.1	Spread spectrum
	5.7.2	Internal oscillator electrical characteristics
5.8	Digital	I/Os
	5.8.1	Digital I/Os electrical characteristics
5.9	Serial F	Peripheral Interface (SPI)
	5.9.1	SPI Quick Look
	5.9.2	Parallel operation
	5.9.3	Daisy chain
	5.9.4	SPI electrical characteristics signal and the timing diagram
	5.9.5	SPI protocol
5.10	SPI MO	OSI/MISO list
	5.10.1	COMMAND X frame partitioning
	5.10.2	RESPONSE X frame partitioning
Safe	ty & dia	gnostics
6.1	Disable	e sources
	6.1.1	DIS & NDIS pins

6



		6.1.2	VDD5 Overvoltage/Undervoltage	118
		6.1.3	BIST & HWSC	119
		6.1.4	VPS undervoltage	120
		6.1.5	Charge pump undervoltage	120
		6.1.6	SPI enable bit	121
		6.1.7	Protection disable bit	121
		6.1.8	EN6 input	121
		6.1.9	NRES assertion	121
		6.1.10	Communication Check (CC)	121
	6.2	Diagno	stics overview	122
	6.3	ON sta	te diagnostics	124
		6.3.1	Behavior in case of OC detection	124
		6.3.2	Output re-engagement strategy after an OC event	125
		6.3.3	OC sensing strategy	125
		6.3.4	OC threshold selection	126
		6.3.5	OC detection timings	128
		6.3.6	Temperature compensation for OC threshold	129
		6.3.7	Battery compensation for OC threshold.	130
		6.3.8	Reading the compensated OC threshold.	131
		6.3.9	OC detection schematics	131
	6.4	OFF st	ate diagnostics	133
		6.4.1	Settling and deglitch filter times	134
		6.4.2	Diagnostic thresholds	135
		6.4.3	Internal regulator for open load (OL) detection	135
		6.4.4	Fast charge/discharge currents	136
	6.5	Silent c	diagnostic pulses for static loads	138
	6.6	Summa	ary of disable sources and faults	139
	6.7	Signal	integrity check	139
7	Pack	age info	ormation	141
	7.1	TQFP6	4 (10x10x1 mm exp. pad down) package information	
Rev	ision		· · · · · · · · · · · · · · · · · · ·	

7

List of tables

Table 1.	Pin list
Table 2.	Absolute maximum ratings capability
Table 3.	Latch-up trials
Table 4.	ESD performance
Table 5.	Thermal behavior
Table 6.	Temperature ADC electrical characteristics
Table 7.	Range of functionality
Table 8.	VDD5 supply block electrical characteristics
Table 9.	VPS supply block electrical characteristics
Table 10.	VPS ADC electrical characteristics
Table 11.	Charge pump electrical characteristics
Table 12.	SDO pin electrical characteristics
Table 13.	Output status depending on control strategy and control input
Table 14.	Selection of gate charge/discharge currents
Table 15.	Output pre-driver stages electrical characteristics
Table 16.	NONx signals in H-bridge configuration
Table 17.	Truth table
Table 18.	Dead time values
Table 19.	Output response in case of DIR transition
Table 20.	Output response in case of NPWM transition
Table 21.	H-bridge state for different DIS/NDIS and NRES
Table 22.	t _{OFF} selection
Table 23.	OFF state diagnostic timings for H-Bridge
Table 24.	Diagnostic strategy for peak & hold configuration
Table 25.	Internal oscillator electrical characteristics
Table 26.	Digital I/Os electrical characteristics
Table 27.	SPI quick look
Table 28.	SPI electrical characteristics
Table 29.	SPI protocol
Table 30.	SPI MOSI list
Table 31.	NDIS OV protection electrical characteristics
Table 32.	HWSC timing characteristics
Table 33.	VPS UV detection electrical characteristics
Table 34.	Charge pump undervoltage detection electrical characteristics
Table 35.	CC timings
Table 36.	Diagnostic codes
Table 37.	Selection of fast shutdown currents in case of OC detection
Table 38.	OC sensing strategy
Table 39.	Overcurrent threshold selection electrical parameters
Table 40.	OC threshold selection
Table 41.	OC detection timings
Table 42.	Temperature compensation
Table 43.	Diagnostic filter time selection for OFF state
Table 44.	Deglitch filter time for OFF state diagnostics
Table 45.	OFF state diagnostic thresholds
Table 46.	Open Load output voltage
Table 40.	V _{out} regulator current capability I _{DIAG}
Table 48.	
Table 48.	Fast charge/discharge current generator electrical characteristics 138 Diagnostic pulses timings 139
Table 50.	Summary of disable sources and faults.
Table 50.	•
10016 31.	Response frames to signal integrity requests

57

Table 52.	TQFP64 (10x10x1 mm exp. pad down) package mechanical data	142
Table 53.	Document revision history	144

List of figures

Figure 1.	Block diagram	3
Figure 2.	Example of High-Side configuration with NMOS on channel 1	4
Figure 3.	Example of High-Side configuration with PMOS on channel 5	5
Figure 4.	Example of Low-Side configuration with NMOS on channel 3	
Figure 5.	Example of peak & hold configuration with NMOS (HS) on channel 1 and NMOS (LS) on channel 4	6
Figure 6.	Example of H-Bridge configuration with NMOS as HS and LS transistors (channels 1-4 used)	8
Figure 7.	L9945 pinout	9
Figure 8.	ESD ratings on pinout	
Figure 9.	Sketch of a 2s2p PCB with thermal vias	16
Figure 10.	Thermal impedance diagram	
Figure 11.	Charge pump connections	
Figure 12.	Output pre-driver control	
Figure 13.	Clamping for HS configuration	
Figure 14.	Clamping for LS configuration.	
Figure 15.	H-bridge driving configurations	30
Figure 16.	OC detection strategies for H-Bridge: (left) one shunt resistor for LS, DSM for HS; (center) two shunt resistors; (right) DSM	33
Figure 17.	Current limitation timing diagram.	34
Figure 18.	Current limitation iterations (until OC failure).	35
Figure 19.	Possible faults in peak & hold configuration	39
Figure 20.	Daisy chain and parallel operation.	42
Figure 21.	Data transfer in daisy chain operation	42
Figure 22.	SPI timing diagram	44
Figure 23.	Out of frame response	44
Figure 24.	NDIS structure	18
Figure 25.	BIST & HWSC sequence	
Figure 26.	NDIS/DIS release after NRES release: t _{CC} is selected as watchdog starting timer value	21
Figure 27.	NDIS/DIS release before NRES release: t _{CC} is selected as watchdog starting timer value. Then, CC timer	~~
	switches to t _{CC}	
Figure 28.	Diagnostic codes quick look	
Figure 29.	FSM describing diagnostic priority.	
Figure 30.	Overcurrent sensing method (example on a LS NMOS)	
Figure 31.	Rshunt and DSM method diagram	
Figure 32.	TCF vs. T _j	
Figure 33.	BCF vs.VPS	
Figure 34.	OC detection through DSM or Shunt Measurement in Low Side configuration	
Figure 35.	OC detection through DSM or Shunt Measurement in High Side configuration with PMOS 13	
Figure 36.	Deglitch and settling filter times for OFF state diagnostics: (left) STG detection on LS; (right) STB detection on H	
Einung 07	CEE state subsubtraction for OL detection. Example of ensuration on U.C.	
Figure 37.	OFF state output regulator for OL detection. Example of operation on HS	
Figure 38.	OFF state output regulator for OL detection. Example of operation on LS.	
Figure 39.	Fast charge/discharge currents for OL detection: (left) OL detection on LS; (right) OL detection on HS 13	
Figure 40.	TQFP64 (10x10x1 mm exp. pad down) package outline	41

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